MITSUBISHI

Ladder Logic Test Function software for Windows SW5D5C-LLT-E

OPERATING MANUAL

Operating Manual

MELSEC

Mitsubishi Programmable Logic Controller

• SAFETY PRECAUTIONS •

(Always read these instructions before using this equipment.)

Before using this product, please read this manual and the relevant manuals introduced in this manual carefully and pay full attention to safety to handle the product correctly.
The instructions given in this manual are concerned with this product. For the safety instructions of the programmable controller system, please read the CPU module user's manual.
In this manual, the safety instructions are ranked as "DANGER" and "CAUTION".

⚠ DANGER	Indicates that incorrect handling may cause hazardous conditions, resulting in death or severe injury.
⚠ CAUTION	Indicates that incorrect handling may cause hazardous conditions, resulting in medium or slight personal injury or physical damage.

Note that the ⚠CAUTION level may lead to a serious consequence according to the circumstances. Always follow the instructions of both levels because they are important to personal safety.

Please save this manual to make it accessible when required and always forward it to the end user.

[Cautions Regarding Test Operation]

⚠ DANGER

- The ladder logic test tool (LLT) simulates an actual PLC to debug sequence programs.
  However, the execution of a debugged sequence program cannot be guaranteed.
  After debugging using the ladder logic test tool (LLT), connect an actual PLC and debug the sequence program normally before starting actual operation.
  Failure to correctly debug a sequence program may result in accidents due to incorrect outputs of operations.
- The simulated result may differ from actual operation because the ladder logic test tool (LLT) cannot access I/O units or special function units and do not support some instructions or device memory.
  After debugging using the ladder logic test tool (LLT), connect an actual PLC and debug the sequence program normally before starting actual operation.
  Failure to correctly debug a sequence program may result in accidents due to incorrect outputs of operations.

REVISIONS

* The manual number is given on the bottom left of the back cover.

Print Date	* Manual Number	Revision
Feb., 2000	SH(NA)-080064-A	First edition
Sep., 2000	SH(NA)-080064-B	Partial corrections A-3, A-6 Partial additions Section 2.4.6, App22
Nov.2000	SH(NA)-080064-C	Partial corrections 5-11

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INTRODUCTION

Thank you for purchasing the Mitsubishi general-purpose MELSEC series sequencer.
Read this manual and make sure you understand the functions and performance of MELSEC series sequencer thoroughly in advance to ensure correct use.

CONTENTS

About Manuals

The following manuals are also related to this product.
In necessary, order them by quoting the details in the tables below.

Related Manuals

Manual Name	Manual Number (Model Code)
GX Developer Version6 & GX Simulator Version5 Operating Manual (Start up) Describes the system configuration, installation procedure, and start-up procedure of the GX Developer and SW5D5C-LLT software packages. (Printed form) (Optionally available)	IB-0800132 (13J988)
GX Developer Version6 Operating Manual Describes the online functions of GX Developer including the programming procedure, printing out procedure, monitoring procedure, and debugging procedure. (Printed form) (Optionally available)	SH-080098 (13J989)

REMARK

GX Developer Version6 Operating Manual, the software package and manual are contained on a single CD-ROM as a set.
If you need GX Developer Version6 & GX Simulator Version5 Operating Manual (Start up), GX Developer Version6 Operating Manual and the Ladder Logic Test Tool Function software package for Windows SW5D5C-LLT (-V) Operating Manual separately from the software, they are optionally available in printed form.

About the Generic Terms and Abbreviations

Unless otherwise specified, the table below defines the abbreviations and terminology of the ladder logic test tool software package of model SW5D5C-LLT-E used in this manual.

Generic Term/Abbreviation	Description
Ladder logic test tool (LLT)	Abbreviation for "SW5D5C-LLT-E ladder logic test tool functions software package"
GPPW	Abbreviation for "SW□D5C-GPPW-E GPP function software package"
Windows 95	Abbreviation for "Microsoft Windows 95 (English version)"
Windows 98	Abbreviation for "Microsoft Windows 98 (English version)"
Windows NT 4.0	Abbreviation for "Microsoft Windows NT Workstation 4.0 (English version)"
Debug	Locating and correcting errors in a sequence program to create a correct program.
Device memory	Areas to store device data in the ladder logic test tool (LLT), including inputs (X), outputs (Y), relays (M), timers (T), data registers (D), etc.
Monitor	Monitoring to determine the ON/OFF status of bit devices or the PV of word devices.
Simulations	Test execution of a program on a personal computer with the ladder logic test tool (LLT) installed, instead of execution in an actual PLC.
Timing chart	Functions to visually confirm ON/OFF status of a bit device or the change in value of a word device.
WDT error	An error issued when a sequence program is written in such a way that it runs an infinite loop.
Pseudo-sequence program	Indicates a sequence program created by the ladder logic test tool (LLT) to realize the settings of I/O System Settings.
A series CPU	A0J2H, A1FX, A1S (S1), A1SJ, A1SH, A1SJH, A1N, A2C, A2CJ, A2N (S1), A2S (S1), A2SH (S1), A3N, A2A (S1), A3A, A2U (S1), A2US (S1), A2USH-S1, A3U, A4U, CPU board (A80BD-A2USH-S1)
QnA series CPU	Q2A, Q2AS (H), Q2AS1, Q2AS (H) S1, Q3A, Q4A, Q4AR
FX series CPU	FX0(S), FX0N, FX1, FX2(C), FX1S, FX1N, FX2N (C)
Motion controller CPU	A171SH, A172SH, A173UH (S1), A273UH (S3)
Q series CPU	Generic term for Q series CPU (A mode) and Q series CPU (Q mode).
Q series CPU (A mode)	Q02-A, Q02H-A, Q06H-A
Q series CPU (Q mode)	Q02, Q02H, Q06H, Q12H, Q25H

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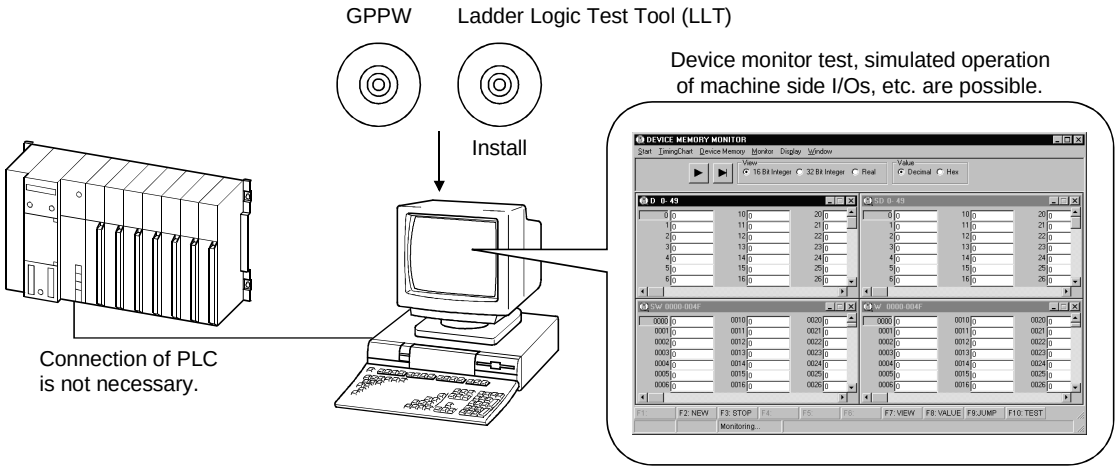
MEMO

1. OUTLINE OF LADDER LOGIC TEST TOOL (LLT)

This operating manual describes the functions and operation of the SW5D5C-LLT-E ladder logic test tool functions software package.

The SW5D5C-LLT-E ladder logic test tool functions software package (hereafter "ladder logic test tool (LLT)") is a software package which runs under Windows 95/98/ NT4.0.
Offline debugging is possible by adding the ladder logic test tool (LLT) to a computer in which the SW□D5C-GPPW- E/SW□D5F-GPPW-E GPP function software package (hereafter "GPPW") is installed. The offline debugging functions include the device monitor test and simulated operation of external device I/Os.
As the ladder logic test tool (LLT) allow sequence programs to be developed and debugged on a single computer, checking a modified program is quick and easy.
GPPW must be installed before these functions can be used.



A sequence program created with GPPW can be debugged by writing it to the ladder logic test tool (LLT).
The sequence program is automatically written to the ladder logic test tool (LLT) when the ladder logic test tool (LLT) are started up.
See the following manuals for information on operations not covered in this manual:

- GPP Function software for Windows SW5D5C-GPPW-E Ladder Logic Test Functions software SW5D5C-LLT-E Operating Manual (Start up) IB-0800093
- GPP Function software for Windows SW5D5C-GPPW-E Operating Manual.....SH-080062

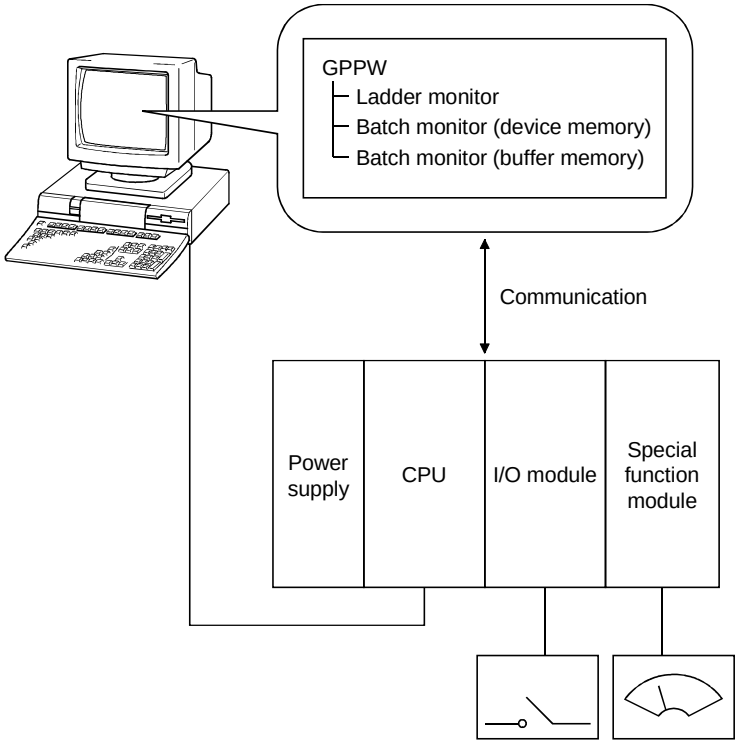
1.1 Features of the Ladder Logic Test Tool (LLT)

The main features of the ladder logic test tool (LLT) are described below.

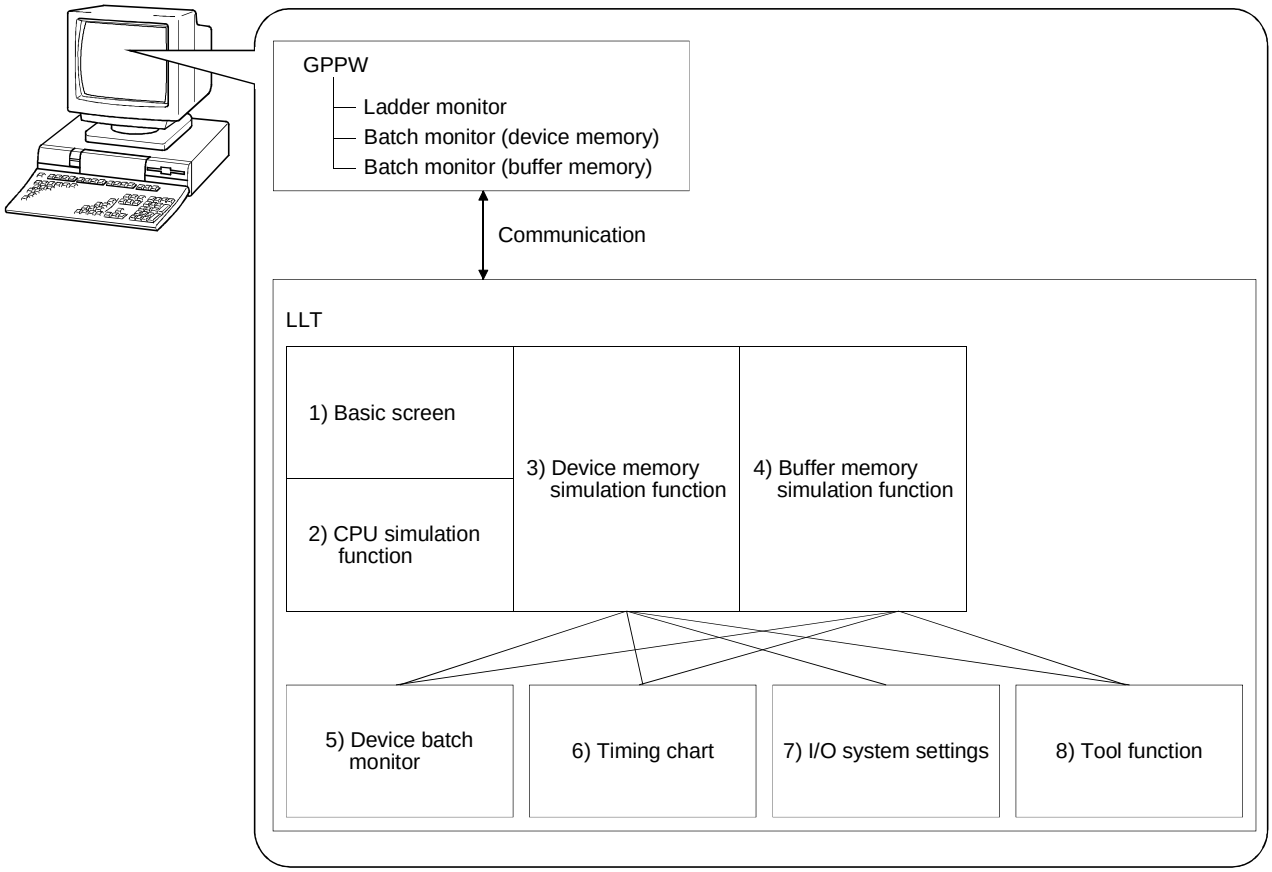
(1) Can be utilized as a single program debugging tool

Using the PLC for debugging in the conventional method required not only the PLC but also I/O and special function modules, external device, etc. to be prepared as needed.
When using the ladder logic test tool (LLT), you can perform debugging on a single personal computer because I/O System Settings for external device simulation and the simulation function for special function module buffer memory are available in addition to the simulation function for PLC.
Also, because of no connection to actual equipment, you can proceed with debugging safely if an abnormal output should occur due to a program bug.

Conventional debugging



Debugging using ladder logic test tool (LLT)



1) ... Key switch, indicator display function
2) ... Function to simulate CPU operation
3) ... Function to simulate CPU device memory
4) ... Function to simulate the buffer memory area of a special function module
5) ... Function to batch-monitor device memory values
6) ... Function to display device memory changes in a chart form
7) ... Function to simulate I/O operation of external device
8) ... Function to save/read device memory or buffer memory data to/from a file

(2) Comparison between PLC and ladder logic test tool (LLT)

There are the following differences between connection with a PLC and use of the ladder logic test tool (LLT).

	An	AnA	AnU Q (A mode)	FX	QnACPU	Q (Q mode)	Refer To
Device range	○＊1	○＊1	○＊1	○	○＊8	○＊8	Appendix-1
Instruction (common)	○＊2	○＊2	○＊2	○＊6	○＊9	○＊9	Appendix-29
Instruction (dedicated)	—	○＊3	○＊3	—	—	—	Appendix-30
Parameter	○＊4	○＊4	○＊4	○＊7	○＊10	○＊10	2-11
Network parameter	×	×	×	×	×	×	2-11
Special function module	○＊5	○＊5	○＊5	○＊5	○＊5	○＊5	—

○: Supported ×: Unsupported —: Irrelevant

＊1: Device I is not supported.

＊2: Output instructions, program branch instructions, data processing instructions, display instructions and other instructions include unsupported instructions.

＊3: Structured program instructions, I/O operation instructions, character string processing instructions, clock instructions, data link instructions and special module instructions include unsupported instructions.

＊4: Memory capacity setting, PLC RAS setting, PLC system setting and device setting include unsupported items.

＊5: Only the buffer memory area is supported. The size of the buffer memory area is fixed to 16K points. The QCPU (Q mode) is fixed to 64K points.

＊6: Program flow instructions, high-speed processing instructions, convenient instructions, external device instructions, positioning instructions and clock instructions include unsupported instructions.

＊7: Memory capacity setting, device setting, PLC name setting, PLC system setting (1) and PLC system setting (2) include unsupported items.

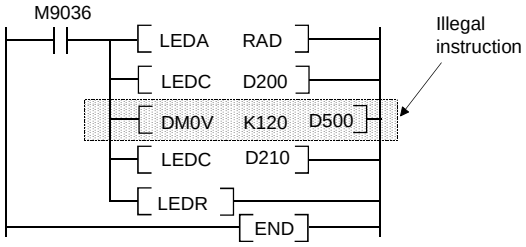
＊8: Devices S, Jn\X, Jn\Y, Jn\B, Jn\SB, Jn\W, Jn\SW, I, BL and TR are unsupported.

＊9: Output instructions, program execution instructions, I/O refresh instructions, other convenient instructions, data processing instructions, structured instructions, display instructions, debugging, diagnostic instructions, character string processing instructions, special function instructions, data control instructions, clock instructions, peripheral device instructions and other instructions include unsupported instructions.

＊10: PLC name setting, PLC system setting, PLC file setting, PLC RAS setting, device setting, boot file setting and SFC setting include unsupported items.

1.2 Differences To Debugging with an Actual PLC Connected

The specifications for debugging using the ladder logic test tool (LLT) differ from those for debugging with an actual PLC connected.
The main differences between debugging using the ladder logic test tool (LLT) and debugging with an actual PLC connected are shown below.
See Section 2.4 for details.

Item Name	Debugging with an Actual PLC Connected	Debugging with Ladder Logic Test Tool (LLT)	Applicable CPU
Step execution, skip execution, partial execution	Not supported by FX series CPU functions	Debugging using step execution, skip execution, and partial execution makes debugging operation more efficient.	• FXCPU
Device range check	Operation continues even if the indirect designation by the index register exceeds the device range.	"OPERATION ERROR" occurs when the device range determined by CPU type or parameters is exceeded. (For the device range for a specific CPU type, refer to Appendix 1.)	• ACPU • QnACPU • FXCPU • Motion controller CPU • QCPU
Real number range check	Dedicated instructions to handle real numbers allow operation to continue when an illegal value occurs which cannot be evaluated as a real number.	Real number range checks are conducted rigorously. "OPERATION ERROR" is displayed if a value cannot be evaluated as a real number.	• ACPU • QnACPU • Motion controller CPU • QCPU
Number range check	Value 0 is given as a result of "0 divided by 0" by DIV instruction, floating point division, of the A series PLC. No error occurs.	The rigorous number range check can detect an illegal 0 denominator and "OPERATION ERROR" is generated if 0 ÷ 0 is executed.	• ACPU • Motion controller CPU • QCPU (A mode)
Illegal instruction in a dedicated instruction	The illegal instruction is ignored and operation continues.	The illegal instruction is checked and "INSTRCT CODE ERR." is displayed. Dedicated instructions must be described as blocks. (Example of illegal ladder) 	• ACPU • Motion controller CPU • QCPU (A mode)

Item Name	Debugging with an Actual PLC Connected	Debugging with Ladder Logic Test Tool (LLT)	Applicable CPU
Time concept	Actual time	As per constant scan setting.	• ACPU • QnACPU • FXCPU • Motion controller CPU • QCPU
Supported instructions	All instructions can be used.	Since data refresh instructions, PID control instructions (QnA series, FX series CPUs), etc. cannot be used, they are processed as NOPs. (Refer to Appendix-2 for supported instructions.)	• ACPU • QnACPU • FXCPU • Motion controller CPU • QCPU
Operating CPU type	According to CPU type used.	Operates as A4UCPU when an A series CPU is selected, Q4ACPU when QnA series CPU is selected, FXCPU when FX series CPU is selected, or A4UCPU when motion controller CPU is selected.	• ACPU • QnACPU • FXCPU • Motion controller CPU • QCPU
Special function module (special block)	Supported	Not supported. Only the buffer memory area of a special function module (special block) is supported.	• ACPU • QnACPU • FXCPU • Motion controller CPU • QCPU (A-mode)
I/O module	Supported	Not supported	• ACPU • QnACPU • FXCPU • Motion controller CPU • QCPU
Network	Supported	Not supported	• ACPU • QnACPU • FXCPU • Motion controller CPU • QCPU
Memory cassette capacity	An error occurs in GPPW if data exceeding the memory cassette capacity is written to the PLC.	No error occurs and normal operation continues if data exceeding the memory cassette capacity is written to the PLC.	• ACPU • QnACPU • Motion controller CPU • QCPU
Intelligent function module (intelligent parameters)	Supported	Only the initial setting, automatic refresh setting and buffer memory area are supported.	• QCPU (Q mode)

2. SPECIFICATIONS

2.1 Table of Functions

The functions supported by the ladder logic test tool (LLT) are shown below.
The functions supported by the ladder logic test tool (LLT) include functions executed from the ladder logic test tool (LLT) menu and functions executed from the GPPW menu.
The Ladder Logic Test Tool simulates the function of the CPU selected at the time of execution of the LLT from the GPPW menu: it supports CPU's of type A, QnA, and FX. Also, when the CPU of the motion controller is selected, the corresponding function of the A series CPU operates. (Refer to Section 2.4.5(1) for the A series CPU corresponding to the motion controller CPU.)
Also, when the Q series (Q mode) is selected, the Q series CPU functions operate, but when the Q series (A mode) is selected, the A series CPU functions operate as equivalent to those of the A4UCPU.
The functions supported by the ladder logic test tool (LLT) are as indicated in Table 2.1.
See the SW5D5C-GPPW Operating Manual for details about the operation of functions executed from the GPPW menu.

Table 2.1 Functions Supported by Ladder Logic Test Tool (LLT)

Function		Description	Reference
Functions executed from the GPPW menu	Ladder monitor Device monitor	● Monitors the processing status of the ladder logic test tool (LLT)	See the SW5D5C-GPPW-E Operating Manual
	Device test	● Forcibly write device values to the ladder logic test tool (LLT) during monitoring.	
	Write to PLC	● Writes parameter file and program file to ladder logic test tool (LLT).	
	PLC diagnostics	● Checks the ladder logic test tool (LLT) status and errors.	
	Skip execution	● Skips program execution in the range between two designated steps.	
	Partial execution	● Executes the part of the program in a designated step or pointer range.	
	Step execution	● Executes the sequence program one step at a time.	
	Remote operation	● Operates the ladder logic test tool (LLT) execution status.	
	Program monitor list	● Monitors the program execution status and number of executions as a table, starts and stops the program execution in the table.	

Function		Description	Reference
Functions executed from the ladder logic test tool (LLT) menu	I/O system settings	● Simulates the operation of external devices by simple settings.	See Chapter 4.
	Monitor test	● Conducts testing by monitoring the device memory status. ● Displaying the ON/OFF chart of the devices. ● Forcing the devices ON/OFF, and changing present values.	See Chapter 5.
	Tools	● Saves and reads the device memory and buffer memory.	See Chapter 6.
	Function equivalent to WDT	● Issues a WDT error if a sequence program is written in such a way that it runs an infinite loop.	—
	Error detail display function	● Displays detailed error information at occurrence of an error.	See Chapter 3.
	Unsupported instruction list display function	● Lists the instructions which are not supported by the ladder logic test tool (LLT) if they are included in a sequence program.	

2.2 Function List

This section provides the function list of each screen.

(1) Basic screen function list

		Reference
Start		
Device Memory Monitor	Shows the Device Memory Monitor screen.	Chapter 5
I/O System Settings	Shows the I/O System Settings screen.	Chapter 4
Tools		
Backup Device Memory	Writes device memory data to a file.	Section 6.1
Backup Buffer Memory	Writes buffer memory data to a file.	Section 6.1
Restore Device Memory	Reads the saved device memory data.	Section 6.2
Restore Buffer Memory	Reads the saved buffer memory data.	Section 6.2
Help		
About LLT	Shows the product information.	

(2) Device Memory Monitor screen function list

		Reference
Start		
Exit	Closes the Device Memory Monitor screen.	Section 5.3
Timing Chart		
Run	Starts the Timing Chart screen.	Section 5.5.2
Device Memory		
Bit Device		
Bit device corresponding to CPU	Shows the window of the selected bit device.	Section 5.4.1
Word Device		
Word device corresponding to CPU	Shows the window of the selected word device.	Section 5.4.1
Monitor		
Start/Stop	Starts/stops monitor.	Section 5.4.2
Test	Sets ON/OFF of the device and changes the present value.	Section 5.4.6
Monitoring Interval	Changes the monitoring interval.	Section 5.4.3
Display		
Starting Page	Shows the first page in the active window.	Section 5.4.1
Previous Page	Shows the preceding page in the active window.	Section 5.4.1
Next Page	Shows the next page in the active window.	Section 5.4.1
End Page	Shows the last page in the active window.	Section 5.4.1
Jump	Shows the specified device and onward in the active window.	Section 5.4.1
Value		
Decimal	Shows decimal values in the active window.	Section 5.4.4
Hexadecimal	Shows hexadecimal values in the active window.	Section 5.4.4
View		
Sixteen Bit Integer	Shows 16-bit integers in the active window.	Section 5.4.4
Thirty Two Bit Integer	Shows 32-bit integers in the active window.	Section 5.4.4
Real	Shows real numbers in the active window.	Section 5.4.4

		Reference
Window		
New	Opens a new window with the specified device.	Section 5.4.5
Cascade	Cascades currently open windows.	
Tile	Tiles currently open windows.	
Arrange	Arranges windows reduced to icons.	

(3) Timing Chart function list

File		
Open File	Reads the saved monitor device data.	Section 5.5.6
Save File As	Writes the device data currently monitored.	Section 5.5.6
Save Timing Data	Saves as the timing chart data file.	Section 5.5.6
Exit	Exits from Timing Chart.	Section 5.5.2
Device		
Enter Device	Registers the devices to be monitored.	Section 5.5.4
Delete Device	Deletes the selected devices.	Section 5.5.4
List Device	Lists the devices being monitored.	Section 5.5.8
Property	Change the display format of the selected device.	Section 5.5.8
Monitor		
Start/Stop	Starts/stops monitor.	Section 5.5.5
Sampling period	To change the Data accumulation interval.	Section 5.5.7

(4) I/O system setting screen function list

		Reference
File		
New	Creates the new I/O system setting file.	Section 4.8.1
Open	Opens current I/O system setting file.	Section 4.8.1
Save	Overwrites and saves file being opened.	Section 4.8.1
Save As	Gives the name to the file being opened and saves it.	Section 4.8.1
Execute I/O System Settings	Executes the I/O system setting.	Section 4.7
Cancel I/O system setting	Cancels the I/O system setting.	Section 4.7
Import Earlier Version of I/O System File	Reads I/O system files from SW0 to SW4.	Section 4.8.4
Exit I/O System Settings	Exits the I/O system setting.	Section 4.2
Edit		
Cut	Cuts the selected setting No..	Section 4.8.2
Copy	Copies the selected setting No..	Section 4.8.2
Paste	Pastes the setting No. cut or copied.	Section 4.8.2
Online		
Monitor Mode	Starts monitor.	Section 4.8.3
Edit Mode	Stops monitor.	Section 4.8.3

		Reference
View		
Tool Bar	Set whether tool bar is displayed or not.	
Status Bar	Set whether status bar is displayed or not.	
Window		
Cascade	Cascades currently open windows.	
Tile	Tiles currently open windows.	
Arrange Icons	Arranges widows reduced to icons.	

(5) Timing chart format input screen function list

File		
Open File	Opens the timing chart data file.	Section 4.5.6
Exit	Exits from timing format input.	Section 4.5.2
Device		
Enter Device	Registers the devices to be setting.	Section 4.5.3
Delete Device	Deletes the registered devices.	Section 4.5.3
List Device	Lists the registered devices.	Section 4.5.6
Property	Changes the display format of the selected device.	Section 4.5.6
Edit		
Undo	Returns to previous status one step before execution.	Section 4.5.6
Bit Device	Sets status of bit device.	Section 4.5.4
Word Device	Sets status of word device.	Section 4.5.4
Wizard	Activates setting of wizard screen.	Section 4.5.4
Insert	Inserts timing to selected section.	Section 4.5.4
Delete	Deletes timing of selected section.	Section 4.5.4
Scan		
Scan Setting	Specifies scan number.	Section 4.5.5

2.3 Devices and Instructions Supported by the Ladder Logic Test Tool (LLT)

The ladder logic test tool (LLT) for the A series, QnA series, FX series, Q series and Motion controller CPU functions operates in the following ranges of devices and instructions.

Function Name	CPU Type	Device	Instruction
A series CPU functions	A0J2H, A1FX, A1S, A1SJ, A1SH, A1SJH, A1N, A2C, A2CJ, A2N(S1), A2S, A2SH, A3N, A2A(S1), A3A, A2U(S1), A2US(S1), A2USH-S1＊1, A3U, A4U	Operates in the device range of the selected CPU type. (See Appendix 1.1.)	Operates with the instructions supported by the ACPU. (See Appendix 2.1.)
QnA series CPU functions	Q2A, Q2AS(H), Q2AS1, Q2AS(H)S1, Q3A, Q4A, Q4AR	Operates in the device range of the selected CPU type. (See Appendix 1.2.)	Operates with the instructions supported by the QnACPU. (See Appendix 2.2.)
FX series CPU functions	FX0(S), FX0N, FX1, FX2(C), FX1S, FX1N, FX2N(C)	Operates in the device range of the selected CPU type. (See Appendix 1.3.)	Operates with the instructions supported by the FXCPU. (See Appendix 2.3.)
Motion controller CPU functions	A171SH (equivalent to A2SH), A172SH (equivalent to A2SH (S1)), A173UH (S1) (equivalent to A3U), A273UH (S3) (equivalent to A3U)	Operates in the device range of the corresponding ACPU. (See Appendix 1.1.)	Operates with the instructions supported by the ACPU. (See Appendix 2.1.) However, motion dedicated instructions (SVST, CHGA, CHGV, CHGT, SFCS, ITP) are not supported. They are not processed.
Q series CPU (A mode) function	Q02-A, Q02H-A, Q06H-A	Operates in the device range of the A4UCPU.	Operates with the instructions supported by the A4UCPU.
Q series CPU (Q mode) function	Q02, Q02H, Q06H, Q12H, Q25H	Operates in the device range of the selected CPU type.	Operates with the instructions supported by the QCPU (Q mode).

＊1: Select CPU type of A2USH-S1 when CPU card A80BD-A2USH-S1 is used.

However, some devices and instructions are restricted or are not supported. Unsupported devices and instructions are not processed (NOP). These NOP instructions are shown on the initial screen of the ladder logic test tool (LLT) as unsupported information. (See Section 3.3.)
See Appendix 1 List of Supported Devices and Appendix 2 List of Supported Instructions for details about the devices and instructions supported by the ladder logic test tool (LLT).

POINT

In this manual, the PLC portion of the motion controller is described as a function of the motion controller CPU.
In addition, the A171SH, A172SH, A173UH(S1), and A273UH(S3) are included in the device/instruction support range of the A2SH, A2SH(S1), A3U, and A3U respectively.

2.4 Ladder Logic Test Tool (LLT) Restrictions and Cautions

The restrictions and cautions when debugging with the ladder logic test tool (LLT) are described below.

2.4.1 Restrictions and cautions common to each type of CPU

(1) Ladder logic test tool (LLT) Processing Time

The ladder logic test tool (LLT) processing time is calculated using 100 ms per scan. The length of each scan becomes the set constant scan time (default = 100 ms).
This is intended to eliminate changes due to computer performance and user-created sequence programs.
The scan time can be set to a value other than 100 ms by changing the constant scan time setting.
(To change the time, you can use D9020 for the ACPU/QCPU (A mode)/motion controller CPU functions, parameter setting for the QnACPU/QCPU (Q mode) functions, or D8039 for the FXCPU functions.)

(2) About timer count-up

In the ladder logic test tool (LLT), the count made by the timer instruction during one scan changes with the constant scan setting and timer speed. At the constant scan setting of 100ms, the 100ms timer counts +1 during one scan and the 10ms timer +10 during one scan. At the constant scan setting of 300ms, the 100ms timer counts +3 during one scan and the 10ms timer +30 during one scan, and at the constant scan setting of 10ms, the 100ms timer counts +1 during 10 scans and the 10ms timer +1 during one scan.

(3) Restarting the ladder logic test tool (LLT)

When restarting the ladder logic test tool (LLT) immediately after ending it, it may take longer than the usual restarting time.

(4) Device Range Checks using I/O System Settings

Appendix 3 shows a table of devices supported by I/O system settings.
The usable device ranges depend on the selected CPU model and parameter setting range. (For details, refer to Appendix-1.)

(5) Interrupt Programs

Interrupt programs are not supported. Any sequence program created is not executed.

(6) Floating Decimal Point

Rounding errors can occur in the results of instructions using the floating decimal point. Therefore, the results may differ from calculations when a CPU is connected.

(7) Read from PLC, Compare with PLC

Not supported by the ladder logic test tool (LLT).

(8) Comments

Not supported by the ladder logic test tool (LLT).

(9) LED Reset Button

The LED display is cleared when the LED reset button on the initial window is clicked. However, the display immediately reappears if the cause of the error has not been removed, so it appears that the LED display is not reset when the button is clicked.

(10) Automatic Writing of the Ladder Logic Test Tool (LLT)

Parameters and sequence programs are written when the ladder logic test tool (LLT) is started up.
As the file register and device initial values are not automatically written, write them to the ladder logic test tool (LLT) using write to PLC.
(If you do not perform Write to PLC on GPPW of SW0D5□-GPPW-E, the file register/device initial values used are the values which were automatically retained when the ladder logic test tool (LLT) was ended last time.)

(11) Restrictions applied to Combinations with GPPW

The following table shows the restrictions that are applied when the LLT is used in combination with the GPPW.

	GPPW					
	SW0D5C/F-GPPW-E	SW1D5C/F-GPPW-E	SW2D5C/F-GPPW-E	SW3D5C/F-GPPW-E	SW4D5C-GPPW-E	SW5D5C-GPPW-E
SW5D5C-LLT-E	△ ∗1, ∗2, ∗3, ∗4, ∗5	△ ∗2, ∗3, ∗4, ∗5	△ ∗3, ∗4, ∗5	△ ∗4, ∗5	△ ∗5	○

○ : No restrictions

△ : Partial restrictions

∗1: When ladder logic test tool (LLT) is running, GPPW program list monitor cannot be selected.

∗2: GPPW does not support the FX series.

∗3: Can not select buffer memory monitor from GPPW, when the ladder logic test tool (LLT) for A series CPU is running.

∗4: GPPW does not support the Q series CPU (Q mode, A mode).

∗5: FX1S and FX1N cannot be selected from GPPW.

Note

It is not possible to install an English version of the ladder logic test tool (LLT) when a Japanese version GPPW is already installed.

(12) Using the I/O system setting file

When I/O system setting of SW4 or earlier versions is to be used, select [File] - [Import Earlier Version of I/O system File] from I/O system settings and read I/O system setting file.
Refer to Section 4.8.4 for details of operation.

(13) Task Bar Settings

If Auto Hide is set in the Windows95/98 task bar settings, the task bar is hidden and not displayed at the bottom of the screen if the GPPW window is displayed at its maximum size and the ladder logic test tool (LLT) initial window is active. The task bar is displayed when the GPPW window is reduced or the GPPW window is set active.

(14) About device range check

If the device range is exceeded in indirect designation using the index register, "OPERATION ERROR" occurs in the ladder logic test tool (LLT).

(15) About real number range check

The ladder logic test tool (LLT) checks the real number range strictly. If any value cannot be evaluated as a real number, "OPERATION ERROR" occurs.

(16) About supported instructions

In the ladder logic test tool (LLT), some instructions are unusable and processed as NOPs.
(Refer to Appendix-2 for the supported instructions.)

(17) About operating CPU types

When selected, the A series CPU/Q series CPU (A mode) operates as the A4UCPU, the QnA series CPU as the Q4ACPU, the FX series CPU as the FXCPU, the motion controller CPU as the A4UCPU, and the Q series CPU (Q mode) as the Q25HCPU.

(18) About I/O modules

The ladder logic test tool (LLT) does not support I/O modules.

(19) About networks

The ladder logic test tool (LLT) does not support networks.

2.4.2 Restrictions and cautions for the A series CPU functions

(1) Special function module Compatibility

The ladder logic test tool (LLT) does not support the special function modules. The special function module buffer memory area capacity is 16 k points × 64 units. It is possible to save to and read from this area but any other access results in an error.

(2) Saving To and Reading From Buffer Memory

Make I/O assignments with GPPW before saving or reading the special function module buffer memory. (See the SW5D5C-GPPW-E Operating Manual.)
It is not possible to save to and read from the buffer area unless I/O assignments are made.

(3) Enabling and Disabling the Parameter Setting Items

Some GPPW parameter settings are disabled by the ladder logic test tool (LLT) even if data is set for them.
The settings disabled by the ladder logic test tool (LLT) are shown below.

Parameter		Setting
PLC parameter	Memory capacity	Disabled other than Sequence and “File register” of “program capacity”.
	PLC system	“Output modes except for STOP→RUN” are disabled.
	PLC RAS	● “Annunciator display mode” is disabled. ● Only “Operation error” and “Special function module access error” in the “operating mode when there is an error” are enabled.
	I/O assignment	All valid.
	Device	“Latch Start” is disabled.
Network Parameter		All disabled.

(4) Microcomputer Programs

Not supported by the ladder logic test tool (LLT).

(5) PLC Memory Clear

Execute to clear all user data written to the ladder logic test tool (LLT) and initialize.
Also execute this function when unstable logic test function (LLT) operation occurs.

(6) A1FXCPU Built-in Functions

If the A1FXCPU type CPU is selected, the A1FXCPU I/O signals become general I/O signals during debugging with the ladder logic test tool (LLT). Consequently, the A1FX functions are identical to the I/O module functions.

(7) About numeric value range check

Checking the numeric value range strictly, the ladder logic test tool (LLT) detects any illegal operation whose divisor is 0.
Execution of 0 ÷ 0 will result in "OPERATION ERROR".

(8) About illegal instructions in dedicated instructions

The ladder logic test tool (LLT) checks the dedicated instructions for illegal instructions and displays "INSTRUCT CODE ERR.", if any.

(9) About special function module (special function block)

The ladder logic test tool (LLT) supports only the buffer memory area of a special function module (special function block).

(10) About memory cassette capacity

The ladder logic test tool (LLT) has no memory cassette capacity. A lot of data which would result in an excess of capacity on the actual device will not result in an error and will be written properly.

2.4.3 Restrictions and cautions for the QnA series CPU functions

(1) Special Function Module Compatibility

The ladder logic test tool (LLT) does not support the special function modules. The special function module buffer memory area capacity is 16 k points × 64 modules. It is possible to save to and read from this area but any other access results in an error.

(2) Saving To and Reading From Buffer Memory

Make I/O assignments with GPPW before saving or reading the special function module buffer memory. (See the SW5D5C-GPPW-E Operating Manual.)
It is not possible to save to and read from the buffer area unless I/O assignments are made.

(3) Enabling and Disabling the Parameter Setting Items

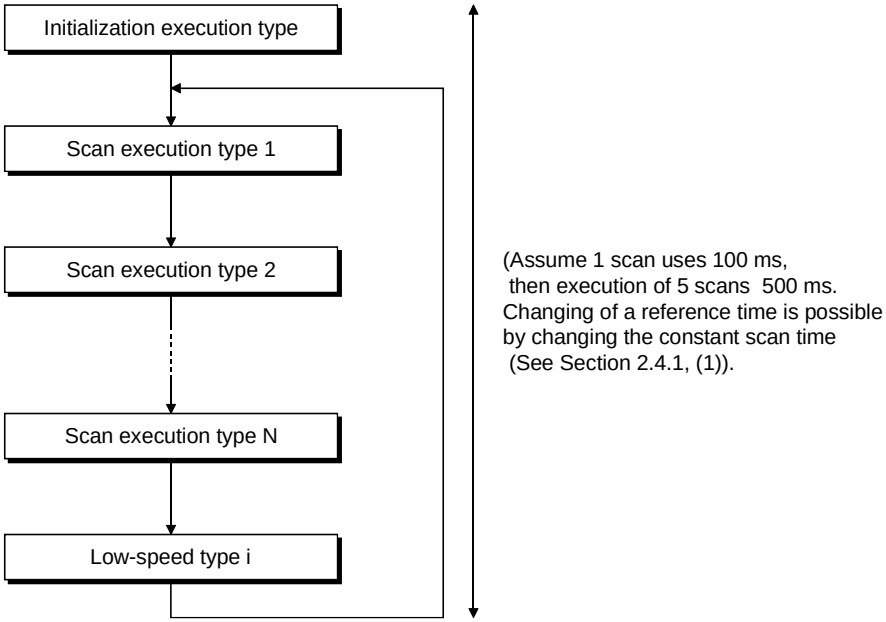
Some GPPW parameter settings are disabled by the ladder logic test tool (LLT) even if data is set for them.
The settings disabled by the ladder logic test tool (LLT) are shown below.

Parameter		Setting
PLC parameter	PLC name	All disabled.
	PLC system	Disabled, except for "Output mode at STOP to RUN" and "Common pointer No."
	PLC file	● The corresponding memory for the "file register" is disabled. ● The "comment file used in a command" is disabled. ● The "corresponding memory" for the "device initial value" is disabled. ● The "corresponding memory" for the "file for local device" is disabled.
	PLC RAS	● "Error Check" is disabled. ● Only "Operation error" and "Special function module access error" in the "operating mode when there is an error" are enabled. ● "Annunciator display mode" is disabled. ● "Break down history" and "Lowspeed program execution time" are disabled.
	I/O assignment	"Standard settings" (base, Power supply unit, Increase cable) are all disabled.
	Device	"Latch Start" is disabled.
	Program	All valid.
	Boot file	All disabled.
	SFC	All disabled.
Network Parameter		All disabled.

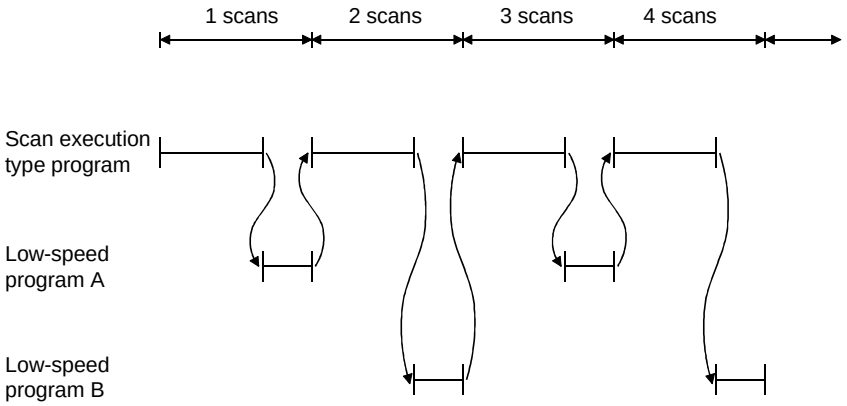
(4) Execution of Low-speed Programs

Regardless of the constant scan setting or setting of the low-speed program execution time, the ladder logic test tool (LLT) always executes the low-speed programs after the scan execution programs.

The program execution sequence is show below. (This sequence is identical during step operation.)



During each scan, all scan programs are executed before one low-speed type program is executed. Consequently, if N low-speed programs are set, N scans are required to execute them all.



POINT

Since a low-speed program is always completed within one scan, the monitor value of SM510 is always OFF.

(5) Device Memory Monitor Device Range Check

T31744 to T32767, SB800 to SB7FFF, and SW800 to SW7FFF are used by the system and are unavailable for monitoring or testing.

(6) Function register (FD) monitor

Monitor of function register (FD) cannot be executed from menu of ladder logic test tool (LLT): Execute only from menu of GPPW.

(7) TTMR Instruction Restrictions

A present value cannot be changed during TTMR instruction execution.

(8) I/O System Setting Device Range Check

SB800 to SB7FFF and SW800 to SW7FFFare used by the system and cannot be assigned.

(9) SFC Programs

Not supported by the ladder logic test tool (LLT).

(10) PLC Memory Format

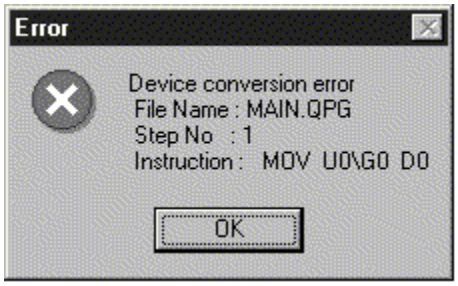
Execute to clear all user data written to the ladder logic test tool (LLT) and initialize.

Also execute this function when unstable logic test function (LLT) operation occurs.

(11) "MISSING END INS" Errors

If a buffer register (Un\G) with no I/O assignment is used for a program or status setting, "MISSING END INS" is displayed on the LED display.

After correctly setting the I/O assignments, write the parameters to the ladder logic test tool (LLT).



(12) About special function module (special function block)

The ladder logic test tool (LLT) supports only the buffer memory area of a special function module (special function +block).

(13) About built-in RAM/memory cassette capacity

The ladder logic test tool (LLT) has no built-in RAM/memory cassette capacity.

A lot of data which would result in an excess of capacity on the actual device will not result in an error and will be written properly.

2.4.4 Restrictions and cautions for the FX series CPU functions

(1) CPU Type Selection and FXCPU Operation

The ladder logic test tool (LLT) for the FX series CPU functions operate according to the CPU functions and device range of the selected CPU. Application instructions not supported by the selected CPU operate with the ladder logic test tool (LLT).

In cases where the sequence program may contain instructions not supported by the actual PLC due to conversion of a program for a higher model to a program for a lower model or due to input in the list mode, a program error occurs when the sequence program is written to the actual PLC, even if the program runs with the ladder logic test tool (LLT).

For example, the FX_0, FX_{0S} and FX_{0N} PLCs do not support pulse-execution application instructions, but these instructions run with the ladder logic test tool (LLT). Even so, a program error occurs when this program is written to the actual PLC because it contains non-supported instructions.

(2) STOP → RUN Program Check

A program error is detected by the STOP → RUN program check only if MC/MCR exists in the STL instruction or if no RET instruction is input for a STL instruction.

No other items are detected by the STOP → RUN program check. Therefore, use the GPPW program check functions in advance to check for these other errors.

(3) Program Memory Capacity

The maximum step capacity for each model is set.

(4) Watchdog Timer

The watchdog timer (D8000) operates every 200 ms for all CPUs. It can be rewritten but the written value has no effect on its operation.

(5) Debugging

The skip execution, partial execution, and step execution functions are only valid when using the ladder logic test tool (LLT). They cannot be used when an actual PLC is connected.

(6) Buffer Memory Monitor

The special extension device buffer memory in the ladder logic test tool (LLT) operates as general registers which allow reading and writing using FROM/TO instructions. This memory does not posses any special functions from the special extension devices.

(7) Analog Volume

The data registers (D8013, D8030, and D8031) storing the analog volume values for the FX_0, FX_{0S}, FX_{0N}, FX_{1S}, and FX_{1N} PLCs operate as normal data registers. Use the GPPW device test functions to write values between 0 and 255 to these registers for testing.

(8) SORT Instruction

The SORT instruction is executed in the actual PLC over multiple scans. However, it is executed completely in a single scan in the ladder logic test tool (LLT) and M8029 (complete flag) operates immediately.

(9) SFC Programs

Testing of SFC program for FXCPU described as STL instructions is possible with ladder logic test tool (LLT) of SW2D5□-LLT-E or later version.
SFC programs for FXCPU corresponding to GPPW later than SW5D5C-GPPW-E can also be tested with ladder logic test tool (LLT) of SW2D5□-LLT-E or later version.
However, when debugging is to be executed with step execution from SFC display screen of GPPW, ladder logic test tool (LLT) of SW5D5C-LLT-E or later version must be used.

(10) Handling Keep Devices

Contents are maintained at a logic test function (LLT) STOP.
Contents are cleared when the ladder logic test tool (LLT) is quit.

(11) Handling Non-Keep Devices

Contents are cleared at a logic test function (LLT) STOP or when the ladder logic test tool (LLT) are quit.

(12) Memory Clear

Execute to clear all user data written to the ladder logic test tool (LLT) and initialize.
Also execute this function when unstable logic test function (LLT) operation occurs.

(13) Quick startup of the ladder logic test tool (LLT) with the FX series CPU

When the ladder logic test tool (LLT) is used combining SW5D5C-LLT-E or later and SW5D5C-GPPW-E or later, the GPPW executes quick startup of the ladder logic test tool (LLT). When other combinations are used, it starts up the LLT at normal speed.

(14) About step execution, skip run and partial run

Compatible with step execution, skip run and partial run, the ladder logic test tool (LLT) ensures more efficient debugging.
Refer to (9) for the step execution of SFC programs.

(15) About special function module (special function block)

The ladder logic test tool (LLT) supports only the buffer memory area of a special function module (special function block).

2.4.5 Restrictions and cautions for the Motion controller CPU functions

(1) Motion controller CPU Type Selection and Applicable CPU Type

The range of devices or instructions of a motion controller CPU are those of the applicable CPU.

The table below shows the types of CPU applicable to the motion controller.

Motion Controller CPU	Applicable CPU
A171SH	A2SH
A172SH	A2SH (S1)
A173UH (S1)	A3U
A273UH (S3)	A3U

(2) Motion dedicated instructions

The ladder logic test tool (LLT) does not support motion dedicated instructions. Thus, when an attempt is made to use motion dedicated instructions on the ladder logic test tool (LLT), nothing will be processed. (NOP)

Motion dedicated instructions are only the following six;
SVST, CHGA, CHGV, CHGT, SFCS, and ITP.

REMARK

Any restrictions and cautions other than the ones described above are the same as those for the A series CPU functions. For the restrictions and cautions for the A series CPU functions, refer to Section 2.4.2.
For details of the motion controller CPU, refer to the Motion Controller CPU User's Manual.

2.4.6 Restrictions and precautions for the Q series CPU functions

1) A mode

For the Q series CPU (A mode) functions, the A series CPU functions perform as equivalent to those of the A4U, and therefore, refer to the restrictions on the A series CPU.

2) Q mode

(1) Compatibility with the special function module

The ladder logic test tool (LLT) does not support the special function module. However, it has the area of 64k points×64 modules for the buffer memory of the special function module. This area can be accessed, but access beyond that will result in an error.

(2) About saving/reading the buffer memory data

When saving/reading the buffer memory data of the special function module, always make I/O assignment on GPPW. (Refer to the SW5D5C-GPPW-E Operating Manual.)
Without I/O assignment, buffer memory data cannot be saved/read.

(3) About validity of parameter setting items

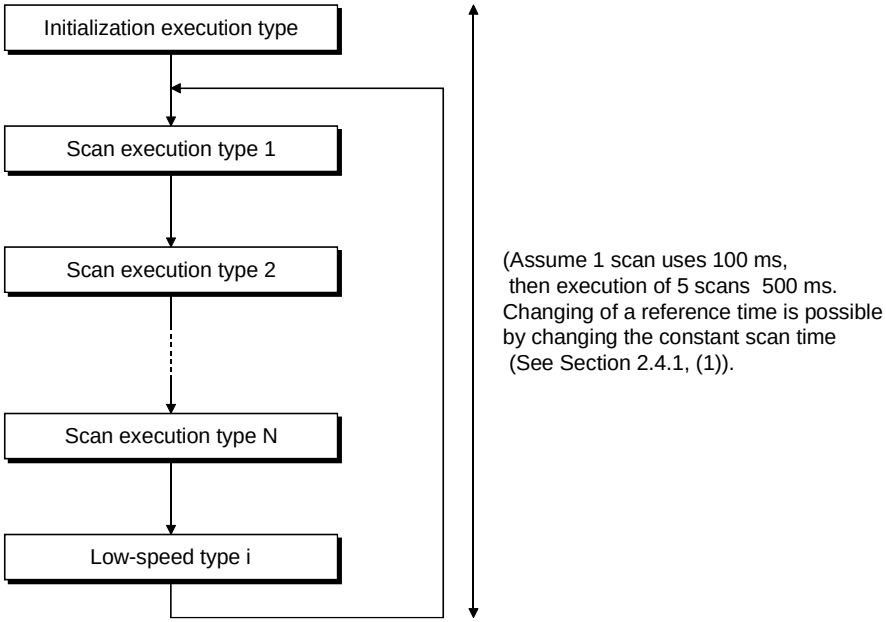
Among the parameter setting items of GPPW, there are setting items which will be invalid for the ladder logic test tool (LLT) if their data have been set.
The following setting items are invalid for the ladder logic test tool (LLT).

Parameters		Setting Item
PLC parameter	PLC name setting	All invalid.
	PLC system setting	Items except "timer time limit setting", "STOP-RUN/output mode" and "common pointer No." are invalid.
	PLC file setting	● "Target memory" of "file register" is invalid. ● "Comment file used for instructions" is invalid. ● "Target memory" of "device initial value" is invalid. ● "Target memory" of "file for local devices" is invalid.
	PLC RAS setting	● "Error check" is invalid. ● Items other than "operation error" and "special function module access error" in "error-time operation mode" are invalid. ● "Fault history" and "low-speed program running time" are invalid.
	I/O assignment	● "Model", "switch setting" and "detail setting" of "I/O assignment" are invalid. ● "Basic setting" (base, power supply module, extension cable) is invalid.
	Device setting	"Latch range" is invalid.
	Program setting	● "Comment" of "file using method setting" is invalid. ● "I/O refresh setting" is invalid.
	Boot file setting	All invalid.
	SFC setting	All invalid.
Network parameters		All invalid.
Multiple CPU setting		Invalid except “No. of PLC”

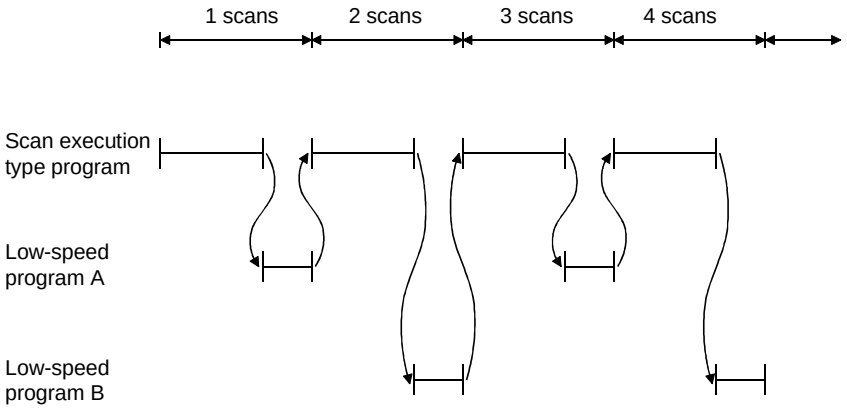
(4) Execution of Low-speed Programs

Regardless of the constant scan setting or setting of the low-speed program execution time, the ladder logic test tool (LLT) always executes the low-speed programs after the scan execution programs.

The program execution sequence is show below. (This sequence is identical during step operation.)



During each scan, all scan programs are executed before one low-speed type program is executed. Consequently, if N low-speed programs are set, N scans are required to execute them all.

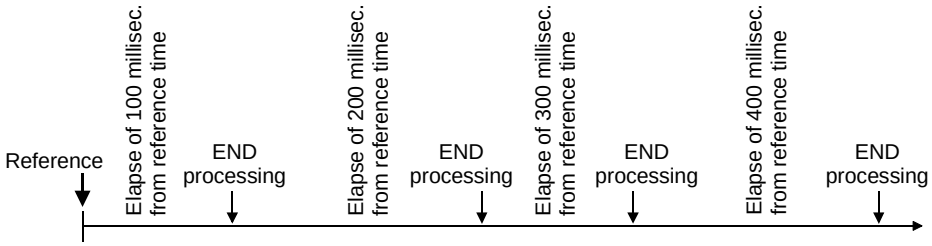


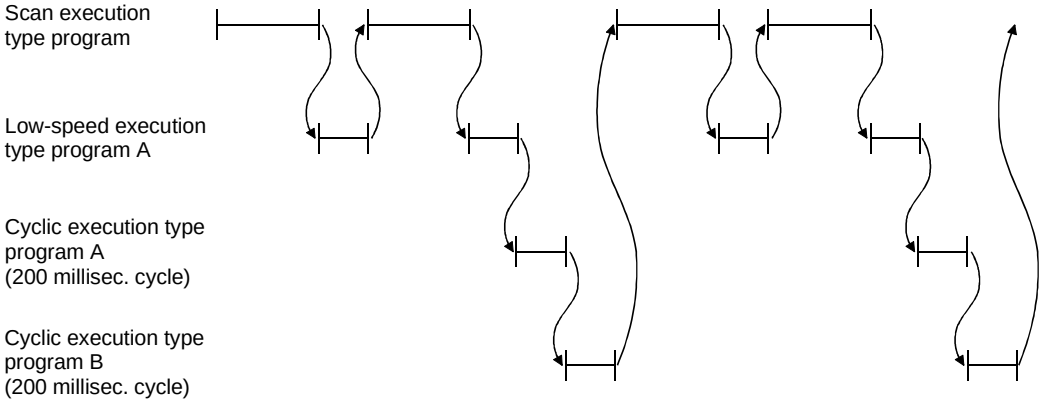
POINT

Since a low-speed program is always completed within one scan, the monitor value of SM510 is always OFF.

(5) About operation of cyclic execution program

A cyclic program judges whether it can run or not by measuring time after the end of a scan execution type and a low-speed execution type. The following timing chart shows the LLT processing timing at the scan time setting of 100 milliseconds and the cyclic program setting of every 200 milliseconds.





(6) About monitoring the function register (FD)

The function register (FD) cannot be monitored from the ladder logic test tool (LLT) menu. Monitor it from the GPPW menu.

(7) About restrictions on TTMR instruction

During execution of the TTMR instruction, the current value cannot be changed.

(8) About SFC program

Not supported by the ladder logic test tool (LLT).

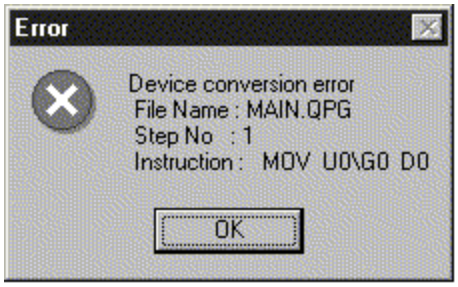
(9) About PLC memory format

Execute to clear all user data written to the ladder logic test tool (LLT) and initialize.

Also execute this function when unstable logic test function (LLT) operation occurs.

(10) "MISSING END INS" Errors

If a buffer register (Un\G) with no I/O assignment is used for a program or status setting, "MISSING END INS" is displayed on the LED display.
After correctly setting the I/O assignments, write the parameters to the ladder logic test tool (LLT).



(11) About built-in RAM/memory cassette capacity

The ladder logic test tool (LLT) has no built-in RAM/memory cassette capacity.
A lot of data which would result in an excess of capacity on the actual device will not result in an error and will be written properly.

(12) About intelligent function module

The ladder logic test tool (LLT) supports only the initial value setting, automatic refresh setting and buffer memory area of the intelligent function module.

3) Q mode (multiple CPU system)

(1) About the LLT Compatibility with multiple CPU system

The LLT can't be compatible with multiple CPU action itself.
There are reasons that the LLT doesn't support multiple starts and isn't conscious of the number of own machine which is necessary for multiple CPU action. (Consciousness of what number the own machine is in some CPUs.)
It is only the part of the minimum requirements (it run as a single CPU sequence program) to run sequence program (project) for applicable multiple CPU which was written by the GPPW.

(2) I/O assignment

I/O assignment parameter of the GPPW appoints control CPU to each I/O and intelligent function units.
Although it is able to read the control information to the LLT, the function isn't compatible without consciousness of own machine. (If it is multiple applicable parameter, it isn't the error for I/O assignment of the LLT original.)

(3) Difference between the LLT and the practical machine under the access instruction to the shared memory of multiple CPU

Although we use description of own machine/the other machine for expression of difference between the LLT and the practical machine, the LLT have no discrimination between own machine/the other machine.

Program	FROM	own machine/the other machine possible (in case of the practical machine, own machine impossible)
	Read G device	own machine/the other machine possible (in case of the practical machine, own machine impossible)
	Write G device	own machine/the other machine possible (in case of the practical machine, impossible)
	S. TO	Impossible (in case of the practical machine, own machine possible)
General data	Batch monitoring G device	possible (in case of the practical machine, own machine impossible)
	G device test	possible (in case of the practical machine, own machine impossible)

(4) The LLT compatibility under the additional instruction with multiple applicable CPU

Instruction	Management	Content
S. TO	NOP	Write to the shared memory of own machine CPU during configuration of multiple CPU
FROM	Support	Possible to read from the shared memory of the other machine with current FORM instruction during configuration of multiple CPU
COM	NOP	Add automatic refresh function to current COM instruction during configuration of multiple CPU

2.5 Ladder Logic Test Tool (LLT) Safety and Handling Precautions

The safety and handling precautions for the ladder logic test tool (LLT) are described below.

(1) The ladder logic test tool (LLT) simulates the actual PLC to debug sequence programs. However, the correct operation of a debugged sequence program cannot be guaranteed.
After debugging with the ladder logic test tool (LLT), before running the program in an actual application, connect a actual PLC and conduct a normal debugging operation.

(2) The calculated results may differ from actual operation because the ladder logic test tool (LLT) does not access the I/O modules or special function modules and do not support some instructions and devices.
After debugging with the ladder logic test tool (LLT), before running the program in an actual application, connect an actual PLC and conduct a normal debugging operation.

MEMO

3. COMMON OPERATIONS FOR THE LADDER LOGIC TEST TOOL (LLT)

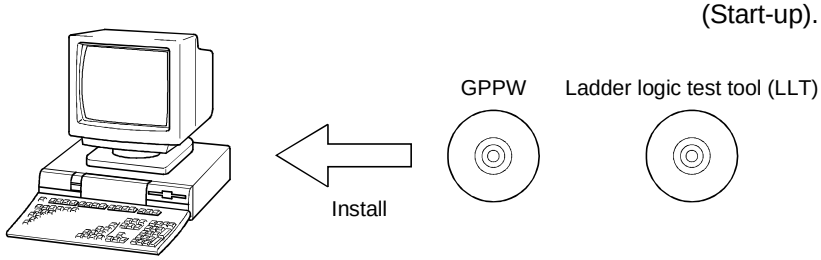
3.1 Procedure from Installation to Debugging

This section describes the procedures from installing the ladder logic test tool (LLT) to debugging a sequence program.

Procedure 1

Install GPPW and the ladder logic test tool (LLT) in the personal computer.

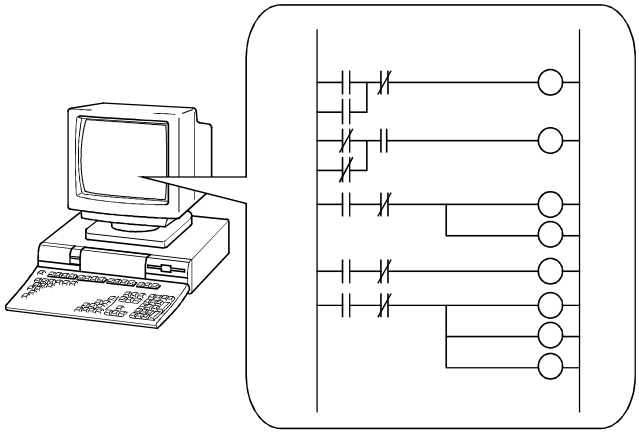
See the SW5D5C-GPPW-E Operating Manual (Start-up).



Procedure 2

Use GPPW to create a sequence program.

See the SW5D5C-GPPW-E Operating Manual.



Procedure 3

In GPPW, set the parameters to assign the I/Os (for A/QnA/Q series CPU functions) and make the program settings (for QnA series/ Q series (Q mode) CPU functions).

See the SW5D5C-GPPW-E Operating Manual.

POINTS

(1) Always do the program settings for the QnA series/Q series CPU function.
If you do not make the program settings and the GPPW is of version later than SW1D5□-GPPW-E the following will occur.
1) The ladder sequence (list) of the active window of GPPW will be written.
2) The sequence program will not be written, if the active window is not a ladder (list) window or if there are no active windows.
(In case of GPPW of SW0D5□-GPPW-E, the sequence program will not be written if you do not make the program settings.)

(2) Please set the I/O assignments (for A/QnA/Q series CPU function) before reading/writing the buffer memory of special function module.

(To next page)

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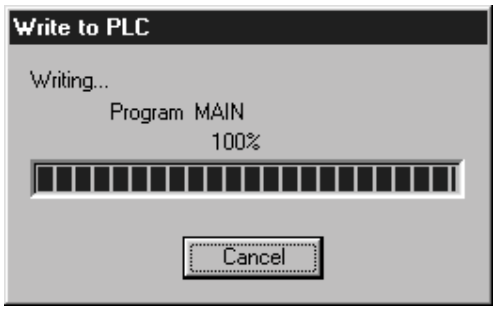
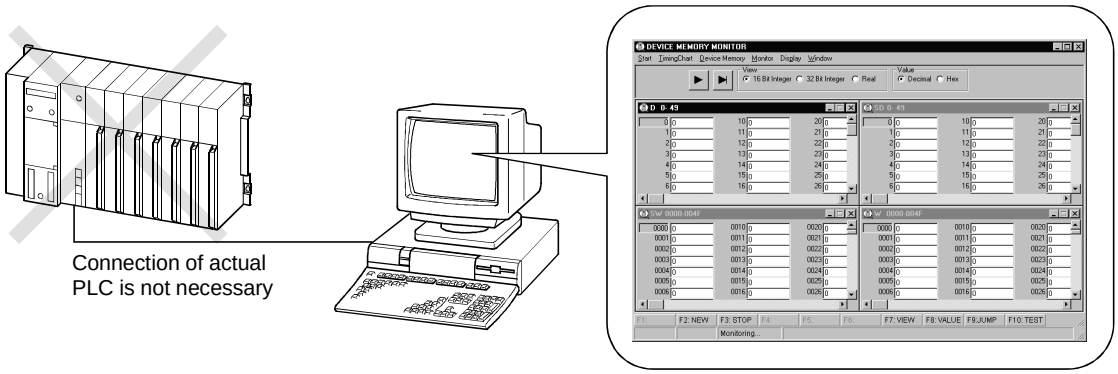
Procedure 4

Select the [Tools] → [Start ladder logic test] GPPW menu items to start the ladder logic test tool (LLT). The sequence program and parameters created with GPPW are automatically written to the ladder logic test tool (LLT) (equivalent to write to PLC).



Procedure 5

Debug the sequence program using the ladder logic test tool (LLT) and GPPW functions.
Debugging is possible by using the device monitor, changing arbitrary device values, or simulation of machine operation.
📖See Chapter 4 I/O System Setting Functions and Chapter 5 Monitor Test Functions.
📖See the SW5D5C-GPPW-E Operating Manual.



Procedure 6

After debugging, modify the sequence program.
📖See the SW5D5C-GPPW-E Operating Manual.

Procedure 7

Set the execution status in the initial window to STOP.
If necessary, save the contents of the device memory and special function module buffer memory.
📖See Chapter 6 Tool Functions.

Procedure 8

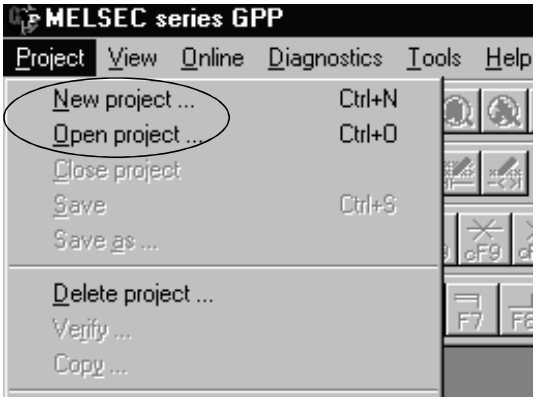
Select the [Online] → [Write to PLC] GPPW menu items to write the modified program to the ladder logic test tool (LLT).
📖See the SW5D5C-GPPW-E Operating Manual.

To debug the program again, repeat Procedures 5 to 8.

3.2 GPPW Operations before Debugging

This section describes the GPPW operations required before debugging with the ladder logic test tool (LLT).
Conduct the operations described below before debugging a program with the ladder logic test tool (LLT).

(1) Make the Project to Create the Sequence Program.
To create a new project, select [Project] → [New project] from the GPPW menus and make the required settings.
To read an existing project, select [Project] → [Open project] from the GPPW menus and select the project.

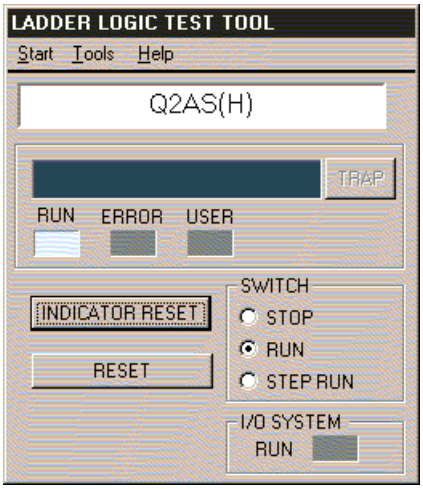


(2) Create the Sequence Program.

(3) On the GPPW side, make parameter settings for I/O assignment (for A/QnA/Q series CPU functions), program setting (for QnA series/Q series (Q mode) CPU functions), etc.

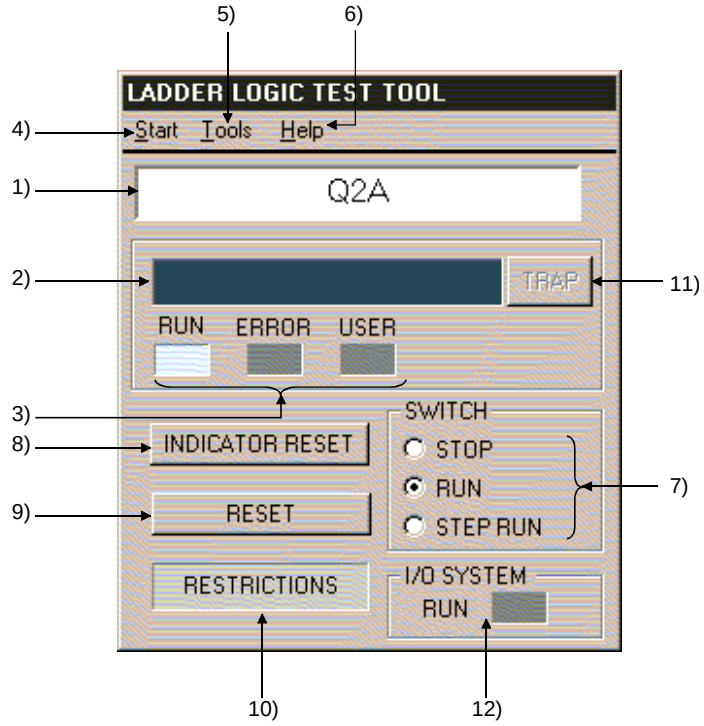
POINT
Always do the program settings for the QnA series CPU function. If you do not make the program settings and the GPPW is of version later than SW1D5□-GPPW-E the following will occur. (1) The ladder sequence (list) of the active window of GPPW will be written. (2) The sequence program will not be written, if the active window is not a ladder (list) window or if there are no active windows. (In case of GPPW of SW0D5□-GPPW-E, the sequence program will not be written if you do not make the program settings.)

(4) Select the [Tools] → [Start ladder logic test] GPPW menu items to start the ladder logic test tool (LLT). An initial window as shown below is displayed.
The sequence program and parameters are automatically written to the ladder logic test tool (LLT) when the ladder logic test tool (LLT) are started by GPPW.
Offline debugging of the sequence program using the ladder logic test tool (LLT) is now possible.



3.3 Description of the Initial Window Display

A ladder logic test tool (LLT) initial window as shown below is displayed when the ladder logic test tool (LLT) is started.
This section describes the items displayed in the ladder logic test tool (LLT) initial window.



Number	Name	Description
1)	CPU type	Displays the currently selected CPU type.
2)	LED Indicators	• Can display up to 16 characters. • The indicator display is equivalent to the display of CPU operation errors.
3)	Operation Status LEDs	• RUN/ERROR: Valid for all of the QnA, A, FX, Q series CPU and motion controller CPU functions. • USER : Appears only for the QnA series/Q series (Q mode) CPU functions.
4)	Start	Enables the selection of [Device Memory Monitor] and [I/O System Settings].
5)	Tools	Use the Tools menu to execute the tool functions. Refer to Chapter 6 Tool Functions.
6)	Help	Displays the ladder logic test tool (LLT) licensee name and software version.
7)	Switch Display and Settings	Displays the execution status of the ladder logic test tool (LLT). Click on the radio buttons to change the execution status.
8)	INDICATOR RESET button	Click to clear the LED display.
9)	RESET button	• Click to reset the ladder logic test tool (LLT) • Displayed only for the A, QnA, Q, and Motion controller series CPU functions.
10)	Unsupported information indicator lamp	• Displayed only when unsupported instructions or devices for the ladder logic test tool (LLT) is found. • Double clicking this indicator will display the unsupported instructions that have been changed to NOP instructions and their steps.
11)	Error advance display button	Clicking this button will display the descriptions of issued errors, error steps, and the name of files in which the error is issued. (The names of error files are displayed only when using the QnA series/ Q series (Q mode) CPU function.)
12)	I/O system setting LED	• LED lights up during execution of I/O system setting. • Double clicking this will show the contents of current I/O system settings.

3.4 Ending the Ladder Logic Test Tool (LLT)

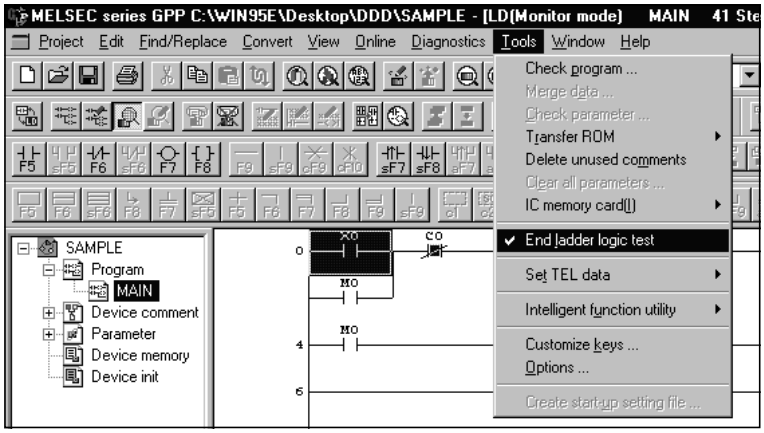
[Purpose]

To end the ladder logic test tool (LLT).

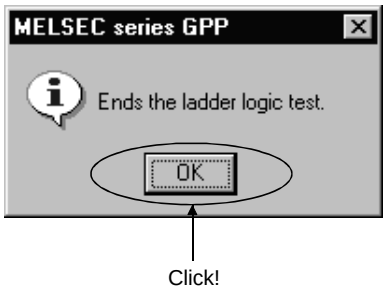
[Operation procedure]

(1) Select [Tool] - [End ladder logic test] of GPPW menu.

You can also click  of GPPW for above.



(2) When the dialog box appears, click the OK button.



4. SIMULATION OF EXTERNAL DEVICE OPERATION --- I/O SYSTEM SETTING FUNCTIONS

The I/O system setting functions allow simulation of the operation of external devices. In conventional debugging, a debugging sequence program was created to simulate the operation of the external devices.
Using the I/O system setting functions, the operation of the external devices can be automatically simulated without the requirement to create a special debugging sequence program.

(1) Differences between Conventional Debugging and Debugging with the I/O System Setting Functions

A comparison between conventional debugging with an actual PLC connected and debugging using the I/O system setting functions is shown below.

(a) Conventional Debugging

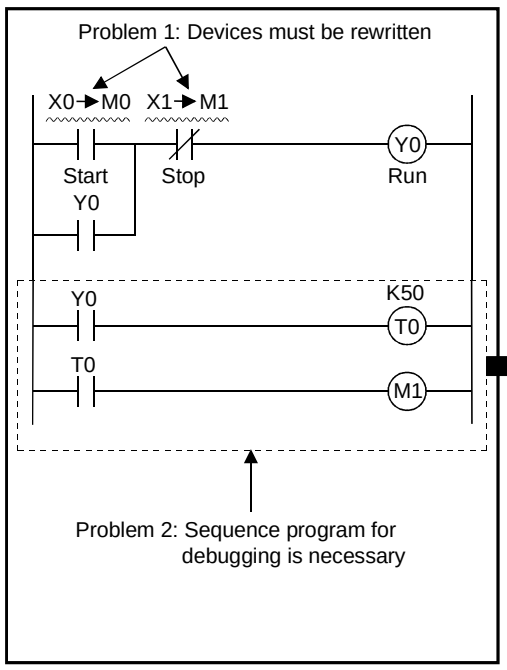
The program must be modified as follows for debugging:

- Add a debugging sequence program to simulate operation of the external devices.
- As an input (X) can be turned ON/OFF only with an external device connected to the I/O unit, modify the program by changing X0 → M0, X1 → M1, etc. to conduct debugging with no external device connected.

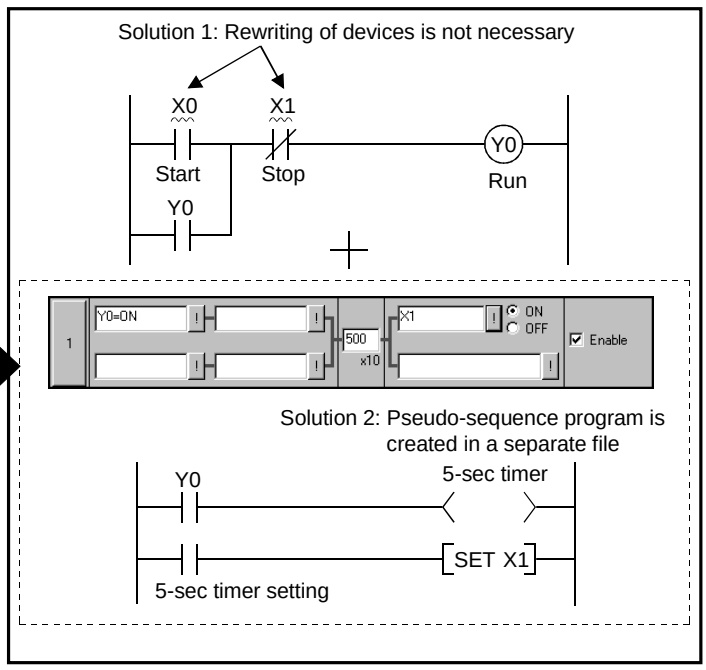
(b) Debugging using the I/O System Settings

The I/O system setting function allows sequence program settings and changes to be made for debugging from the setting window.
It is unnecessary to add a sequence program. It is not necessary to rewrite the devices (X0 → M0) as the inputs (X) can be directly turned ON/OFF from GPPW.

<Program used in conventional debugging>



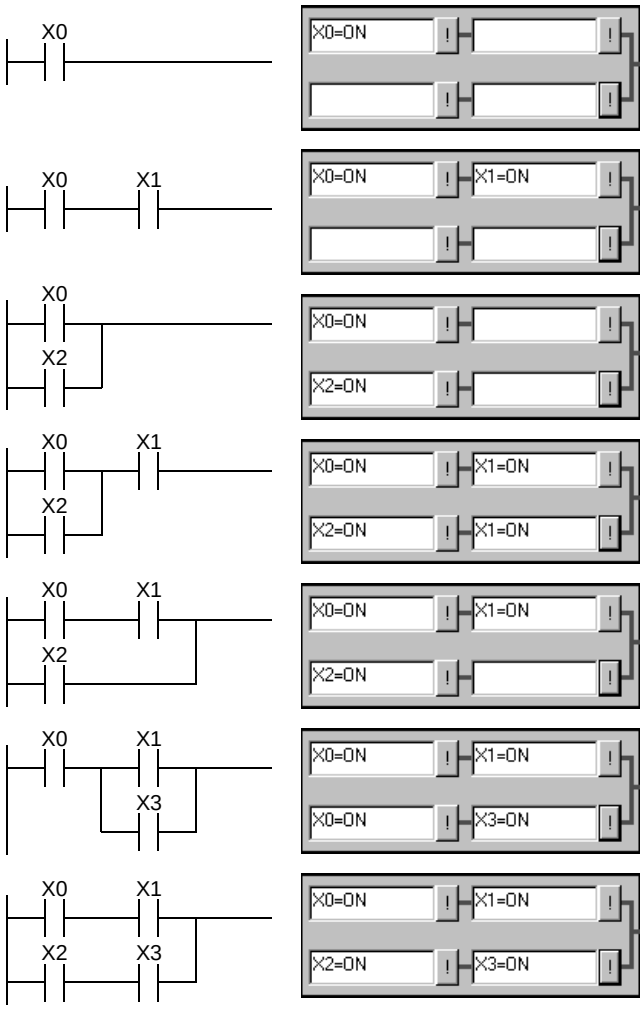
<Program used for debugging using the ladder logic test tool (LLT)>



(2) Conditions for simulation

With I/O system setting, optional operation will be performed after the condition is fulfilled.

By combining conditions, conditions equivalent to the following circuits can be set.

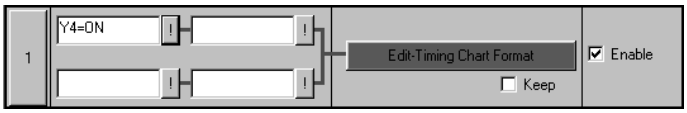


(3) Timing chart input and device value input

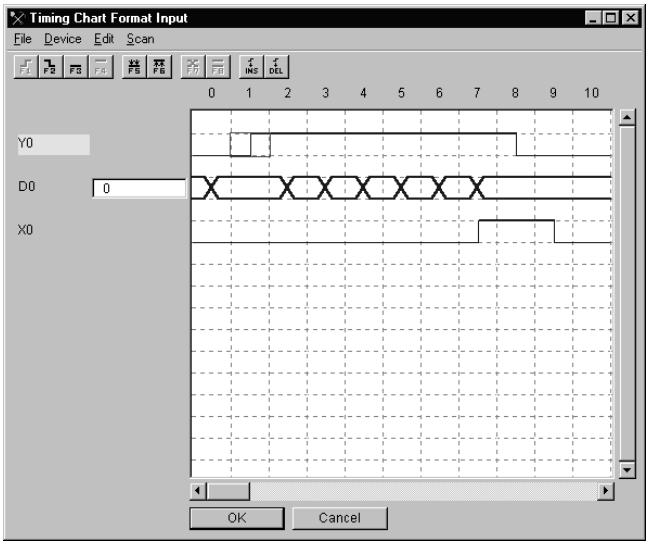
With I/O system setting, there are two inputs: one is timing chart input to execute timing chart prepared by user after condition is fulfilled; the other is device value input to set optional device value after specified time has elapsed.
Differences between the above two inputs are described below.

(a) Timing chart input

When condition set by user has been fulfilled, timing chart set by the user can be operated.
With this input, complicated operations, such as "When Y0 is turned ON, D0 is counted up, Y0 is turned OFF when X0 is turned ON", can be set.
However, the timer cannot be set: If timer is to be used, select device value input.

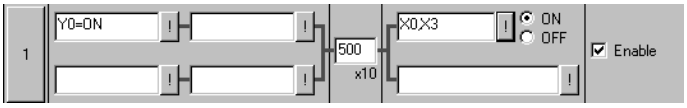


<Timing chart format input screen>



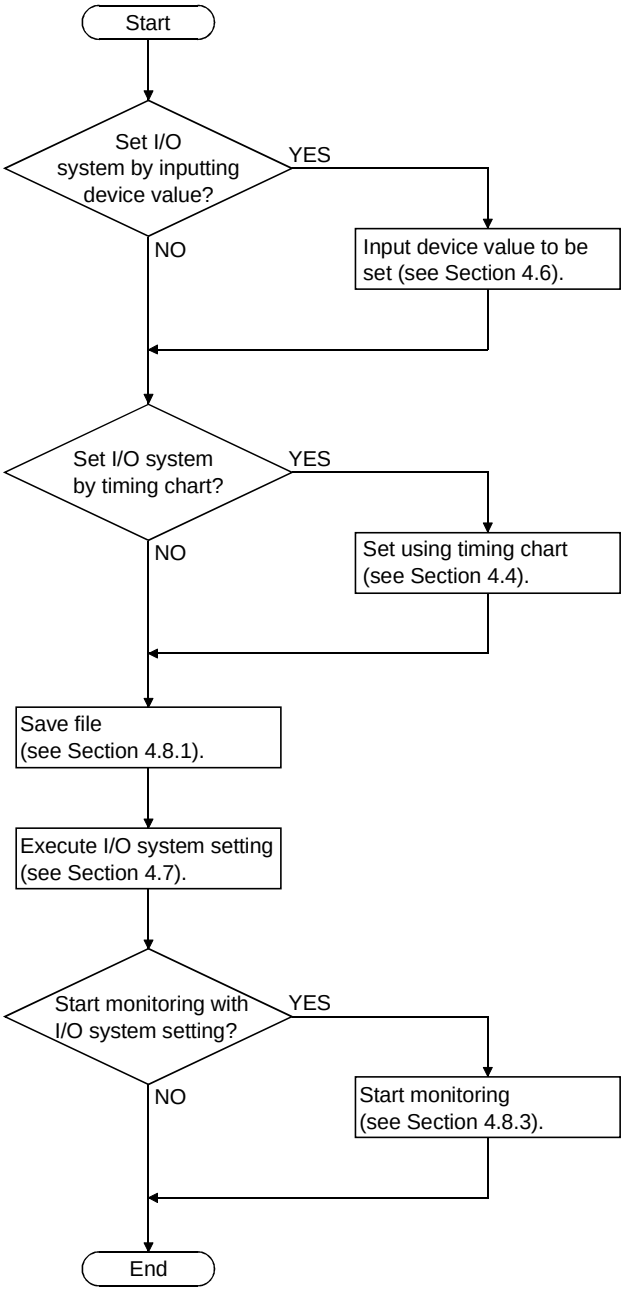
(b) Device value input

When condition set by user has been fulfilled, specified device value can be changed after an optional time has elapsed.
With this input, an operation such as "When Y0 is turned ON, 5 seconds later X0 and X3 are turned ON" can be set.



4.1 I/O System Setting Operation Procedure

Operation procedure for I/O system setting is shown below.



4.2 Start and End of I/O System Setting

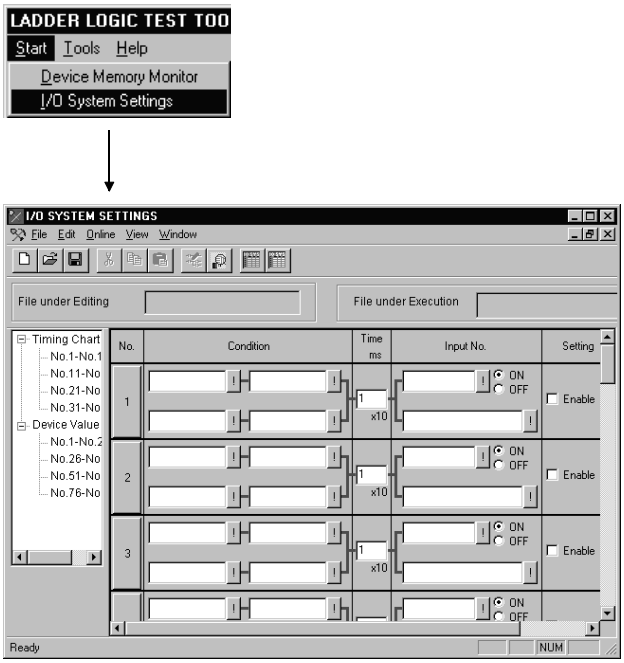
(1) Starting I/O system setting

[Purpose]

To start I/O system setting.

[Operation procedure]

Select [start] - [I/O system settings] from the initial window.



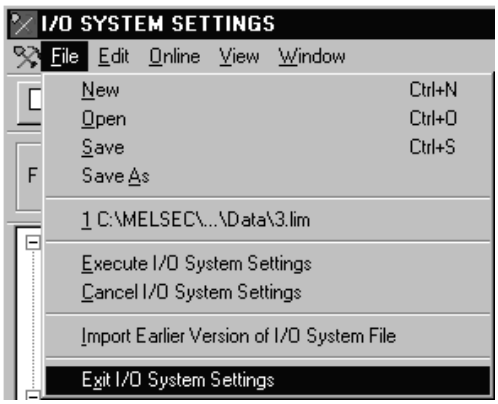
(2) Ending I/O system setting

[Purpose]

To end I/O system settings.

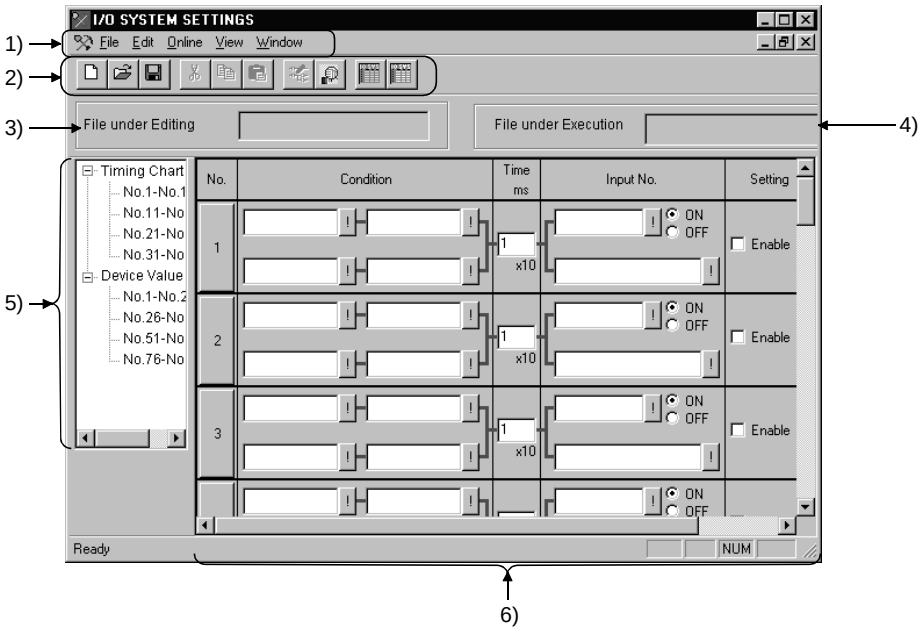
[Operation procedure]

Select [File] - [Exit I/O System Settings] from I/O system settings screen.



4.3 Configuration of I/O System Settings Screen

I/O system settings screen is opened by clicking [Start] - [I/O System Settings] of initial window. Configuration of I/O system settings screen is shown below.



1) Menu bar

Name of menu that can be used in I/O system settings is displayed.
When menu has been selected, drop-down menu will be displayed and various functions from this menu can be used.

2) Tool bar

From functions assigned by menu bar, those most frequently used are displayed with buttons.

3) File during editing

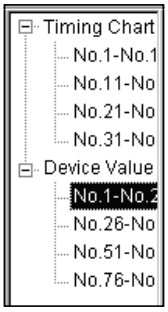
Displays name of file being edited.

4) File being executed.

Displays name of file registered as I/O system execution file.

5) I/O system settings tree

Selects setting method of I/O system settings.



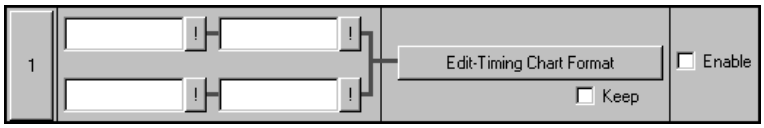
• Timing chart input
Double-click column of number to be set: I/O system setting with timing chart format can now be performed.
Ups to 40 settings (from No. 1 to No. 40) are possible.

• Device value input
Double-click column of number to be set: I/O system setting with device value set can now be performed.
Ups to 100 settings (from No.1 to No.100) are possible.

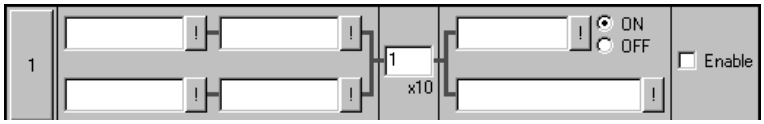
6) Edit/monitor screen

Editing and monitoring of I/O system settings are performed using this screen.

• In timing chart input mode (see Section 4.4)



• In device value input mode (see Section 4.6)



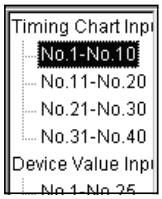
4.4 Setting by Using Timing Chart

This section describes how to perform I/O system settings using timing chart.

[Operation procedure]

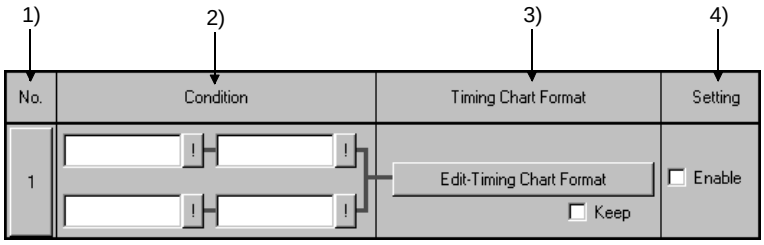
(1) Select [Start] - [I/O System Settings] from initial window.

(2) Double-click column of number to set timing chart as shown below.



[Setting window]

Make the setting below in I/O system setting dialog box.



1) No.

The number of settings in the I/O system setting dialog box.

Up to 40 settings can be chosen.

When clicked, set No. is made object of Cut, Copy or Paste.

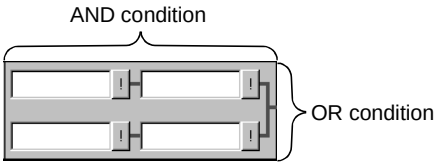
2) Condition

Designates the input condition from ladder logic test tool (LLT).

The input conditions can be designated as either a bit device or a word device.

For a bit device, designation condition is ON/OFF; for a word device, designation condition is a comparison (=,<>,<,>,<=,>=) with a constant or another word device.

In addition, relational conditions can be set by specifying AND/OR operation.



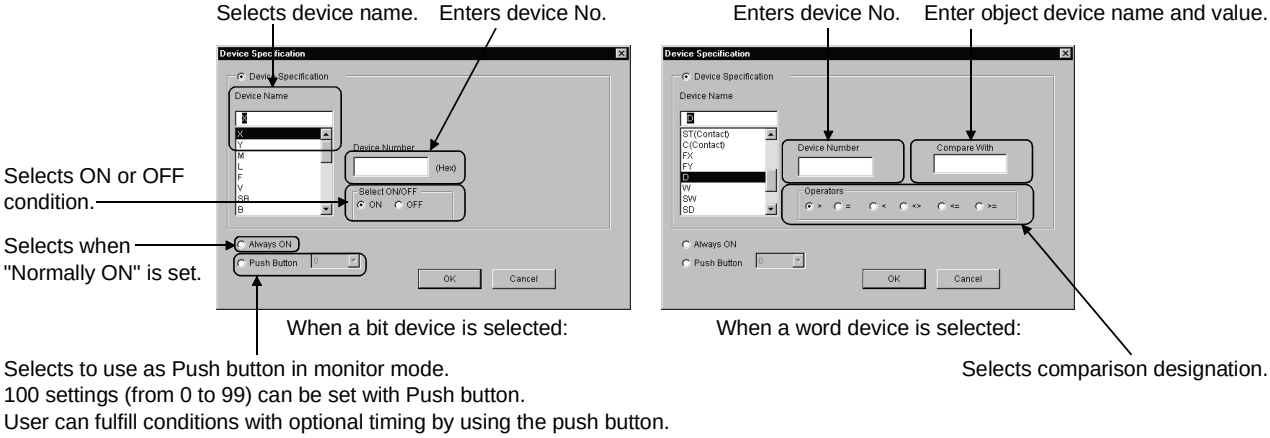
AND••••The condition will be fulfilled if both designated conditions on the left and right are achieved. Otherwise, the condition will not be fulfilled.

OR•••••The condition will be fulfilled if either or both of designated conditions in upper and lower columns are achieved.

• Input method (direct input)
Entering condition expression directly can perform setting.
<Example>
For a bit device: X0=OFF, M10=ON
For a word device: D5<20, D15<>5, D20=2, D25>=10, D0=D50

• Input method (entering by using dialog box)
Click button and enter device name, device No., designated condition, etc.

Object of comparison is handled as a 16 bits hexadecimal integer.
When designated as K○○, setting is done using decimal number, and designated as H○○, a hexadecimal number. If neither K nor H is designated, decimal number setting will be selected.
Refer to Appendix 3(1) for devices that can be entered in the Condition area.



POINT
Index representation (eg. D0Z0), representation of a word device in bits form (eg. D0,0), and sets of bits device representation (eg. K4X0) are not allowed in the Condition area.

3) Timing chart format

• Edit-Timing Chart Format button
Click this button: The timing chart format input screen will appear.
Refer to Section 4.5 for operation of screen/

• Continuing
When timing set by timing chart input is to be executed continuously, apply check mark ☑ to check box.

4) Setting

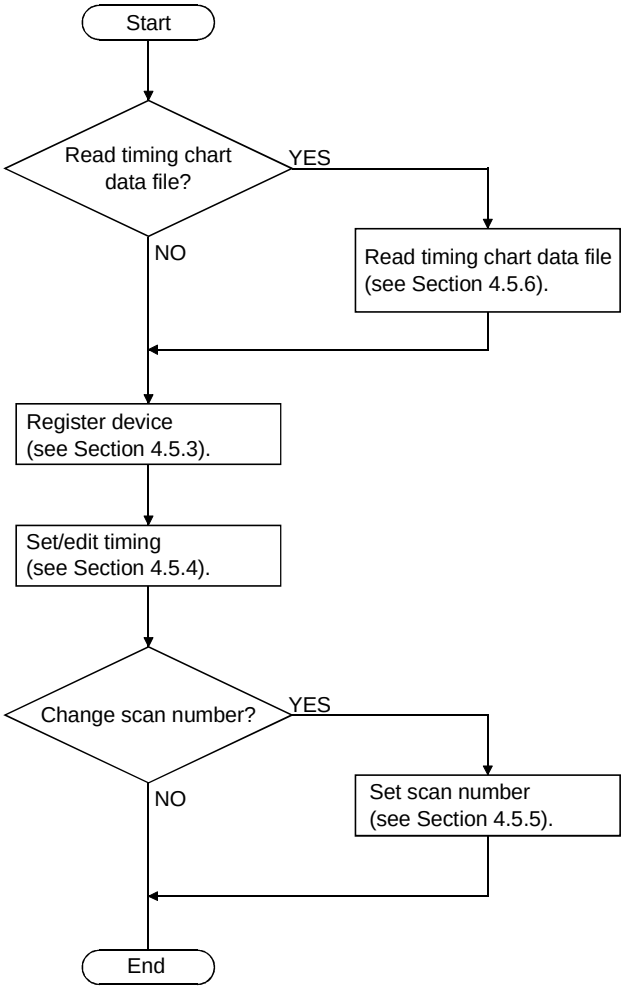
Designates enable or disable for each setting.
Apply a check mark ☑ to enable the setting.

4.5 Operation of Timing Chart Format Input Screen

This section describes operation of timing chart format input screen.

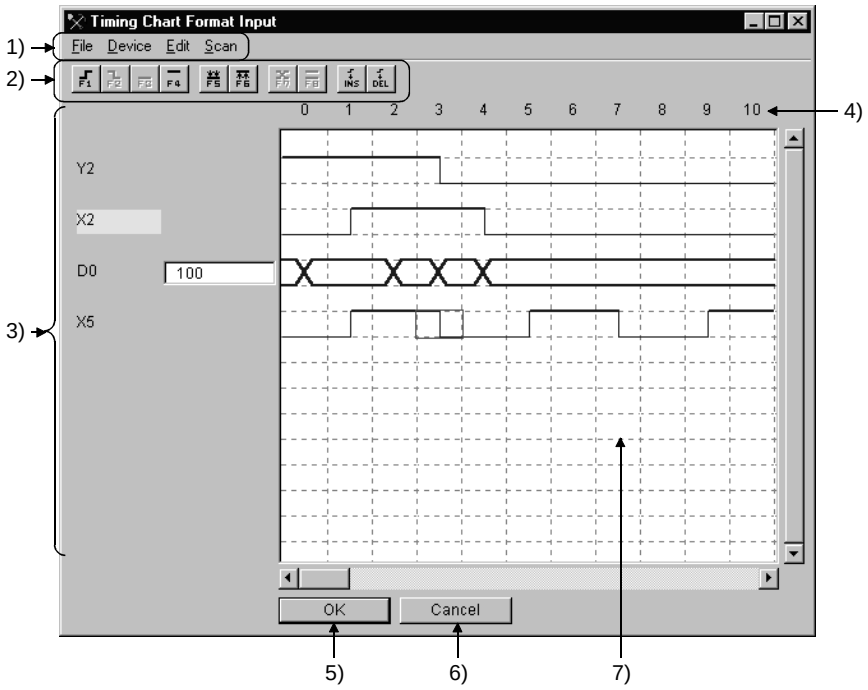
4.5.1 Operation procedure of timing chart format input screen

The operation procedure of timing chart format input screen is indicated below.



4.5.2 Configuration of timing chart format input screen

Configuration of timing chart format input screen is described below.



1) Menu bar

Name of menu, which can be used in timing chart format input screen, is displayed.

When menu has been selected, drop-down menu will be displayed and various functions from this menu can be used.

2) Tool bar

From functions assigned by menu bar, those most frequently used will be displayed with buttons.

3) Device name/device value

Bit device: When timing at cursor position is ON, device name lights (Yellow).

Word device: Device value, with the timing at cursor position, will be displayed in the text box on the right of device name.

POINT

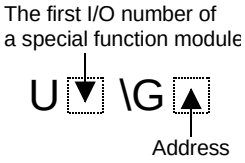
(1) There are three types, Contact, coil and current value, for each expression of timer (T), Counter (C) and retentive timer (ST) in the timing chart: They are displayed with following the expressions in the timing chart.

	Expressions used in timing chart		
	Timer	Counter	Retentive timer
Contact	TS	CS	STS
Coil	TC	CC	STC
Present value	TN	CN	STN

POINT

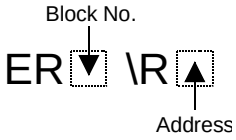
(2) Buffer memory and extension file register are displayed as shown below.

<Buffer memory>



When first I/O No. is 4, and address is K30, "U4\G30" will be displayed.

<Extension file register>

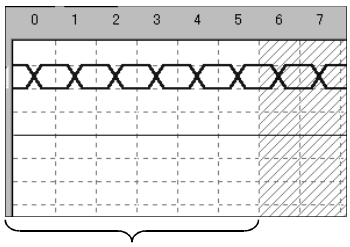


When block No. is 2, and address is K30, "ER2\R30" will be displayed.

(3) When a word device is designated as a 32-bit integer, (D) is added to the device name.
Example: D0(D), W6(D)

4) Scan number

Shows scan number of timing.
When scan number is set by selecting [Scan] - [Scan setting], disabled scans will be displayed with shading.
When applying check mark to "Keep" on the right of Edit-Timing Chart Format button, the enabled scans can be repeated while the condition is being fulfilled.
Example: For continuation with 6 scans designated:



5) OK button

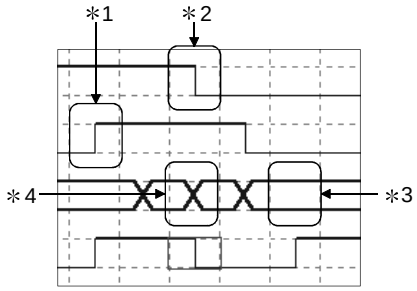
Defines settings and exits from this screen.

6) Cancel button

Cancels settings and exits from this screen.

7) Status

Displays state of timing chart being set.



∗1: Shows that object device was turned ON from OFF.
∗2: Shows that object device was turned OFF from ON.
∗3: Shows that object device remains unchanged.
∗4: Shows that object device has changed.

4.5.3 Entering/deleting device

(1) Entering device to be simulated

[Purpose]

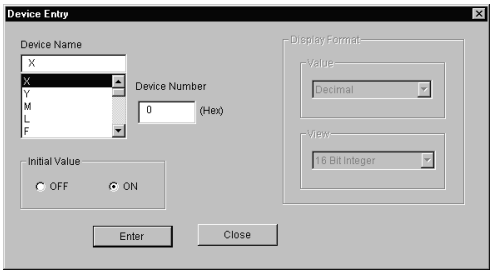
To enter device for setting timing.

[Operation procedure]

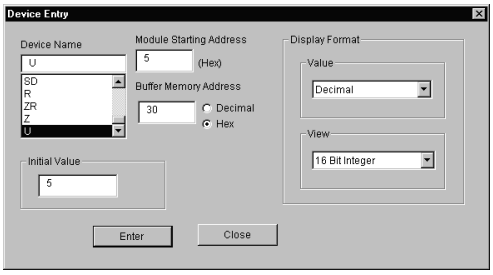
(a) Select [Device] - [Enter Device].

(b) Dialog shown below will appear. After setting each item, click Enter button.
A maximum of 16 devices can be entered.

[Bit device selected]



[Word device selected]



Item	Contents
Device name	Selects name of device to be entered.
Device No.	Enters device No.
Unit initial address	Displayed when "U" is selected with device name. Enter the higher two digits when initial I/O No. is expressed in three digits. Example: In case of X/YIF0, enter "IF".
Initial value	Sets initial value. For a bit device, select ON/OFF. For a word device, enter value.
Displayed format	Sets display format of word device to be displayed. Both decimal and hexadecimal numbers can be set. Display can be selected from 16 Bit integers, 32 Bit integers and real numbers.
Enter button	Enters device.
Close button	Closes this screen.

(2) Deleting entered device

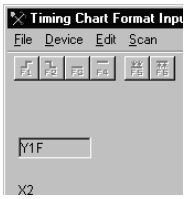
[Purpose]

To delete entered device.

[Operation procedure]

(a) Select device to be deleted.

Deleting X1F is described here, as example.



(b) Select [Device] - [Delete Device].

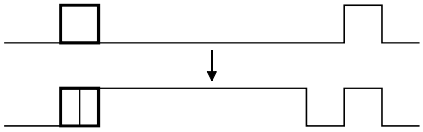
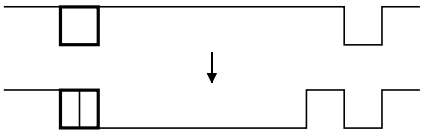
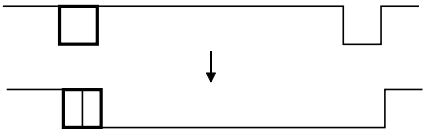
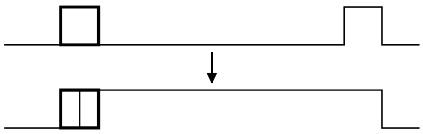
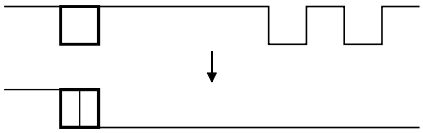
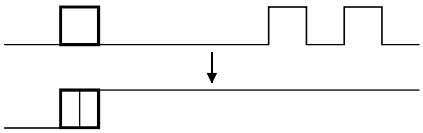
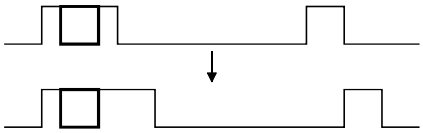
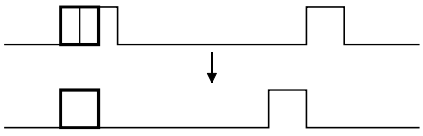
Device has been deleted.

4.5.4 Setting/editing timing

This section describes setting and editing method of timing.

(1) Setting the timing of bit device

Timing of bit device can be set following the procedure shown below.
Move cursor to the timing to be set and operate using any tool button, menu or short-cut key.

Operation	Tool button	Menu	Short-cut key	Timing
To turn ON designated timing		• [Edit] - [Bit Device] - [Device ON] • Right-click, then [Device ON] (Also can be done by double-clicking cursor position.)	F1	
To turn OFF designated timing		• [Edit] - [Bit Device] - [Device OFF] • Right-click, then [Device OFF] (Also possible to double-click cursor position.)	F2	
To turn OFF until next ON timing		• [Edit] - [Bit Device] - [Progressive OFF]. • Right-click, then [Progressive OFF].	F3	
To turn ON until next OFF timing		• [Edit] - [Bit Device] - [Progressive ON]. • Right-click, then [Progressive ON].	F4	
To turn OFF designated timing and all later		• [Edit] - [Bit Device] - [All OFF]. • Right-click, then [All OFF].	F5	
To turn ON designated timing and all later		• [Edit] - [Bit Device] - [All ON]. • Right-click, then [All ON].	F6	
To insert timing		• [Edit] - [Insert] • Right-click, then [Insert].	Insert	
To delete timing		• [Edit] - [Delete] • Right-click, then [Delete].	Delete	

☐ shows cursor position.

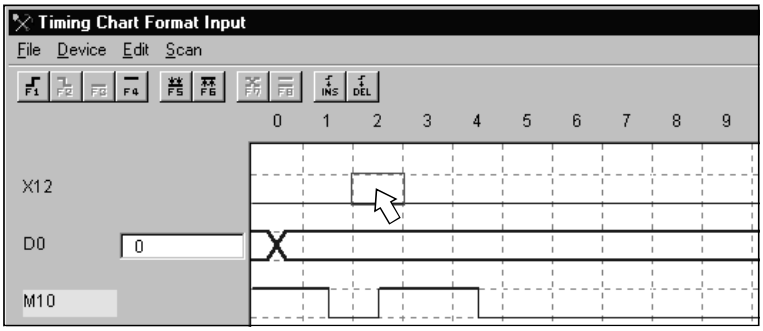
(a) Setting ON/OFF period

[Purpose]

To set ON/OFF continuously, with optional period after designated timing.

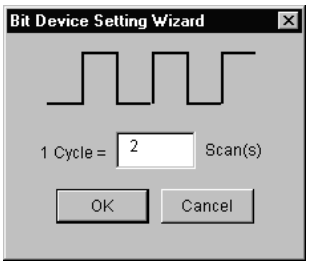
[Operation procedure]

1) Select initial bit device timing.

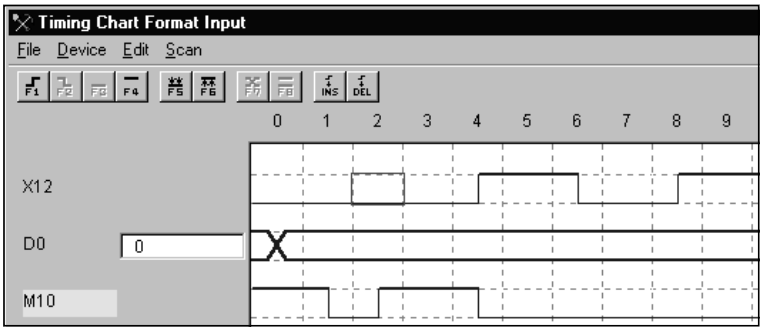


2) Operate either of operations shown below.
   - Select [Edit] - [Wizard] menu.
   - Right-click, select [Wizard] menu.

3) Bit device setting wizard screen will appear. Enter scan number and click OK button.



4) Bit device ON/OFF has been set periodically.



(2) Setting the timing of word device

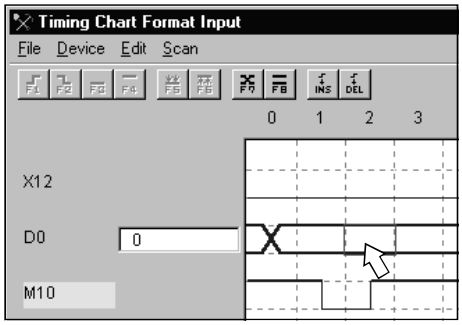
(a) Changing the designated timing value

[Purpose]

To change the timing value of designated word device.

[Operation procedure]

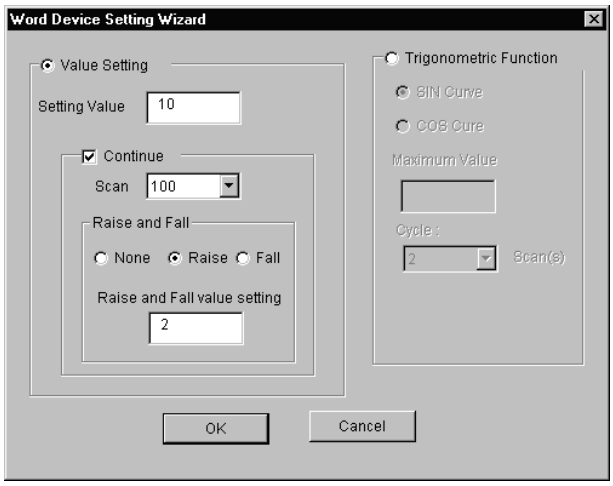
1) Select timing of word device to be changed.

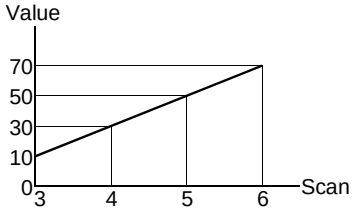
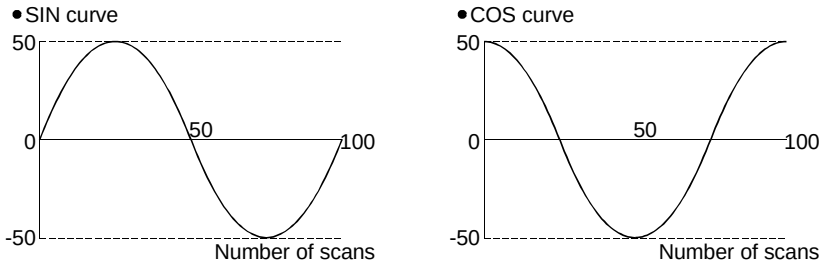


2) Operate any one of the following operations:

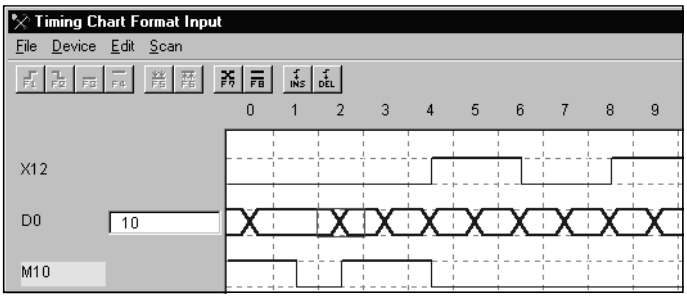
- Select [Edit] - [Word Device] - [Change] menu.
- Right-click, then select [Change] menu.
- Click  .
- Enter "F7" key.
- Double-click designated timing.

3) Word device setting wizard screen will appear: Set each item and click OK button.



Item		Contents
Value setting		
	Set value	Enter set value of word device.
	Continuation	Apply check mark when setting is to be performed continuously. (Example) Cursor position is scan No. 3, set value is 10, scan number is 4, changed value is 20 increased. 
	Scan	Select number of scans to be continued.
	Increase & decrease	Set to change set value when setting is to be performed continuously. • Increase: Select when value is to be increased. • Decrease: Select when value is to be decreased.
	Changed value	Set increased/decreased value.
Trigonometric functions		
	SIN curve, COS curve	Set when device value is changed as shown below. (Example) Maximum value is 50, periodical scans are 100. 
	Maximum value	Enter maximum value. When maximum value is set, minimum value will be set as "-maximum value".
	Periodic scan	Select number of scans corresponding to 1 period of SIN/COS curve.

4) Word device value has been set.



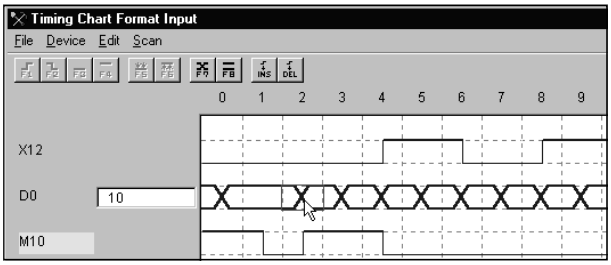
(b) Fixing unchanged designated timing value

[Purpose]

To make certain word device value of designated timing is not changed.

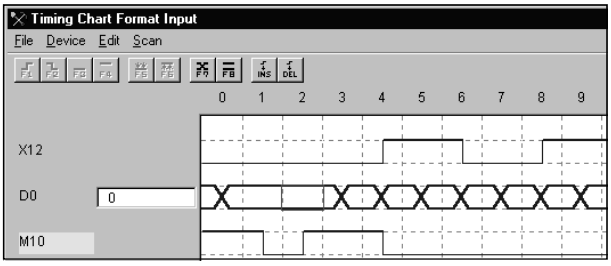
[Operation procedure]

1) Select word device timing that is not to be changed.



2) Operate any one of following operations:

- Select [Edit] - [Word Device] - [No change] menu.
- Right-click, then select [No change] menu.
- Click  .
- Enter "F8" key.



Mark of scan No.2 has been changed.

(C) Inserting timing

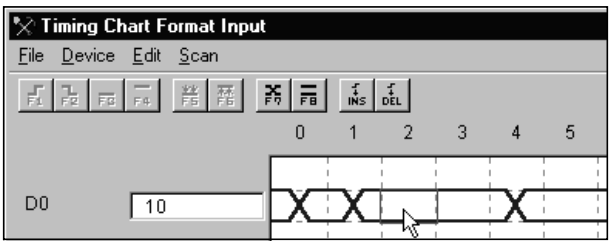
[Purpose]

Insert the timing before designated timing.

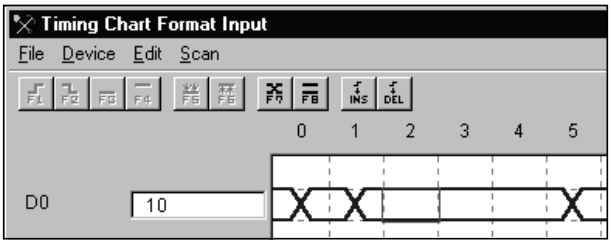
Timing is inserted to the left side of cursor position.

[Operation procedure]

1) Select the timing at the right side of the position where timing is to be inserted.



2) Operate any one of the following operations.
- Select [Edit] - [Insert] menu.
- Right-click, then select [Insert] menu.
- Click  .
- Enter "Insert" key.



After timing has been inserted, timing will shift to the right.

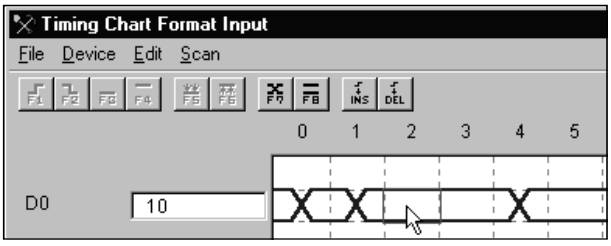
(d) Deleting the timing

[Purpose]

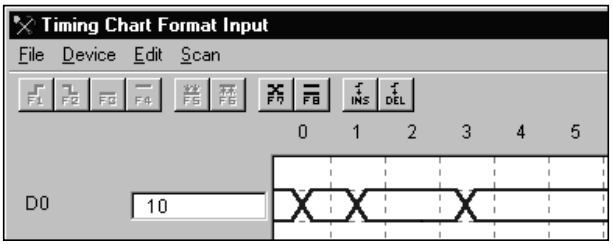
To delete designated timing.

[Operation procedure]

1) Select timing of the position to be deleted.



2) Operate any one of the following operations:
- Select [Edit] - [Delete] menu.
- Right-click, then select [Delete] menu.
- Click  .
- Enter "Delete" key.



After timing is deleted, timing will shift to the left.

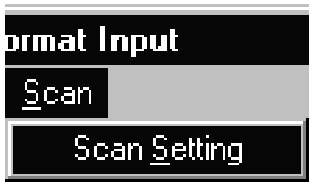
4.5.5. Setting scan number of timing chart

[Purpose]

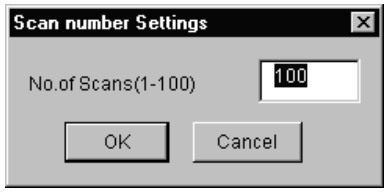
To set scan number of timing input from external device.

[Operation procedure]

(1) Select [Scan] - [Scan Setting].

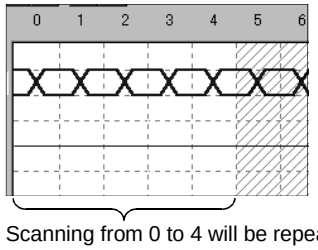


(2) Scan number setting screen will appear: Enter scan number.



(Example)

When Scan number is set to 5, and timing chart is set to "Keep", scanning from 0 to 4 will be repeated as long as the condition is fulfilled.



Only 5 scans from 0 to 4 are effective.

Scanning from 0 to 4 will be repeated as long as the condition is fulfilled.

4.5.6 Other operations

(1) Reading data saved using timing chart of device memory monitor

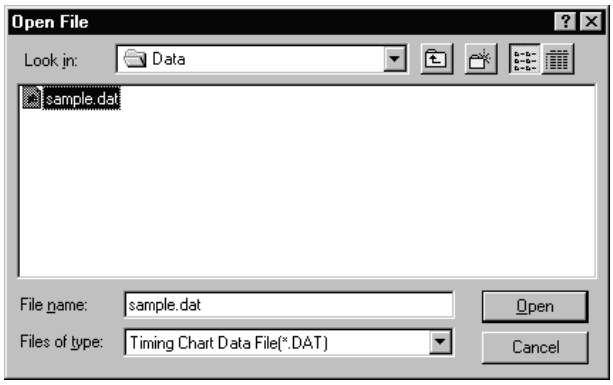
[Purpose]

To read and use timing chart data file (*.DAT) saved with timing chart.
When the file is read, device and timing will be automatically registered. It is not necessary to re-enter them.

[Operation procedure]

Select [File] - [Open File].

[Setting window]



Designate optional file with "Look in", click file to be opened and click Open button.

POINT
Devices for only 16 points from upper side of timings (maximum 64 points) set by timing chart screen can be read. It is necessary to move required timings to upper side before creating timing data file.

(2) Returning to original state before operation

[Purpose]

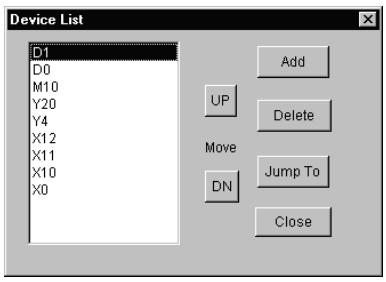
To return to previous state before last operation performed.
Only the operation immediately before can be regained.

[Operation procedure]

Select [Edit] - [Undo].

(3) Displaying registered device list

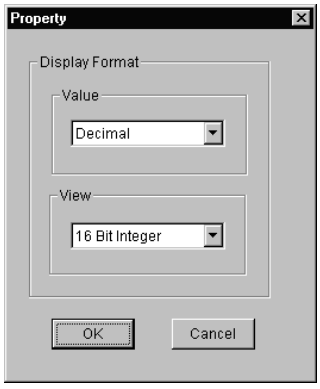
Select [Device] - [List Device]. Registered device list will be displayed.



- Click Add button. Device registration dialog will be displayed. Refer to Section 4.5.3 (1) for details.
- By clicking Delete button, the device is deleted from object of monitoring. Two or more devices can be deleted by using "Shift key + Select" or "Ctrl key + Select".
- By clicking Jump To button, display of timing chart format input screen jumps to device being selected.
- By clicking UP / DN button, device being selected moves up or down.
- Selecting Two or more devices
  (Two or more devices cannot be selected and moved simultaneously.)

(4) Changing display format of word device

Select [Word Device]. Then select [Device] - [Property]. Dialog shown below will appear: Display format can be changed.

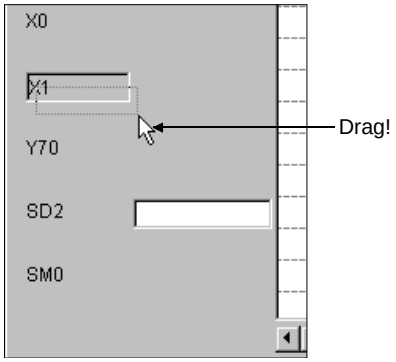


- Value
  Selects decimal or hexadecimal number display.
- View
  Selects 16 Bit, 32 Bit or real number.

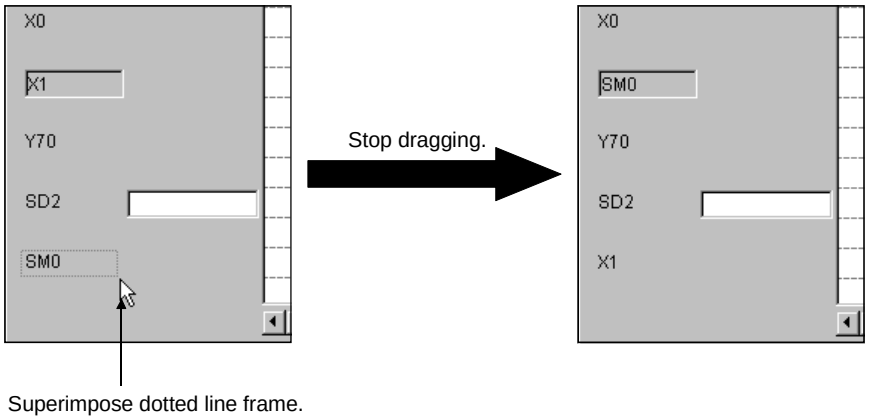
(5) Exchanging device display position

Display position of device can be exchanged by drag & Drop.

(a) Drag the device name in the timing chart format input screen. Dotted line frame will appear during dragging.



(b) Superimpose dotted line frame on the device name to be exchanged. Device name can now be exchanged.



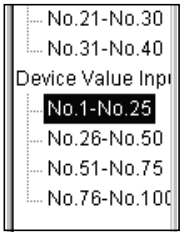
4.6 Setting by Entering Device Value

This section describes I/O system setting by entering device value.

[Operation procedure]

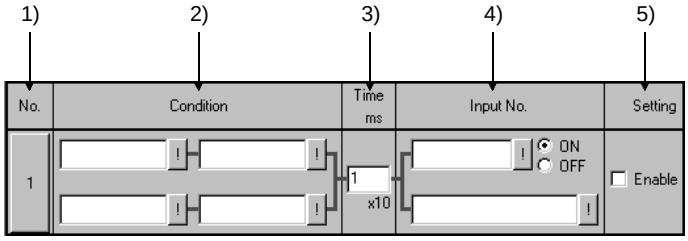
(1) Select [Start] - [I/O System Settings] from initial window.

(2) Double-click column of number to which device value is to be set.



[Setting window]

Perform setting in I/O system setting dialog box as shown below.



[Description of items]

1) No.

Number of settings in I/O system setting dialog box.
Maximum 100 settings can be chosen.
Once the set No. has been clicked, it can be cut, copied or pasted.

2) Condition

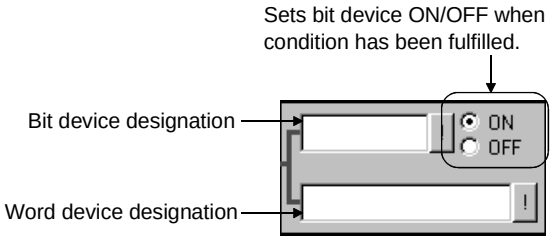
Since the conditions are the same as those when timing chart is used, refer to Section 4.4 (2).

3) Timer

Sets the time from the point when designated condition is fulfilled until the input is issued. Enter the time in 10 ms units. The setting range is 1 to 1000 (× 10 ms).

4) Input No.

Designates the bit device which is turned ON/OFF once designated condition has been fulfilled. Also designates word device whose value is to be changed.



• Input method (Direct input)

Independent device designation.... Designates non-consecutive devices, separated by commas (,).
(Example: D0=10,D2=20,D3=50)

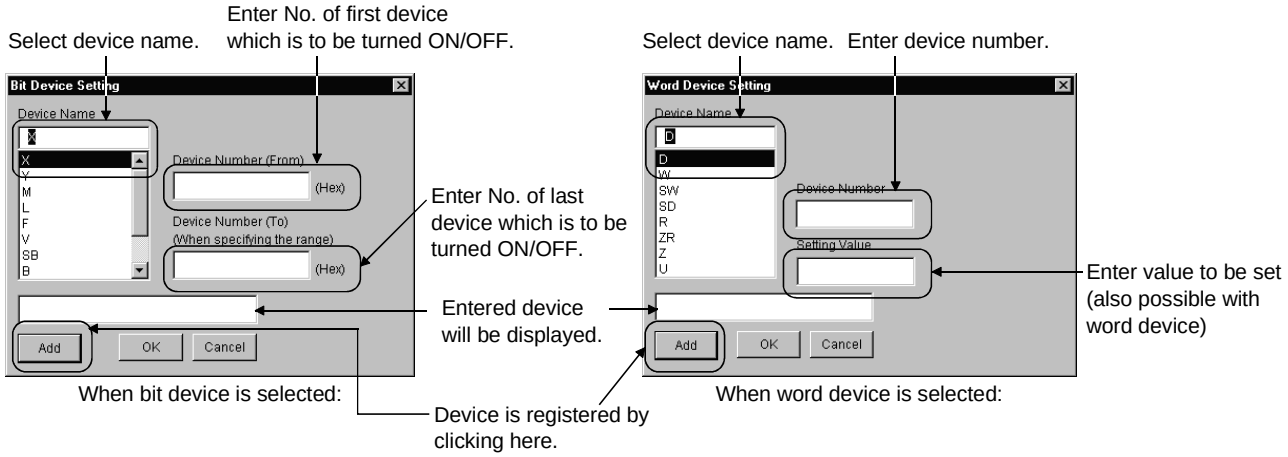
Consecutive device designation.... Designates the first and last of a series of consecutive devices, separated by a hyphen (-).
(bit device only)
(Example: X0-100)

Mixed device designation..... Designates a mixture of independent and consecutive devices.
(bit device only)
(Example: X0, X2, M10-20)

• Input method (using dialog box)

Click ! button and enter device name and device No., etc.

Refer to Appendix 3 (2) for devices that can be entered in the input No. area.



5) Setting

Designates whether each setting is to be enabled or disabled. Apply check mark ☑ to check box for the setting to be enabled.

4.7 Starting/Stopping the Simulation

Refer to Section 7.3 "Using I/O System Settings for Debugging" for example of simulation.

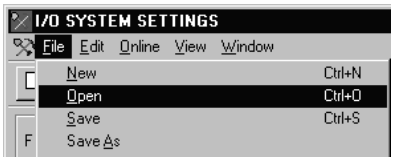
(1) Starting the simulation

[Purpose]

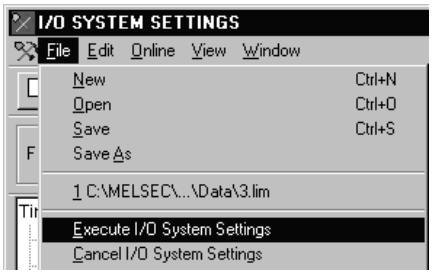
To start simulation with contents in I/O system settings.

[Operation procedure]

(a) Select [File] - [Open] to open I/O system setting file (*.LIM).
Refer to Section 4.8.1 for details of operation.

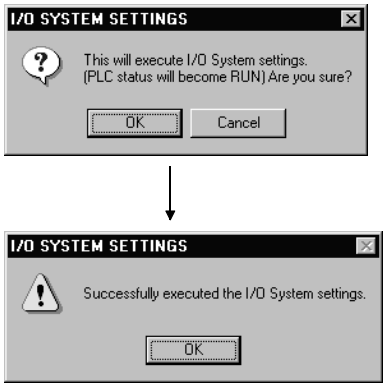


(b) Select [File] - [Execute I/O System Settings].
 (Yellow) can also be clicked instead of above.



(c) Dialog box for confirmation will appear: Click OK button.

[For A/QnA/QCPU]



[For FXCPU]

POINT
After changing I/O system setting of a file being opened, the file can automatically be saved by executing the I/O system settings. If I/O system setting file is not to be saved, save the file under a different file name and execute I/O system settings.

(d) When A/QnA/QCCPU is used, execution state will automatically change from STOP to RUN mode, and simulation will start.
When FXCPU is used, simulation is started by switching the setting in the initial window from STOP to RUN.

- When GPPW is SW1D5□-GPPW-E or later
  After the ladder logic test tool (LLT) is started, the set I/O system settings will remain enabled until they are deleted or the ladder logic test tool (LLT) is quit.
  To use the same I/O system settings when the ladder logic test tool (LLT) is restarted, read the I/O system setting data from the saved file, and then execute the I/O system setting again.
- When GPPW is SW0D5□-GPPW-E
  The I/O system settings made once are effective until [Cancel I/O Settings] is executed, regardless of starting/ending the ladder logic test tool (LLT).

POINT
For FXCPU: If settings are made in RUN status, the status must be switched to STOP once before returning to RUN, to enable the new settings.

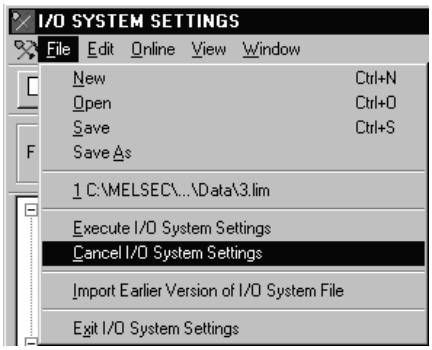
(2) Stopping the simulation

[Purpose]

To stop the I/O system setting operation currently being executed.

[Operation procedure]

(a) Select [File] - [Cancel I/O System Settings].
Also  (White) can be clicked instead of above.



POINT
When I/O System Settings are not being executed, the I/O system setting LED on the initial window will turn off.

4.8 Other Operations

4.8.1 Operating the file

(1) Creating a new file

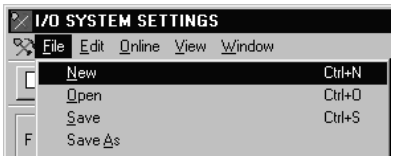
[Purpose]

To create a new file (∗.LIM) to be used for I/O system settings.

[Operation procedure]

Select [File] - [New].

Also  can be clicked instead of above.



(2) Opening saved file

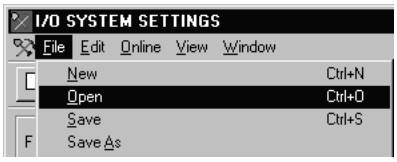
[Purpose]

To open an I/O system setting file (∗.LIM) which has been saved.

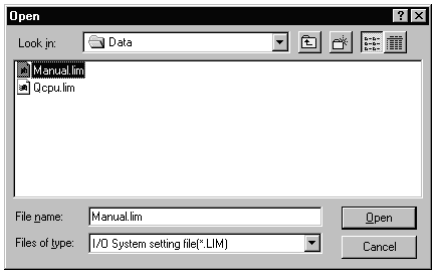
[Operation procedure]

Select [File] - [Open].

Also  can be clicked instead of above.



[Setting window]



Designate optional holder with "Look in", click the file to be opened, then click Open button.

(3) Saving the file

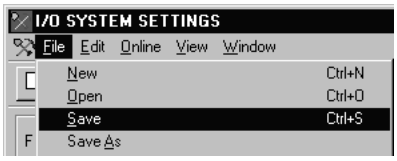
[Purpose]

To over-write and save the I/O system setting file (*.LIM) being opened.

[Operation procedure]

Select [File] - [Save].

 can also be clicked instead of above.



If file being opened has not been saved, "Save As" dialog will be displayed: Save with optional name entered. Refer to (4) for details.

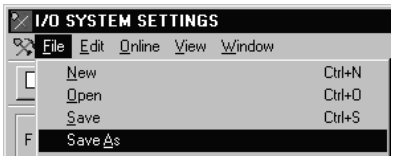
(4) Saving with new name

[Purpose]

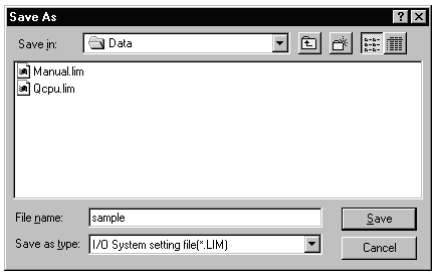
To save I/O system setting file (*.LIM) that is being opened with new name entered.

[Operation procedure]

Select [File] - [Save As].



[Setting window]



Designate optional folder with "Save in", and enter file name to be saved in "File name".

If setting is to be over-written on existing file, select the file to be saved by clicking: Then click Save button.

4.8.2 Cutting, copying and pasting all settings in the set No.

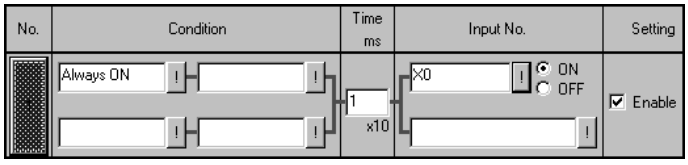
(1) Cutting and copying the selected set No.

[Purpose]

To cut and copy selected set No. and save on clipboard.

[Operation procedure]

(a) Select the set No. to be cut/copied by clicking.



(b) For cutting, select [Edit] - [Cut].

 can also be clicked instead of above.

For copying, select [Edit] - [Copy].

 can also be clicked instead of above.

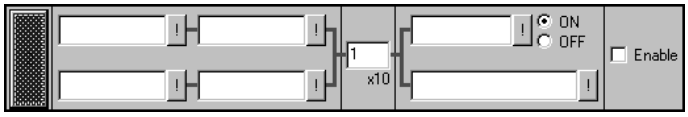
(2) Pasting the cut/copied set No.

[Purpose]

To paste cut/copied set No. to optional position

[Operation procedure]

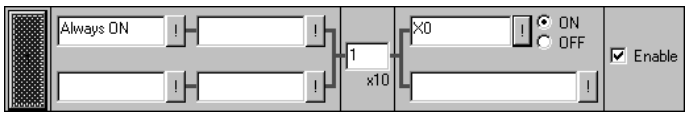
(a) Select the set No. to be pasted by clicking.



(b) Select [Edit] - [Paste].

 can also be clicked instead of above.

(c) Cut/copied set No. has been pasted.



POINT
A set No. copied or cut in device value input mode cannot be pasted with timing chart input, and vice-versa.

4.8.3 Executing monitoring

(1) Starting monitoring

[Purpose]

To start monitoring a device on the I/O system settings screen.

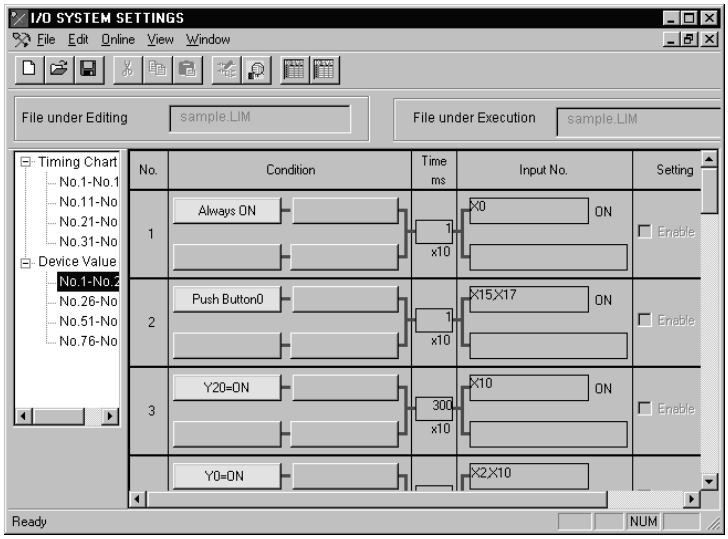
[Operation procedure]

(a) Select [Online] - [Monitor mode].

 can also be clicked instead of above.

(b) Monitoring will start.

Refer to (3) for details of operation on the screen during monitoring.



(2) Stopping monitoring

[Purpose]

To stop monitoring with I/O system setting screen.

[Operation procedure]

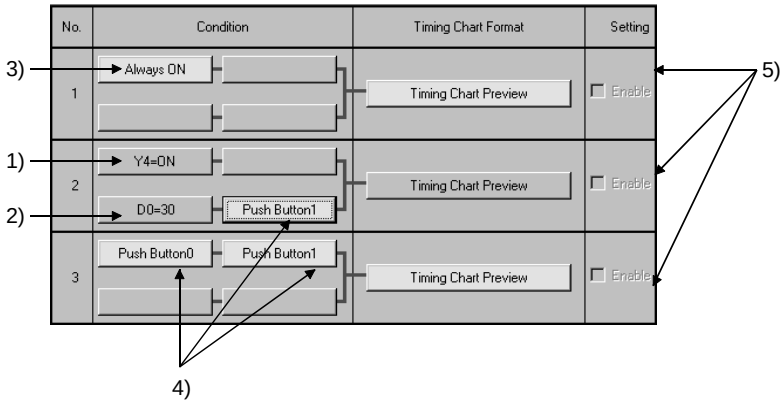
Select [Online] - [Edit mode].

 can also be clicked instead of above.

(3) Screen during monitoring

When monitoring is started, I/O system settings screen will appear as shown below:

Area displayed in yellow is effective.



1) Bit device

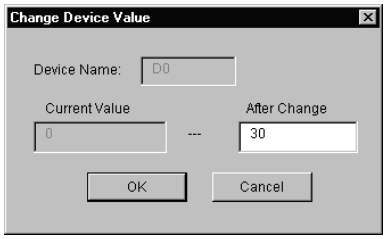
The status of displayed bit device can be inverted by clicking.

As shown on the screen, when "Y4=ON" is indicated, yellow display will show ON status.

If "Y4=OFF" is indicated, yellow display will show OFF status.

2) Word device

Following dialog box is displayed by clicking: Displayed value can be changed.



3) Normally ON

Since ON is normally set, nothing changes even if clicked.

4) Push button

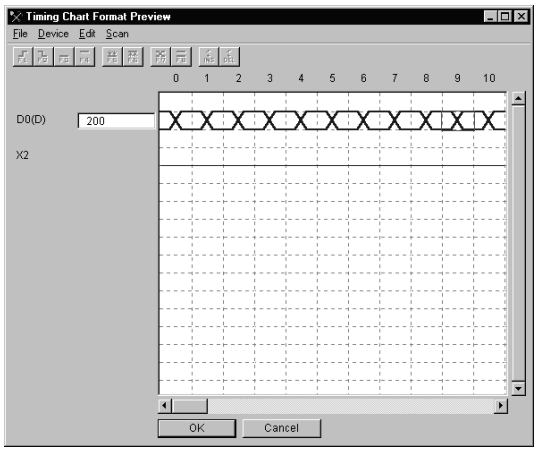
Push button state is inverted by clicking.

If there are push buttons with the same number, all buttons are linked for operation.

(5) Timing chart preview button

Timing chart format input screen is displayed by clicking and the set contents can be confirmed.

However, the contents of this displayed screen cannot be edited.



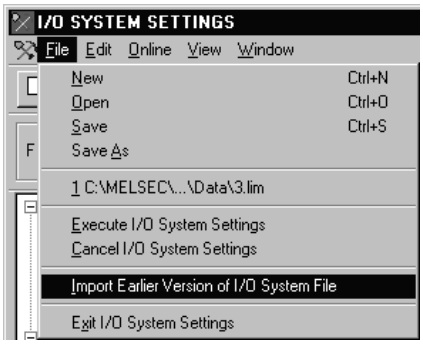
4.8.4 Reading I/O system setting file for SW4 or earlier versions

[Purpose]

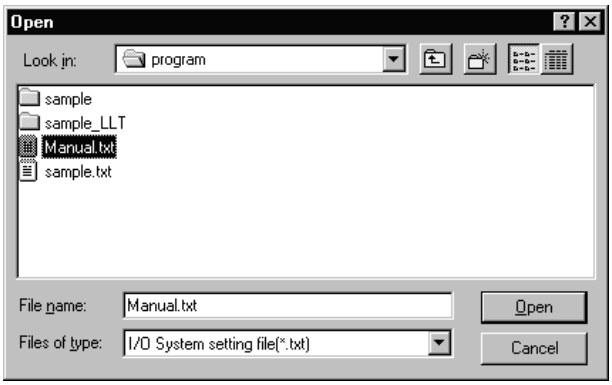
To read I/O system setting file for SW0D5□-LLT-E to SW4D5C-LLT-E.

[Operation procedure]

Select [File] - [Import Earlier Version of I/O System File].



[Setting window]



Designate optional folder with "Look in", click the file (*.TXT) to be opened, then click Open button.

5. MONITORING DEVICE MEMORY --- MONITOR TEST FUNCTION

The monitor test functions monitor the status of the device memory saved in the ladder logic test tool (LLT), force bit devices ON/OFF, and test changes to word device present values.

5.1 GPPW and Ladder Logic Test Tool (LLT) Monitor Test Functions

A combination of the ladder logic test tool (LLT) and GPPW monitor test functions allows the extensive GPPW monitor test functions to be used offline.
All monitor test functions available with the GPPW and ladder logic test tool (LLT) are described below.
If the ladder logic test tool (LLT) does not support a function, execute a function from a GPPW menu.

Function		Function Executed from a GPPW Menu	Function Executed from a Ladder Logic Test Tool (LLT) Menu
Monitor test functions	Ladder monitor	○	—
	Device batch monitor	○	○
	Device registration monitor	○	—
	Buffer memory batch monitor	○	○
	Device test	○	○
	Skip execution	○	—
	Partial execution	○	—
	Step execution∗1	○	—

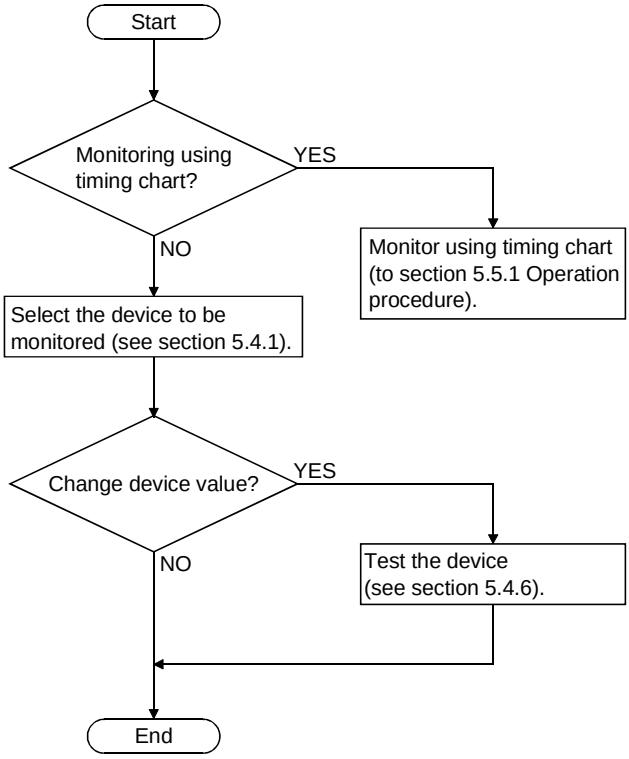
○…… Available
—…… Not supported

∗1: For the Q series CPU (Q mode), GPPW cannot be used. Only LLT may be used.

See the SW5D5C-GPPW Operating Manual for details of the functions which can be executed from the GPPW menu.

5.2 Operation Procedure of Monitoring Device Memory

Operation procedure of monitoring device memory is shown below:



5.3 Starting/Ending Monitoring Device Memory

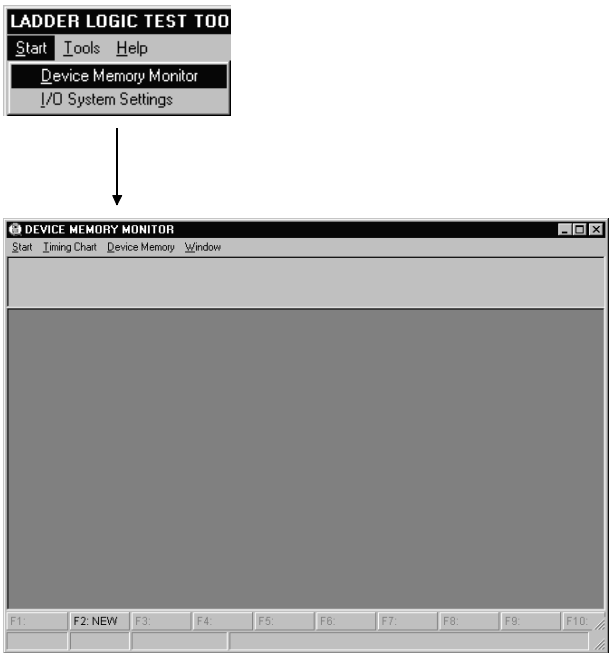
(1) Starting monitoring device memory

[Purpose]

To start monitoring device memory.

[Operation procedure]

Select [Start] - [Device Memory Monitor] from initial window.



(2) Ending monitoring device memory

[Purpose]

To end monitoring device memory.

[Operation procedure]

Select [Start] - [Exit] from device memory monitor screen.

5.4 Monitoring/Testing the Device Memory

This section describes how to monitor/test the device memory.
This section provides only the functions which are performed from the ladder logic test tool (LLT) menu. See the SW5D5C-GPPW-E Operating Manual for details of the functions performed from the GPPW menu.

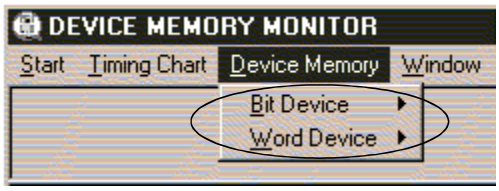
5.4.1 Selecting the devices for monitoring

This section describes how to select the devices for monitoring.

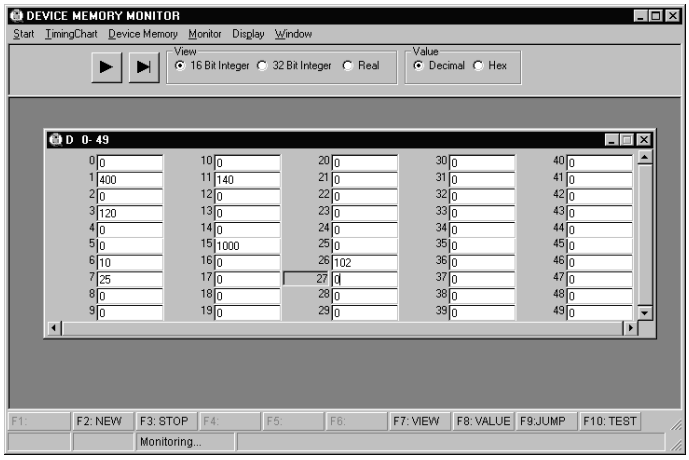
[Operation Procedure]

1) Select [Start] → [Device Memory Monitor] from the initial window.

2) Select [Device Memory] then [Bit Device] or [Word Device] in the device memory monitor window and select the devices to be monitored in the monitor test.



3) The selected device window is displayed.
The selected device monitor is started automatically.



POINT
For the A series, QnA series, Q series or motion controller CPU functions, always make I/O assignment setting of GPPW when monitoring the buffer memory of the special function module.

4) Click on the |◀ ◀ ▶ ▶| button or select [Display] → [Jump] (F9) to change the displayed device range.

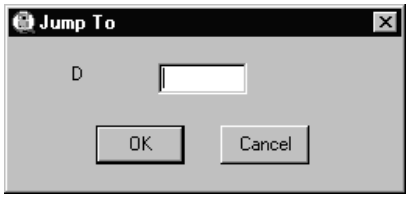
|◀..... Click this button to display the first page of currently displayed devices.

◀..... Click this button to display the previous page of currently displayed devices.

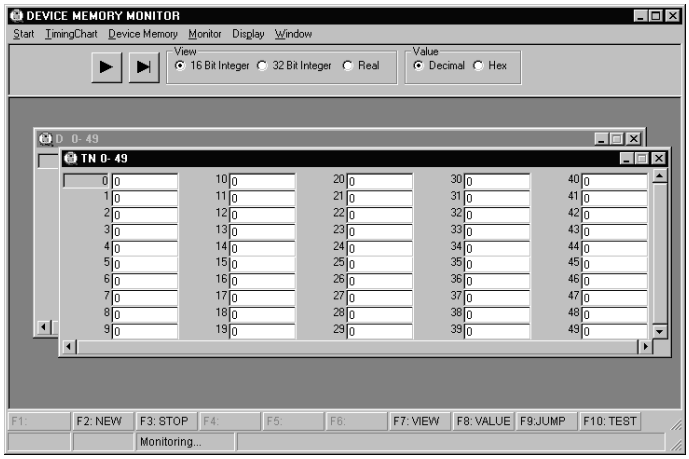
▶..... Click this button to display the next page of currently displayed devices.

▶|..... Click this button to display the last page of currently displayed devices.

[Display] → [Jump] (F9)... Select these items to open the following setting window.
Designate the first device number to bdisplayed.



5) To open multiple windows, select [Window] → [New] (F2) and designate the device names and device numbers.
The designated device windows are displayed overlapping each other.



POINTS

(1) Although the device window opens in either procedure of [Device Memory] → [Bit Device] / [Word Device] or [Window] → [New] (F2), the device window called by the procedure beginning with the selection of [Device Memory] display the devices starting from device number 0.
Select [Window] menu (F2) to specify an arbitrary start device number for display.

(2) Pressing the ESC key closes the device window which is currently active.

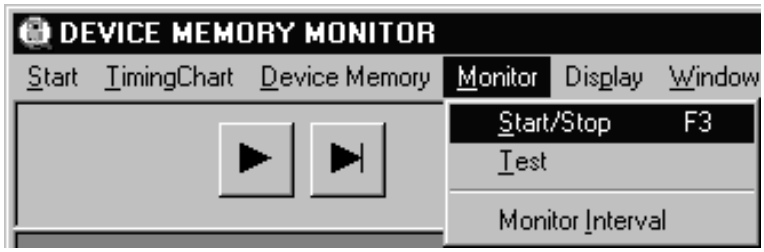
5.4.2 Stopping and restarting the device memory monitor

[Purpose]

To stop the device data changes and view the monitor window.

[Operation Procedure]

1) Select [Monitor] → [Start/Stop] (F3) in the Device memory monitor window while monitoring the device memory.



2) The device memory monitoring stops.

3) To restart the device memory monitoring, select [Monitor] → [Start/Stop] (F3) again.

POINT

The present monitor status is displayed in the guidance column below the device memory monitor window.

- During monitoring

- During monitor stopped

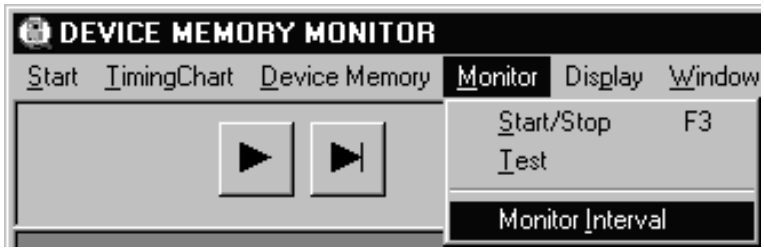
5.4.3 Changing the monitor communications interval

[Purpose]

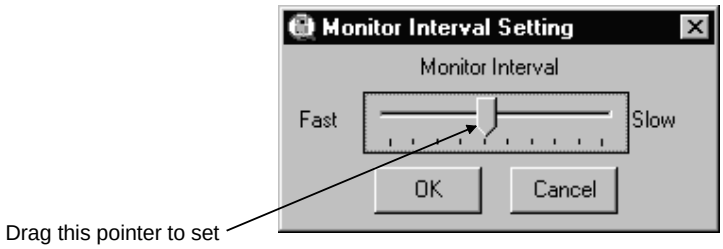
To set the interval at which the ladder logic test tool (LLT) device memory status is monitored.

[Operation Procedure]

1) Select [Monitor] → [Monitor Interval] in the Device memory monitor window.



2) The monitoring interval dialog box is displayed.
Drag the pointer in the dialog box to set the monitoring interval.
Click on the OK button when the setting is complete.

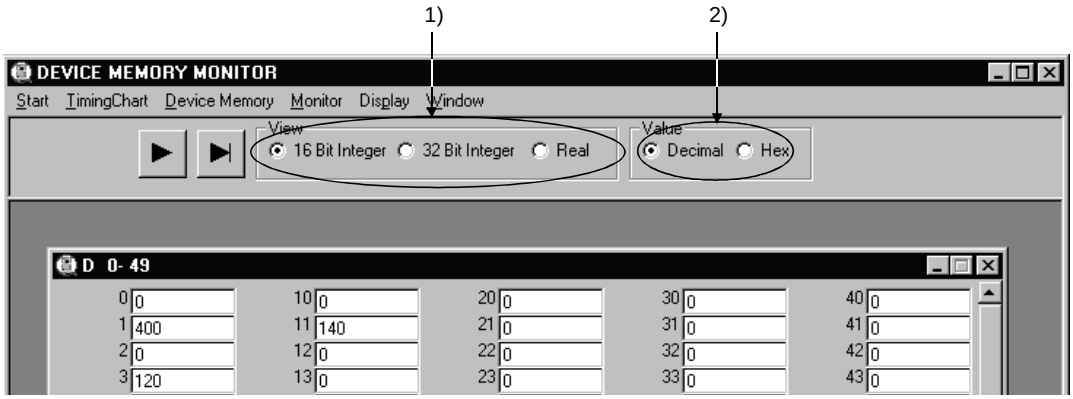


5.4.4 Changing the device memory monitor format

[Purpose]

To switch the display format of the device monitor column to match the data contents.

[Setting Window]



[Description of the Settings]

1) View

Selects whether to display the values in the device monitor column in 16-bit units, 32-bit units, or as a floating decimal-point display when monitoring a word device.

The same operation is possible from the keyboard by pressing the F7 key.

16 Bit Integer .....Displays the values in 16-bit units.

32 Bit Integer .....Displays the values in 32-bit units.

Real .....Displays the value as a floating decimal point value (single-precision value).

2) Value

Selects whether to display the values in the device monitor column as a decimal or hexadecimal value when monitoring a word device.

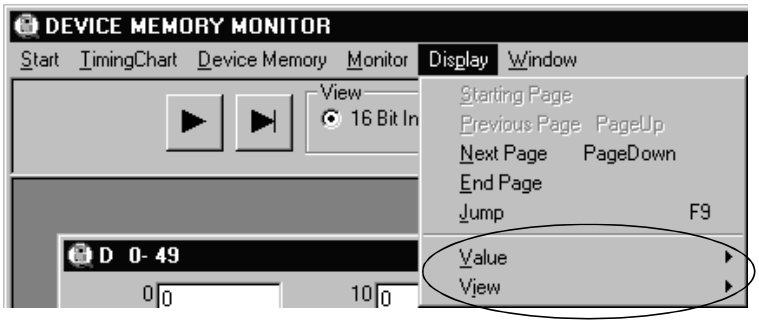
The same operation is possible from the keyboard by pressing the F8 key.

Decimal.....Displays a decimal value.

Hexadecimal.....Displays a hexadecimal value.

POINT

The device monitor format can also be changed by selecting the desired format from the drop-down menu of [Display] in the Device memory monitor window.



5.4.5 Opening the new window

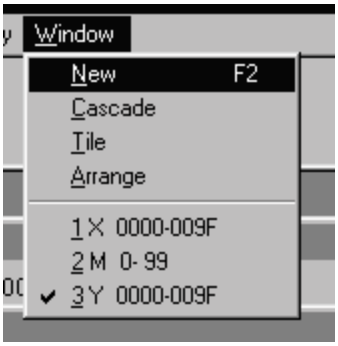
[Purpose]

To open a new window, designate the device.

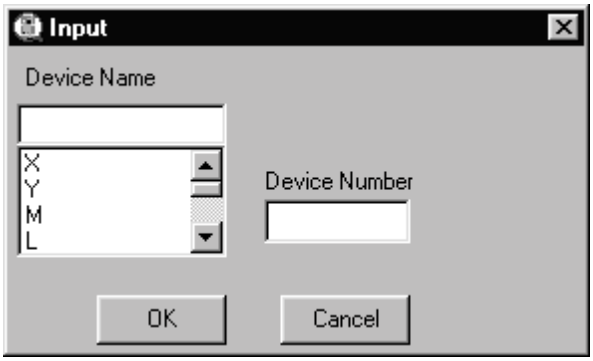
[Operation Procedure]

1) Opening a new window

Choose [Window] → [New] in the Device Memory window.



Entering the device name and device number and clicking the [OK] button opens a new window.



POINT
You can open up to 8 windows concurrently.

5.4.6 Running the device test

[Purpose]

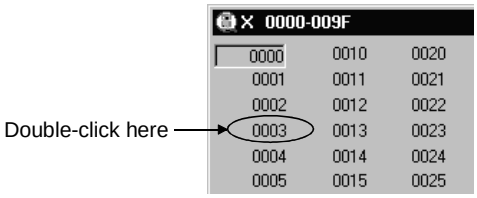
To force bit devices ON/OFF or force changes to the present values of word devices while monitoring the devices.

[Operation Procedure]

Select [Device Memory] then [Bit Device] or [Word Device] in the Device memory monitor window and select the devices to be monitored in the monitor test.

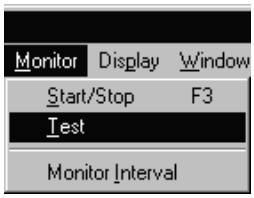
(1) Forcing Bit Devices ON/OFF

(a) Double-click on the device number to be turned ON/OFF forcibly in the bit device monitor window.



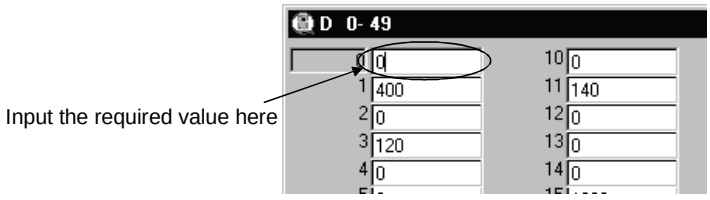
(b) Click on the device number to select it and press the F10 key. The ON/OFF status of the selected bit device is highlighted.

(c) Click on the device number to select it and select [Monitor] – [Test].



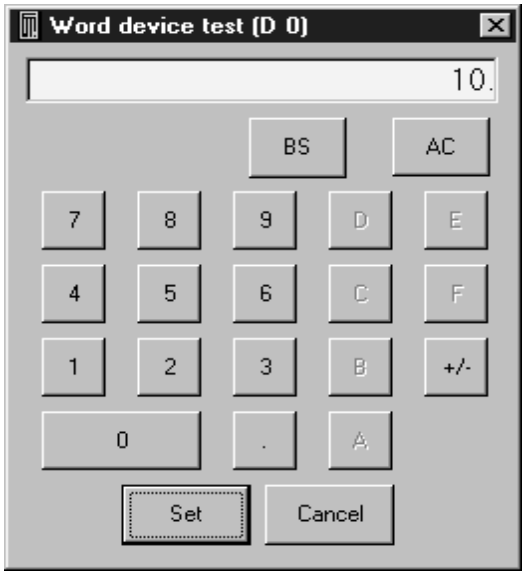
(2) Changing Word Device's Present Values

(a) Move the cursor to the present value text box for the word device and directly input the required value.

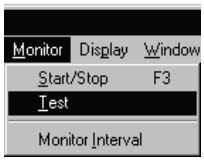


Press the Enter key to change the original present value to the designated value.

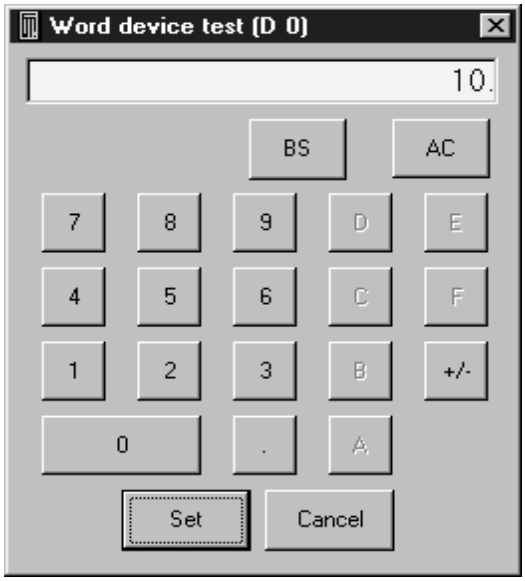
(b) Double-click on the device number.
Calculator screen will appear: Designate present value after change and click Set button.



(c) Click device number and select [Monitor] - [Test].



Calculator screen will appear: Designate present value after change and click Set button.



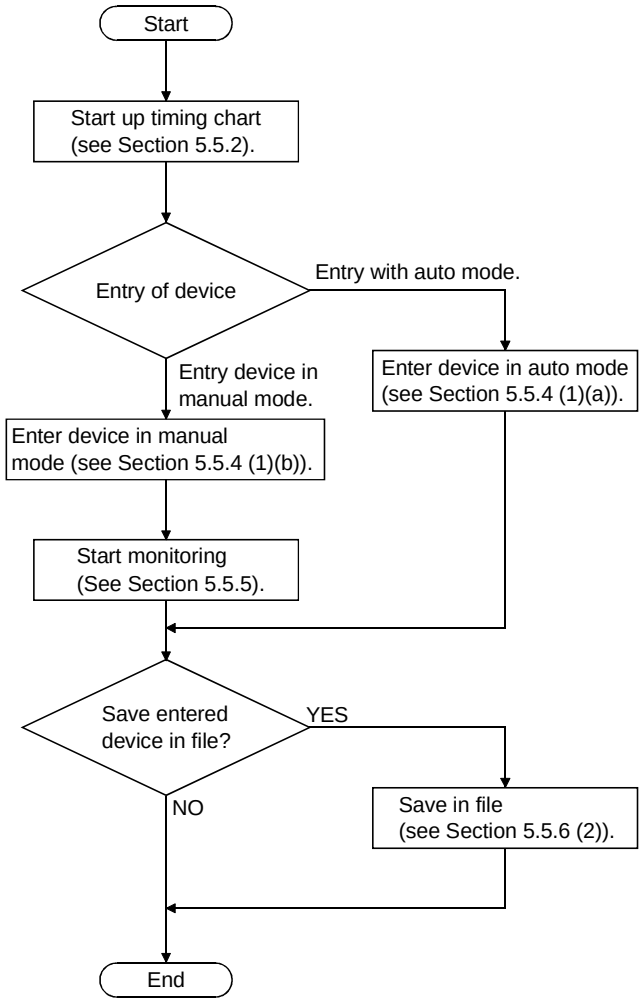
POINT
Always select the hexadecimal display for numeric values when inputting a hexadecimal using the numeric keypad. Note that character-string cannot be input.

5.5 Using Timing Chart

By using timing chart, timing of ON/OFF for bit device and change in word device value can be confirmed easily.

5.5.1 Operation procedure of timing chart

Operation procedure of timing chart is shown below:



REMARK

When sampling period is to be set, refer to Section 5.5.7.
Refer to Section 5.5.6 (3) if saved as timing chart data file.

5.5.2 Starting/exiting timing chart

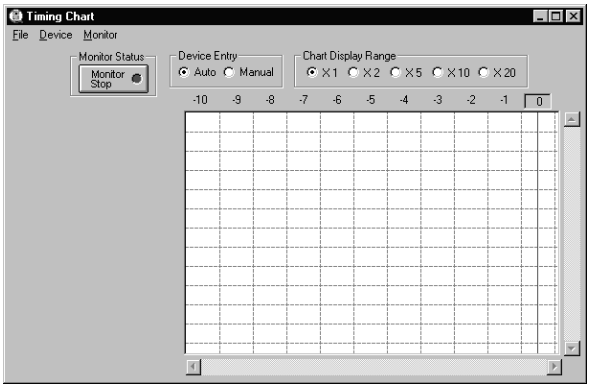
(1) Staring timing chart

[Purpose]

To start timing chart.

[Operation procedure]

Select [Timing Chart] - [Run] from device memory monitor screen.
Maximum 4 timing charts can be started.



(2) Exit timing chart

[Purpose]

To exit timing chart.

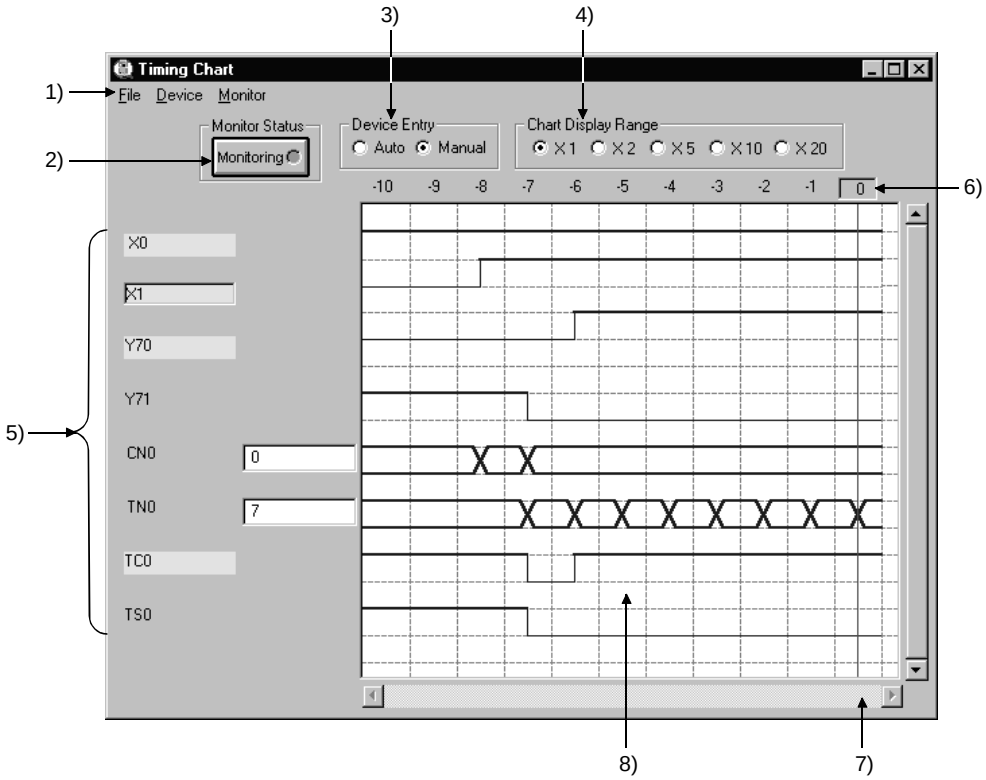
[Operation procedure]

Select [File] - [Exit] from timing chart screen.

5.5.3 Using timing chart

(1) Screen display/operation

When you run Timing Chart, the following Timing Chart screen appears.
The following gives the explanations of the display data of the Timing Chart screen.



1) Menu bar

Names of menu that can be used in timing chart are displayed.
When menu is selected, drop-down menu will be displayed and you can use various functions from this menu.

2) "Status" button

By clicking the "Status" button, you can start/stop monitoring.
For the details, refer to Section 5.5.5.

3) Device Entry

Selects auto or manual entry of device to be monitored.
For the details, refer to Section 5.5.4.

4) Range of Chart Display

When the sampling interval is set to per scan, the chart display range is enlarged by 1, 2, 5, 10, and 20 times.

5) Device name/Device value

Bit device ..... When a device is in ON status, the device name lights up (Yellow). Clicking on the device name will highlight either ON and OFF of the device.

Word device ..... Displays the device value in an edit box at the right side of the device name. Double clicking on the device value will edit the device value.

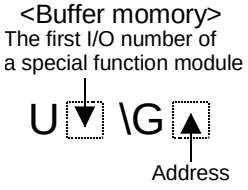
POINTS

(1) The expressions in the timing chart are timer (T), counter (C), and retentive timer (ST), and each of them has three types; contact, coil, and present value. In the timing chart, they are expressed as follows.

	Expressions used in the timing chart		
	Timer	Counter	Retentive timer
Contact	TS	CS	STS
Coil	TC	CC	STC
Present value	TN	CN	STN

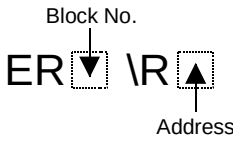
(2) Buffer memory and extension file register are displayed as follows.

<Buffer momory>



When the first I/O number is 4 and the address is K30, they are displayed as "U4\G30".

<Extension file register>



When the block No. is 2 and the address is K30, they are displayed as "ER2\R30".

(3) When word device is designated as 32 bit integer, (D) is added to the end of device name.
Example: D0(D), W6(D)

6) Reference line/scale

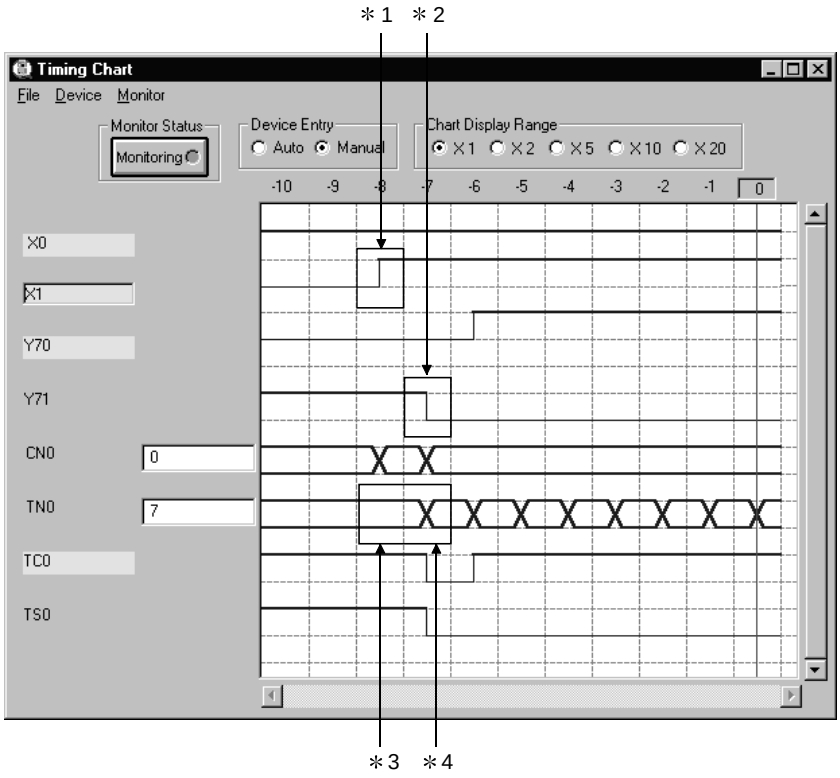
The scale displayed indicates the past scan count.
Clicking the scale moves the reference line (vertical line) and shows the device values at that scan in 5).

7) Scroll bar

Up to 1000 sampled past states of devices area saved.
By operating the scroll bar, you can confirm the past states of devices.

8) Status display

Shows the states of the monitor devices.



＊1 denotes that the corresponding device turned from OFF to ON.
＊2 denotes that the corresponding device turned from ON to OFF.
＊3 denotes that the value of the corresponding device remains unchanged.
＊4 denotes that the value of the corresponding device has changed.

5.5.4 Entering/deleting device to be monitored

(1) Entering device to be monitored

(a) Automatic setting

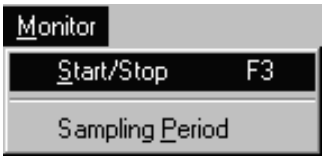
[Purpose]

Automatically enters device used with sequence program.

[Operation procedure]

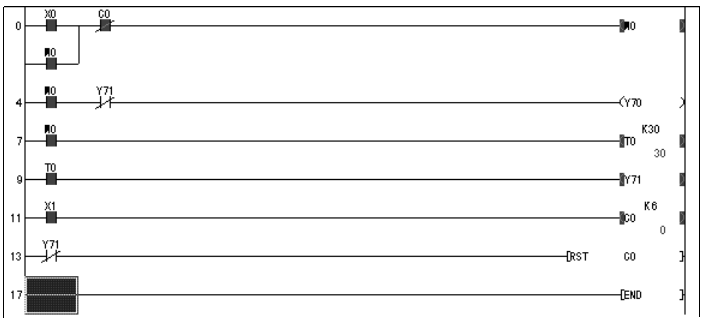
1) Make sure that device entry is set to "AUTO":
If set to "MANUAL", switch to "AUTO".

2) Select [Monitor] - [Start/Stop] to set to monitor mode.
You can also click Monitor Stop button instead of above.



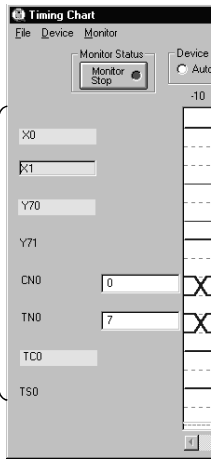
3) Device displayed on GPPW screen will automatically be registered as device, and monitoring will start. (Maximum 64 devices can be entered.)
If displayed device is changed by scrolling the screen, device entry will automatically change.

<GPPW screen>



Device monitored with GPPW will be displayed on timing chart screen.

<Timing chart screen>



POINTS

(1) If devices registered using GPPW do not appear in the timing chart screen, switch the device entry setting from Auto to Manual, and execute device entry.
(2) For any instruction whose argument occupies double-word positions, two word devices will be displayed on the timing chart screen.
(For DINC D0, D0 and D1 are entered.)
(3) When batch monitor of GPPW is used to monitor a bit device, this bit device will not be entered.
(4) When the A/FX/Q (A mode)/motion controller CPU is selected, the bit digit-specified/index-qualified device will not be entered.
(5) When QnA/QCPU (Q mode)is selected, directly designated buffer memory will not be entered.
(6) When FX series CPU is selected, the following instructions displayed on GPPW circuit monitor screen will not be entered.
(RST T, RST C
PLS Y, PLS M
PLF Y, PLF M)

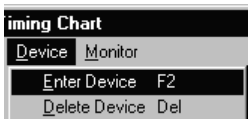
(b) Manual entry

[Purpose]

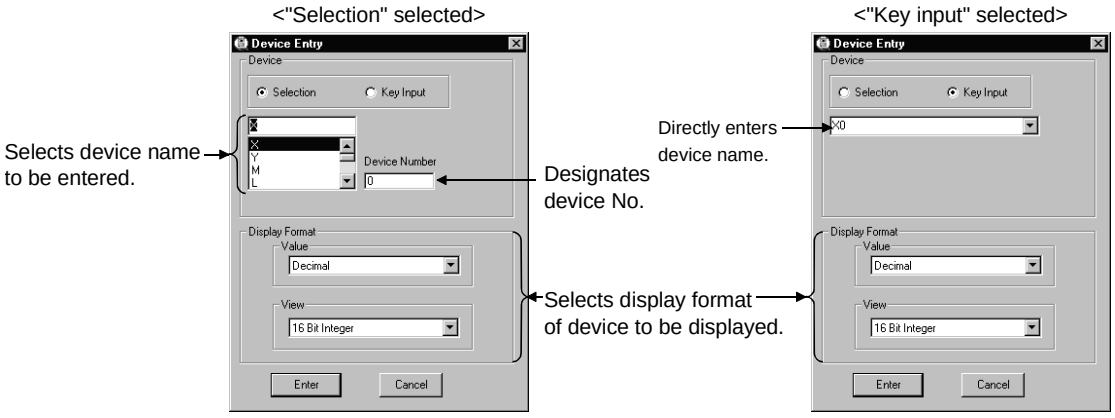
Manually enters device to be monitored in timing chart.

[Operation procedure]

1) Select [Device] - [Enter Device].



2) The dialog shown below will appear: After setting each item, click Enter button.
Maximum 64 devices can be entered.



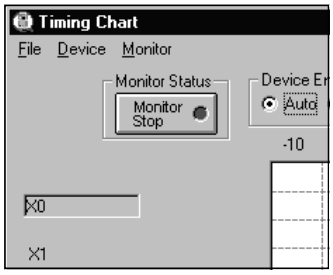
(2) Deleting registered device

[Purpose]

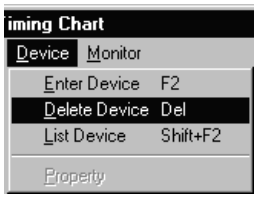
To delete registered devices.

[Operation procedure]

(a) Select the device to be deleted:
For example, X0 is deleted here.



(b) Select [Device] - [Delete Device].
Device has been deleted.



5.5.5 Starting/stopping monitoring

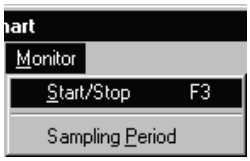
(1) Starting monitoring

[Purpose]

To start monitoring the timing chart.

[Operation procedure]

After registering device, select [Monitor] - [Start/Stop] while monitor is stopped.
You can also click Monitor Stop button instead of above.
However, if device is registered in AUTO mode, monitoring will start when device is registered.



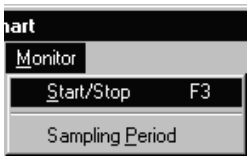
(2) Stopping monitoring

[Purpose]

To stop monitoring timing chart.

[Operation procedure]

Select [Monitor] - [Start/Stop] during monitoring.
You can also click Monitoring button instead of above.



5.5.6 Operating file

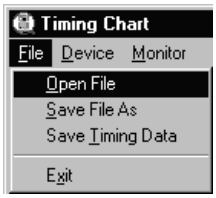
(1) Opening saved file

[Purpose]

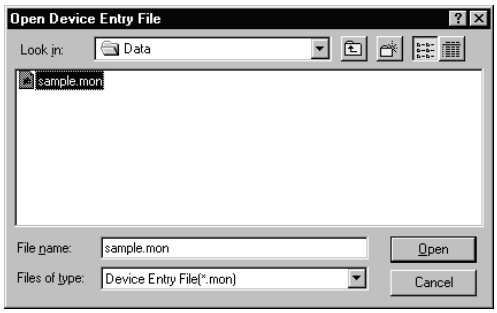
To open device registration file (*.MON) that have been saved.

[Operation procedure]

Select [File] - [Open file].



[Setting window]



Designate optional folder with "Look in", click file to be opened, then click Open button.

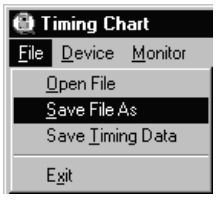
(2) Saving in file

[Purpose]

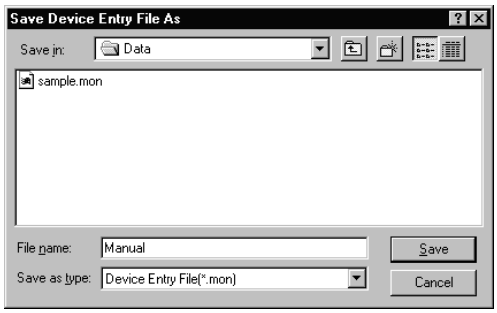
To save entered device as a device registration file (*.MON).

[Operation procedure]

Select [File] - [Save File As].



[Setting window]



Designate optional folder with "Save in", and enter new file name in "File name".
If data is to be overwritten on existing file, select the file by clicking.
After setting, click Save button.

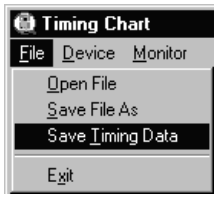
(3) Saving as timing chart data file

[Purpose]

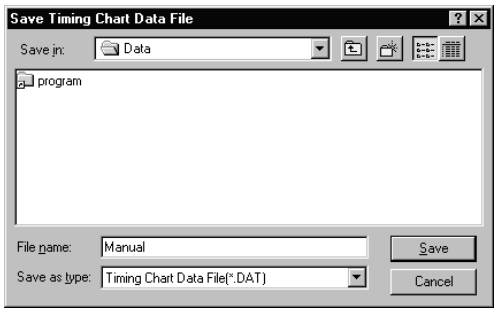
To save as a timing chart data file.
Timing chart data file can be read using timing chart format input of I/O system settings.

[Operation procedure]

Select [File] - [Save Timing data].



[Setting window]



Designate optional folder with "Save in", and enter new file name in "File name".
If data is to be overwritten on existing file, select the file by clicking.
After setting, click Save button.

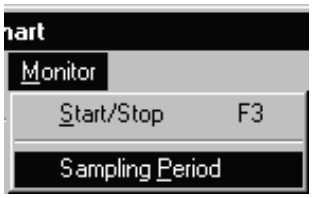
5.5.7 Setting sampling period

[Purpose]

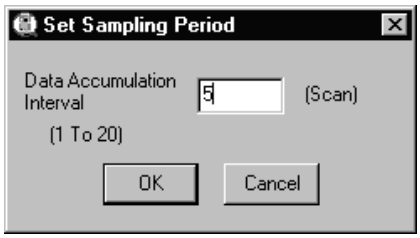
To set collection interval of device value in the range between 1 and 20 scans.

[Operation procedure]

(1) Select [Monitor] - [Sampling Period].



(2) Sampling period setting screen will appear: Input data collection interval.



<Example>

When Data Accumulation Interval is set to 5 scans, the device value will be collected every 5 scans and displayed in the timing chart display screen. (The default value is 1 scan.)

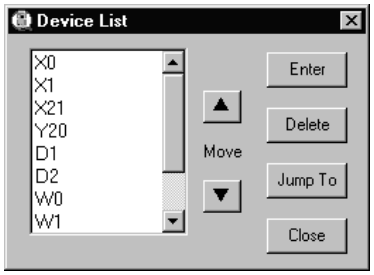
REMARK

Every time you change the sampling period, the data displayed in the timing chart will be cleared.

5.5.8 Other operations

(1) Displaying the list of registered devices

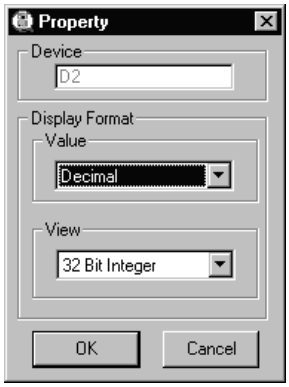
Select [Device] - [List Device]: The list of registered devices will be displayed.



- Click Enter button: Device entry dialog will appear.
  Refer to Section 5.5.4 for details.
- Click Delete button: The device will be deleted from target of monitoring.
  By using "Shift key + Select" or "Ctrl key + Select", two or more devices can be deleted simultaneously.
- Click Jump To button: Timing chart being displayed will jump to selected device.
- Click ▲ / ▼ button: Device being selected will move up/down.
- Selecting two or more devices
  (You cannot select two or more devices for moving.)

(2) Changing word device display format

Select "Word Device" and select [Device] - [Property]. The dialog shown below will appear: Display format can now be changed.



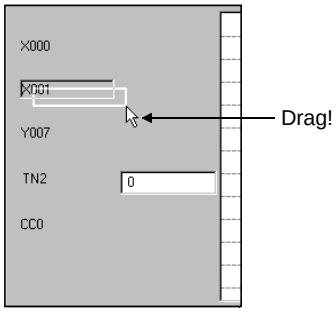
- Value
  Changes between decimal and hexadecimal.
- View
  Changes between 32 bit integer and Real number.
  (Effective only when selected device is a double word)

(3) Exchanging display position of device

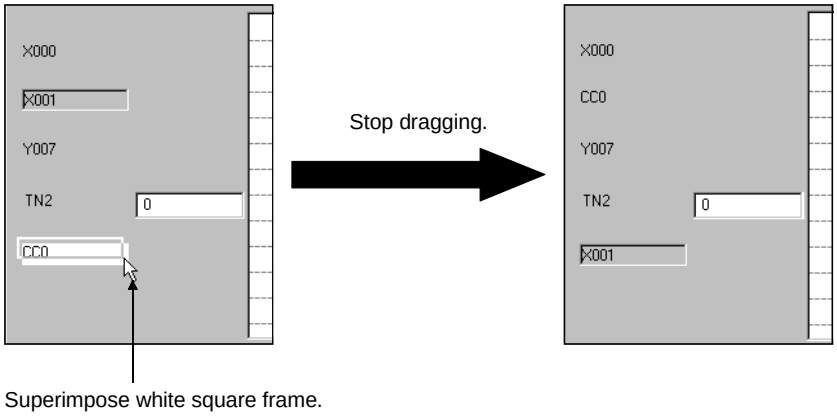
Dragging and dropping device name can exchange the device displayed position.

(a) Drag device name of the timing chart screen.

During dragging, a white square frame will appear.



(b) By superimposing white square frame on the device name to be exchanged, device name can be exchanged.



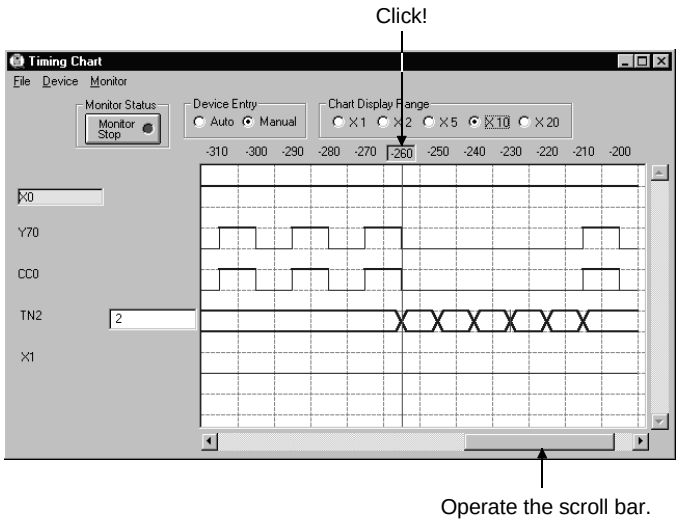
(4) Viewing the status changes of the devices monitored

The ladder logic test toll (LLT) can save up to 1000 samples of past states of devices.

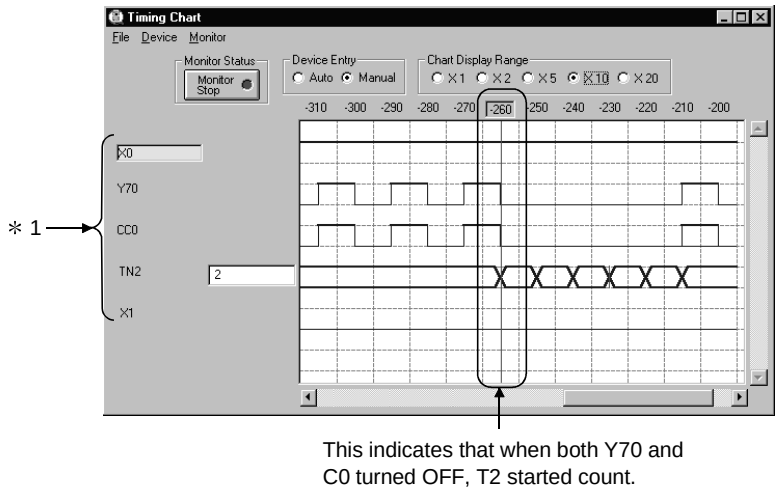
The following example shows how to confirm the device status of 260 scans before.

(a) Set the monitoring state of timing chart to stop.

(b) Operate the scroll bar until -260 appears on the timing chart screen.
Click "-260"on the screen.



(c) By clicking "-260", the device status of 260 scans before will appear in ＊1.
In ＊1, the bit device ON/OFF status and word device value are displayed.



5.5.9 Usable devices in the timing chart

The device names that can be used (displayed) in the timing chart are shown below.

A series CPU Functions, Motion Controller CPU Function Q series CPU (A Mode) Functions		
Symbols Displayed on Window		Device Name
Bit device	X	Input
	Y	Output
	M	Internal relay
	F	Annunciator
	B	Link relay
	TS	Timer (contact)
	TC	Timer (coil)
	CS	Counter (contact)
	CC	Counter (coil)
	Sp.M	Special relay
Word device	TN	Timer (Current value)
	CN	Counter (Current value)
	D	Data register
	W	Link register
	Buffer Memory	Buffer memory
	R	File register
	ER	Extension file register
	Z	Index register
	V	
	A	Accumulator
	Sp.D	Special register

FX series CPU Functions		
Symbols Displayed on Window		Device Name
Bit device	X	Input
	Y	Output
	M	Internal relay
	S	State
	TS	Timer (contact)
	TC	Timer (coil)
	CS	Counter (contact)
	CC	Counter (coil)
	Sp.M	Special relay
Word device	TN	Timer (Current value)
	CN	Counter (Current value)
	D	Data register
	Buffer Memory	Buffer memory
	Z	Index register
	V	
	Sp.D	Special register

QnA series CPU Functions Q series CPU (Q Mode) Functions		
Symbols Displayed on Window		Device Name
Bit device	X	Input
	Y	Output
	M	Internal relay
	L	Latch relay
	F	Annunciator
	V	Edge relay
	SB	Special link relay
	B	Link relay
	SM	Special relay
	TS	Timer (contact)
	TC	Timer (coil)
	STS	Retentive timer (contact)
	STC	Retentive timer (coil)
	CS	Counter (contact)
	CC	Counter (coil)
	FX	Function input
	FY	Function output
Word device	TN	Timer (Current value)
	STN	Retentive timer (Current value)
	CN	Counter (Current value)
	D	Data register
	W	Link register
	SW	Special link register
	SD	Special register
	R	File register
	ZR	Serial file register
	Z	Index register
	U	Buffer memory

MEMO

6. SAVING AND READING THE DEVICE AND BUFFER MEMORIES --- TOOL FUNCTIONS

The tool functions are functions to save the contents of the device memory or special function unit buffer memory at any time and to read the saved data to the ladder logic test tool (LLT).
The tool functions allow the contents of the ladder logic test tool (LLT) device memory or special function unit buffer memory to be saved during debugging. The saved data can then be read to the ladder logic test tool (LLT) when debugging is repeated, to allow debugging to be continued from the status when the data was saved.

6.1 Saving the Device and Buffer Memories

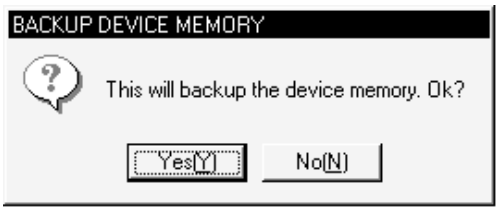
[Purpose]

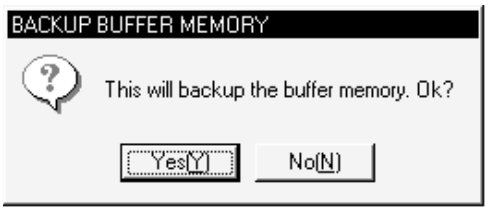
To temporarily save the contents of the device memory and buffer memory to allow debugging to continue after the personal computer is re-booted.

[Operation Procedure]

1) Set the execution status in the initial window to STOP when the device memory or buffer memory contents are to be saved.
2) Select [Tools] → [Backup device memory] or [Backup buffer memory].

[Setting Window]





Click on the Yes button, to save the entire device memory or the buffer memory for the slots allocated to special function units in the I/O assignment settings.
The buffer memory data is saved to the following directories:

- A series CPU Functions
  (Directory where the ladder logic test tool (LLT) are installed) \Acpu\Devmem
- QnA series CPU Functions
  (Directory where the ladder logic test tool (LLT) are installed) \QnAcpu\Devmem
- FX series CPU Functions
  (Directory where the ladder logic test tool (LLT) are installed) \FXcpu\Devmem
- Motion controller CPU Functions
  (Directories where the ladder logic test tool (LLT) are installed)\Acpu\Devmem
- Q series CPU Functions
  (Directory where the ladder logic test tool (LLT) are installed) \Qcpu\Devmem

[Example]

If C:\Melsec\LLT is designated as the directory where the ladder logic test tool (LLT) are installed, then the buffer memory data is saved to the following directories:

A series CPU Functions..... C:\Melsec\LLT\Acpu\Devmem
QnA series CPU Functions..... C:\Melsec\LLT\QnAcpu\Devmem
FX series CPU Functions..... C:\Melsec\LLT\FXcpu\Devmem
Motion controller CPU Functions..... C:\Melsec\LLT\Acpu\Devmem
Q series CPU Functions ..... C:\Melsec\LLT\Qcpu\Devmem

POINTS

(1) If the execution status is RUN, device memory/buffer memory cannot be saved.
To save the device memory/buffer memory, change the status to STOP.

(2) The ladder logic test tool (LLT) can save only one file.
If data already exists in the ladder logic test tool (LLT), the new file overwrites the existing data (file).

6.2 Reading Saved Device Memory or Buffer Memory Data

[Purpose]

To read the stored data of device memory and buffer memory.

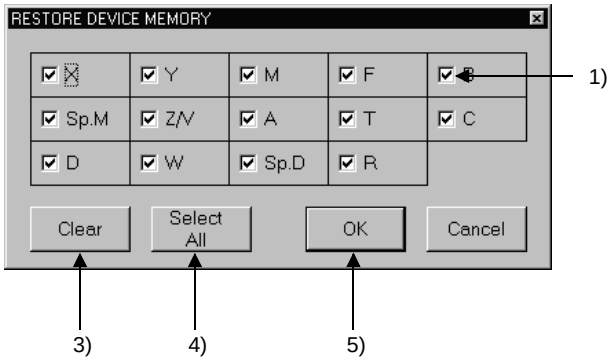
[Operation Procedure]

Set the execution status in the initial window to STOP. Select [Tools] → [Restore device memory] or [Restore buffer memory].

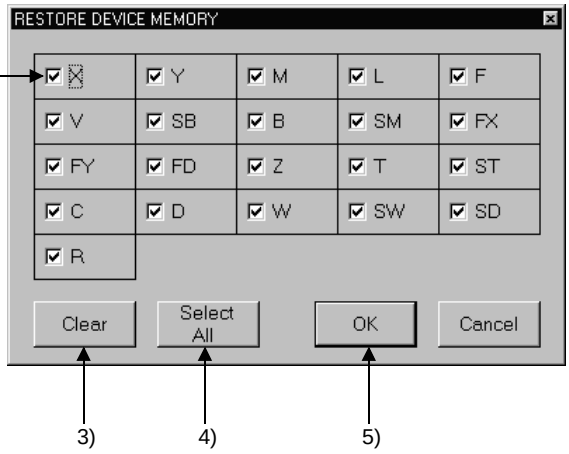
[Setting Window]

Reading device memory

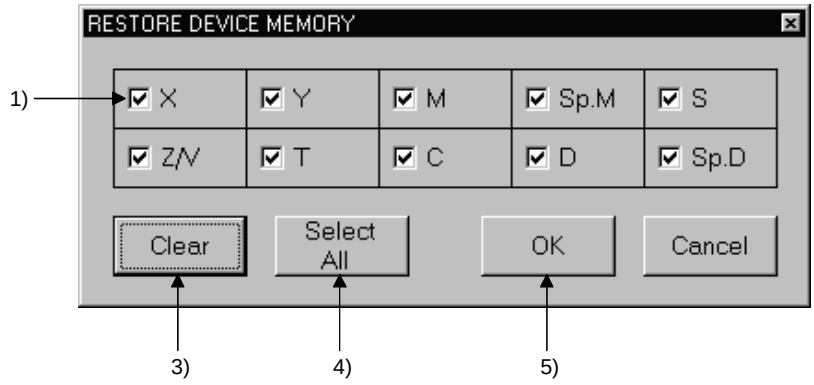
<A series CPU, Motion controller CPU and Q series CPU (A Mode)>



<QnA series CPU and Q serise CPU (Q Mode)>

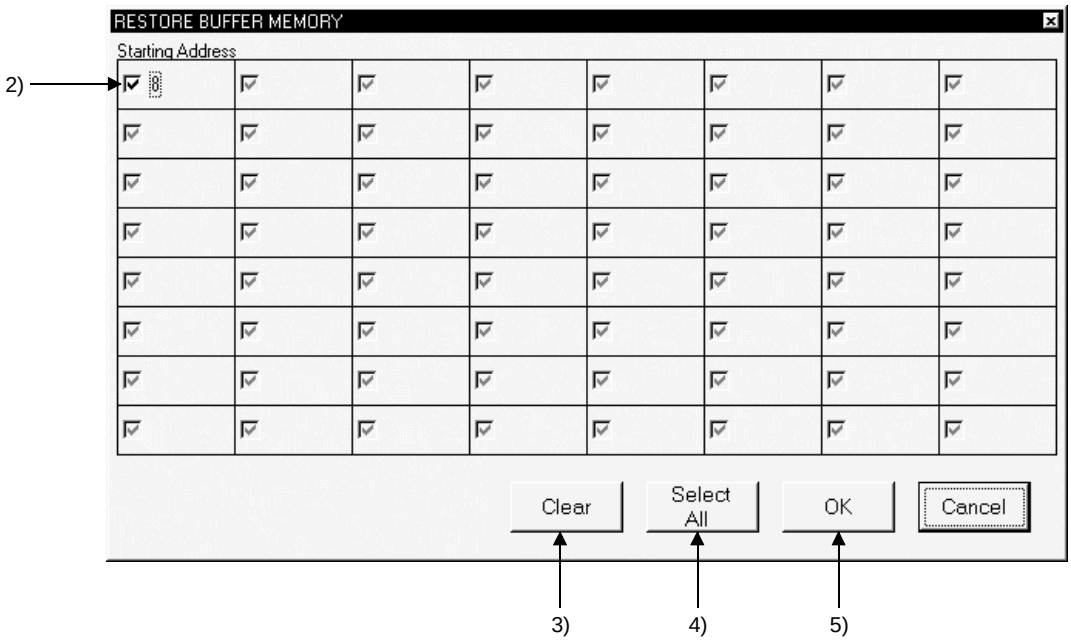


<FX series CPU>

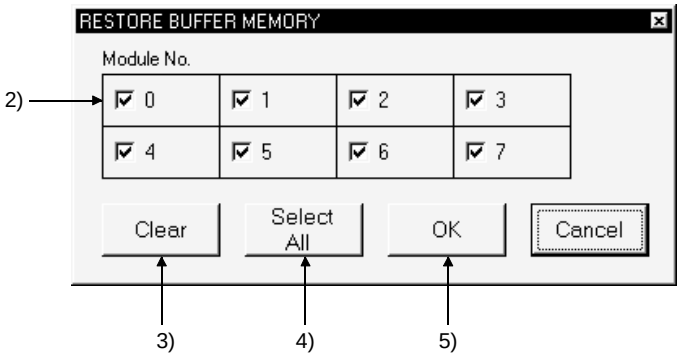


Reading buffer memory

<A series CPU, QnA series CPU, Motion controller CPU and Q serise CPU >



<FX series CPU>



[Description]

1) Read Device Check Boxes

Click in the check boxes to select the devices read to ladder logic test tool (LLT).
Click on a check box again to cancel a selection.
All devices are selected by default.

2) Read Special Function Module Check Boxes

For A series, QnA series, Motion controller or Q series CPU functions, the special function module first I/O number is displayed at the top of the window.
The special function module block number or module block number is displayed at the top of the FX series window.
Click the check box to select the special function module to be read to the ladder logic test tool (LLT).
Click on a check box again to cancel a selection.
All special function modules are selected by default.
Only the special function module buffer memory can be read.

3) [CLEAR] button

Click to clear all device or special function module selections.

4) [SELECT ALL] button

Click to select all devices or special function modules.

5) [OK] button

Click this button after completing all settings.

POINTS

(1) Device memory/buffer memory read is not allowed while the execution status is RUN.
Change the execution status to STOP before reading device memory/buffer memory.

(2) With the A series, QnA series, Q series, Motion controller CPU functions, selection of a slot that is not assigned to a special function module using the GPPW I/O assignment setting is not possible.
Before reading buffer memory, set the GPPW I/O assignment.

MEMO

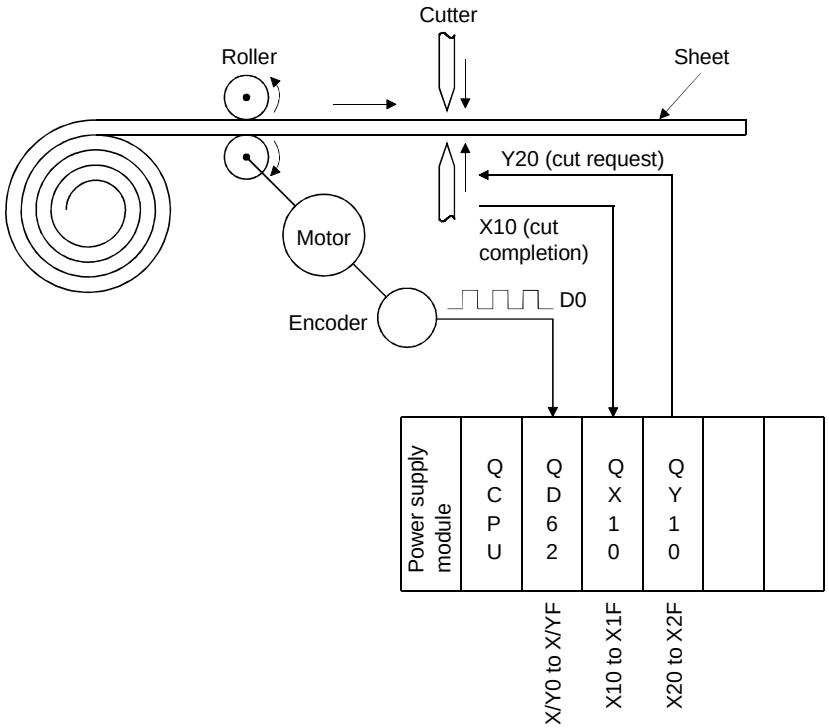
7. EXAMPLES OF LADDER LOGIC TEST TOOL (LLT) APPLICATIONS

This chapter provides examples of debugging an actual program using the ladder logic test tool (LLT).
In this manual, explanations are given using the system configuration shown below and program shown on page 7-2.

[Simulation Example]

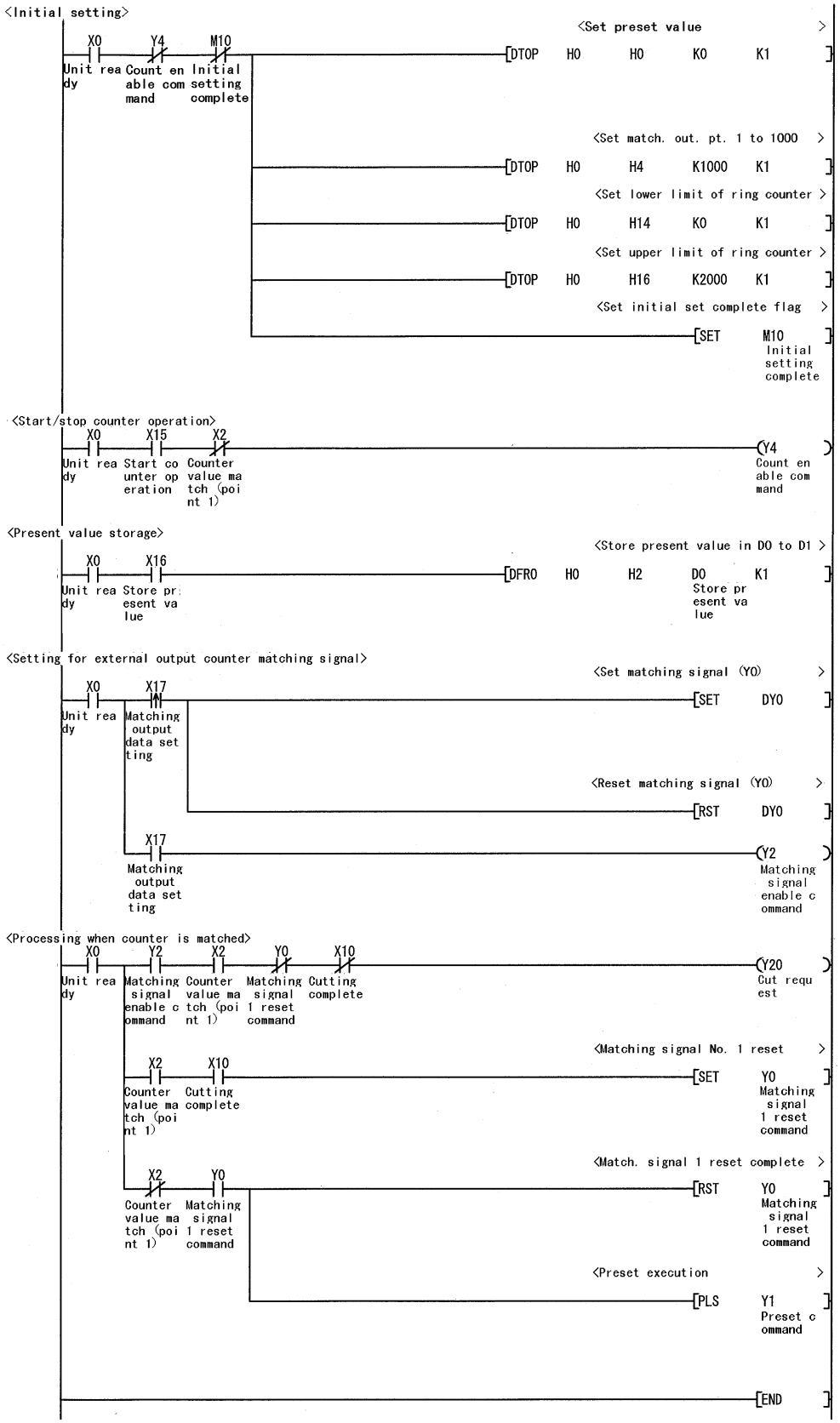
The following shows the system where sheet is fed using roller and cut by cutter. Rotation amount of roller is taken into high-speed counter unit (Channel 1 is used), roller stops when the value reaches "1000" and sheet is cut by Y20 (cut request). Roller turns again by X10 (cut completion) from cutter to feed sheet.

[System Configuration]



POINT
Program, device registration file (∗.MON), and I/O system setting file (∗.LIM) are stored in "Manual" folder of CD-ROM for the product.

[Sequence program]



[Devices used]

	Device No.	Signal name	Contents
High-speed counter unit signals	X0	Unit ready	Turns ON when high-speed counter unit is ready for start.
	X2	Counter value matching (point No.1)	Turns ON when present value matches the preset value of matching output point. Turns ON when value reaches "1000" in this example.
	Y0	Matching signal No. 1 reset command	Turns ON to turn X2 OFF.
	Y1	Preset command	Turns ON when executing preset functions. In this example, present value is set to "0" when preset is executed.
	Y2	Matching signal enable command	Turns ON when matching signal is output to external terminal. In this example, it can be ignored.
	Y4	Count enable command	Starts high-speed counter unit. Count can be executed only when this signal is turned ON.
Cutter operation control signals	X10	cutting complete	Turns ON when cutting of sheet is completed. Turns OFF when Y20 is turned OFF.
	Y20	Cut request	Turns ON when sheet cutting is to be executed.
Signals for ON/OFF by user	X15	Count operation start	Turns ON when executing count with high-speed counter unit.
	X16	Present value reading	Turns ON when reading present value of high-speed counter unit.
	X17	Matching output data setting	Turns ON when matching signal is externally output. Normally turns ON when matching signal is used.
Other devices	M10	Initial setting complete	Signal to inhibit initial setting at scan 2 or after.
	D0 to D1	Present value storage	Device to store present value.

7.1 Debugging Using GPPW Step Execution Function

Using GPPW independently, it is not possible to turn arbitrary devices ON/OFF or to change device values during step execution. However, using the ladder logic test tool (LLT) allows the device values to be easily changed during step execution.
In this section, example of debugging with step execution jointly used with following program is described.

Running the program on page 7-2 and turning on X0 causes "SP. UNIT ERROR" to occur.
Carry out step execution to find out the step at which the error has taken place.

(1) Pre-debugging operation

1) Start GPPW and create the program on page 7-2.

2) Choose [Tools] → [Start ladder logic test] on GPPW to start the ladder logic test tool (LLT). (At a start, the parameters and program are automatically written and SWITCH changes to RUN.)

(2) Step execution

1) Set SWITCH of the ladder logic test tool (LLT) to STEP RUN.

2) Turn on X0.

3) Move the cursor to the position where step execution will be started (step 0).

4) Select [Online] → [Debug] → [Debug] on GPPW.
In addition, select [Online] → [Debug] → [Step execution] on GPPW.
The Step Execution dialog box then appears.

5) Every time you click the Step excute button in the Step Execution dialog box, one instruction is executed.

6) As you click the Step excute button to run the program on an instruction-by-instruction basis, you will know that "SP. UNIT ERROR" occurs when [DTOP H0 H0 K0 K1] is executed.

POINT

"SP. UNIT ERROR" occurred because you attempted to write a value to the buffer memory using the TO instruction, without making I/O assignment.
Section 7.2 gives a debugging example in which I/O assignment is made and the buffer memory is used.

7) Double-click "Parameter" - "Set PLC parameter" from project data list on GPPW and click "I/O assignment" tab so that I/O assignment is as shown below.

	Slot	Type	Model	Points
0	0 (0-0)	Special	QD62	16 points
1	0 (0-1)	Input	QX10	16 points
2	0 (0-2)	Output	QY10	16 points

8) By updating parameter with PLC writing and setting to RUN after resetting, error will not occur even if X0 is turned ON.

7.2 Using Timing Chart Display for Debugging

This section explains how to check device value changing timings with the timing chart which displays the device chart using the ladder logic test tool (LLT).

(1) Pre-debugging operation

1) Start GPPW and create the program on page 7-2.

2) Double-click "Parameter" - "PLC parameter" of project data list on GPPW, click the "I/O assignment" tab, and make I/O assignment as indicated below.

	Slot	Type	Model	Points
0	0 (0-0)	Special	QD62	16 points
1	0 (0-1)	Input	QX10	16 points
2	0 (0-2)	Output	QY10	16 points

3) Choose [Tools] → [Start ladder logic test] on GPPW to start the ladder logic test tool (LLT). (At a start, the parameters and program are automatically written and SWITCH changes to RUN.)

4) Select [Start] - [Device Memory Monitor] from initial window of Ladder Logic Test tool (LLT), and start device memory monitor.

(2) Displaying the timing chart

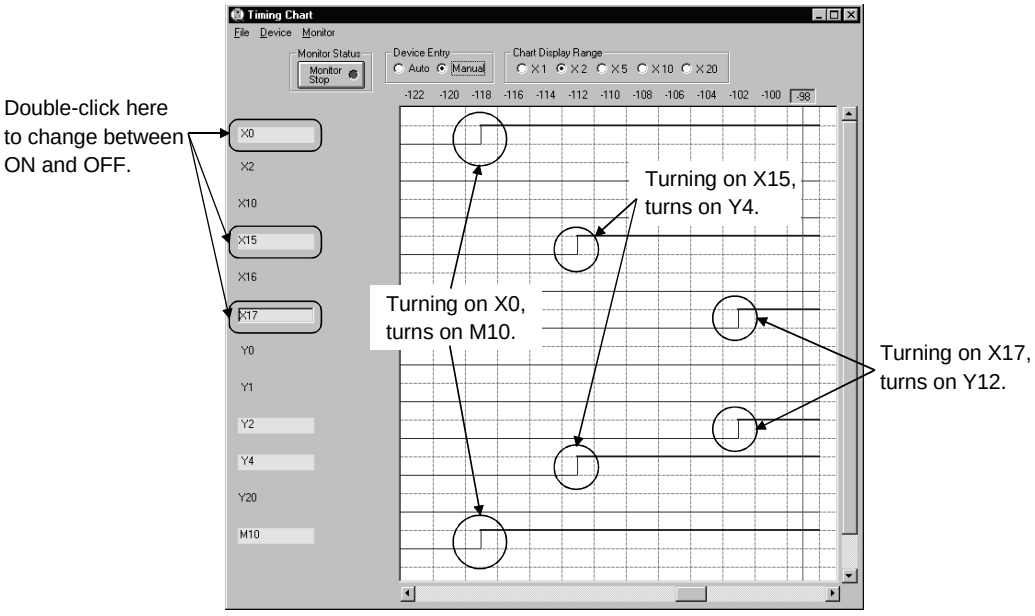
1) Running the timing chart
Choose [Timing Chart] → [Run] of Device Memory Monitor to run the timing chart.

2) Register device and start monitoring.
Register the following devices and click "Monitor Stop" button to start monitoring.
• X0, X2, X10, X15, X16, X17, Y0, Y1, Y2, Y4, Y20, M10, D0 (Double word)

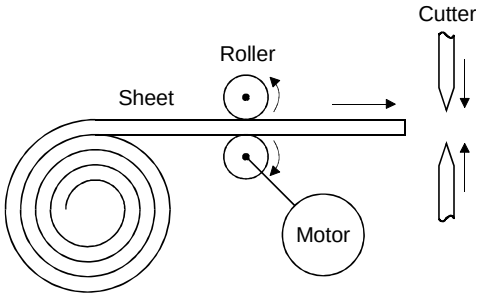
3) Turning X0, X15 and X17 ON (initial setting)
X0, X15 and X17 are turned ON in sequence.
When X0 is turned ON, M10 is turned ON, in like manner X15: Y4, and X17: Y2.

POINT

The timing chart retains data of up to 1000 scans.



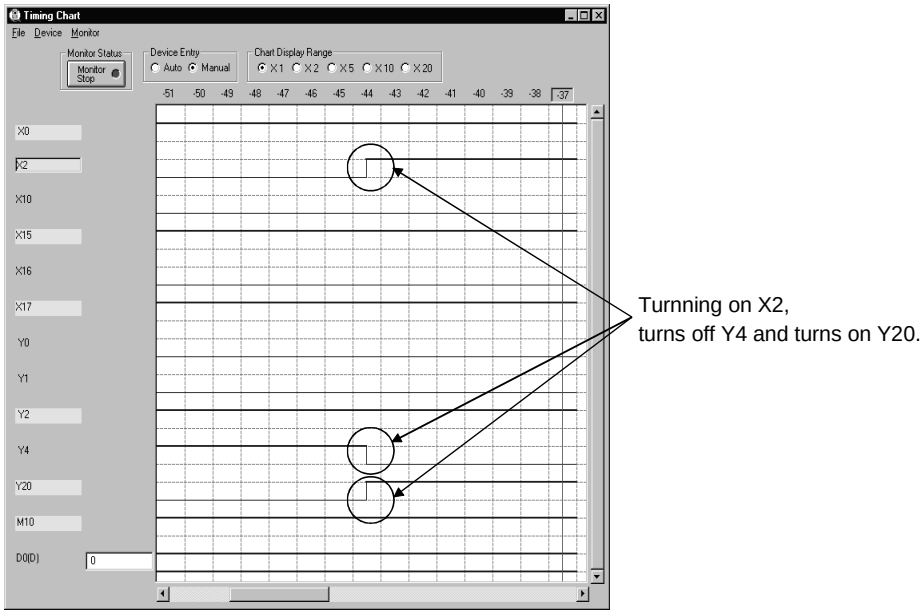
<Actual machine state>



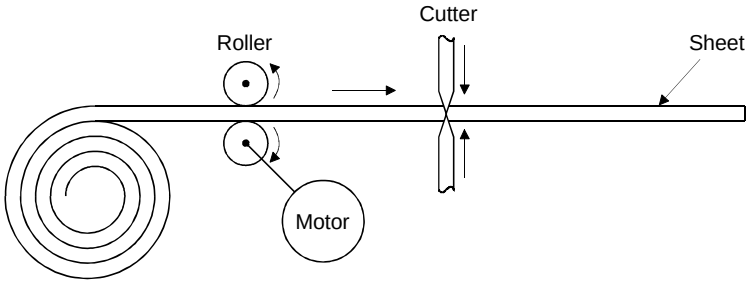
4) Turning X2 ON (Sheet feeding complete → start cutting)

Assuming that present value of high-speed counter unit matches the matching output point No. 1 (reaches 1000), turn X2 ON.

When X2 is turned ON, Y4 is turned OFF to stop roller operation, and cutter executes cutting by turning Y20 ON.

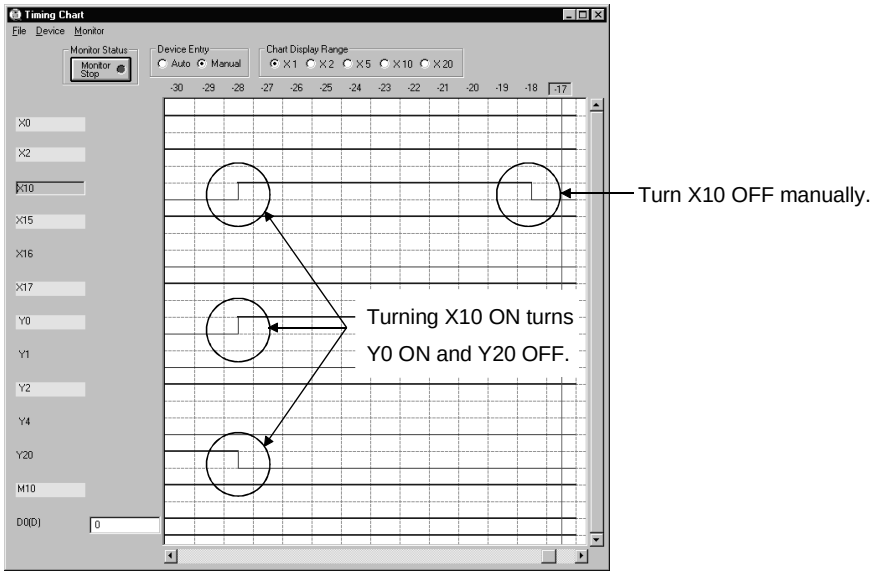


<Actual machine state>

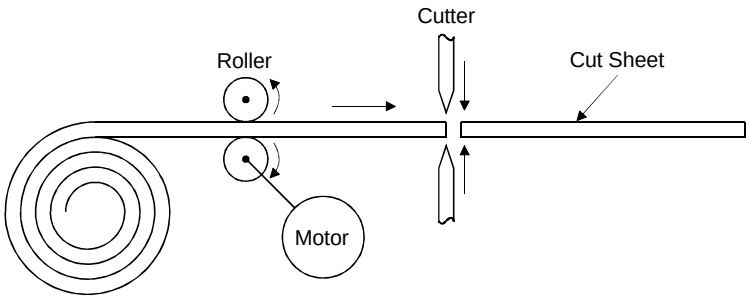


5) Turn X10 ON (cutting complete)

Assuming that cutting is complete, signal X10 sent from cutter turns ON.
When X10 is turned on, Y20 is turned OFF and YO is turned ON.
When Y 20 is turned ON, cutter turns OFF X10. Turn X10 OFF manually.



<Actual machine state>



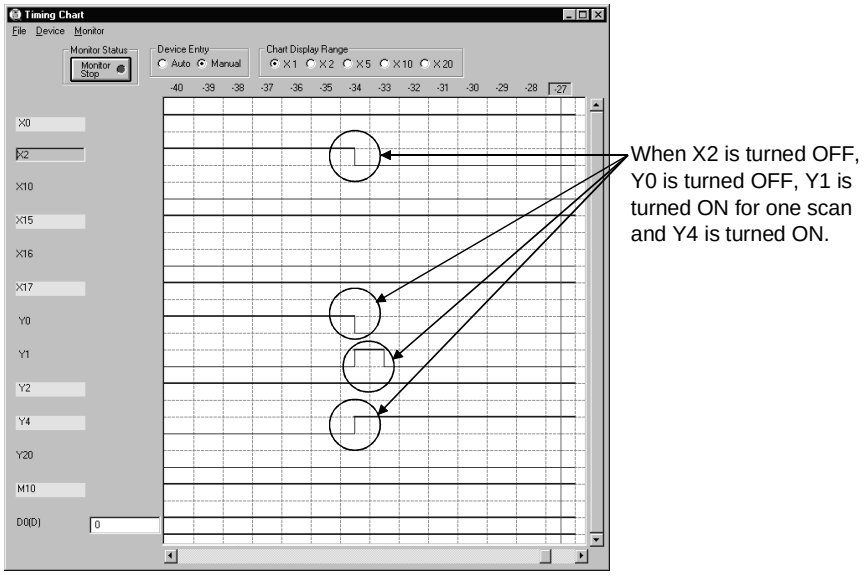
6) Turn X2 OFF (Re-starting operation)

When Y0 is turned ON, high-speed counter unit turns X2 OFF. Turn X2 OFF manually.

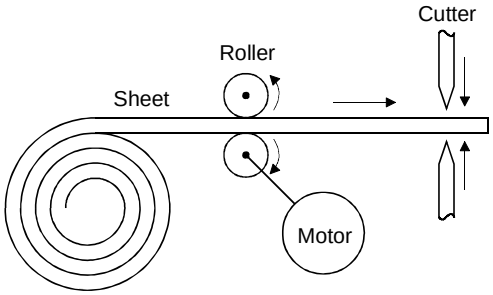
When X2 is turned OFF, Y0 is turned OFF, Y1 ON and then OFF and Y4 ON.

By turning Y4 ON, roller re-starts operation.

General operation of program is now complete.



<Actual machine state>



7.3 Using I/O System Settings for Debugging

This section describes the operation to perform simulation of external equipment using the I/O system setting.

(1) Pre-debugging operation

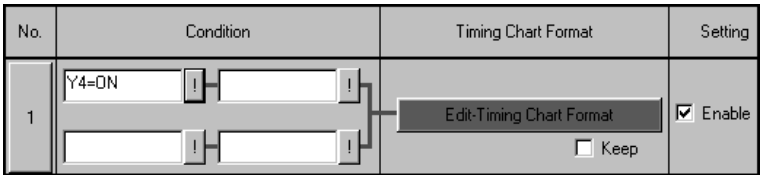
1) Start GPPW and create the program on page 7-2.
2) Double-click [Parameter] - [PLC parameter] of project data list on GPPW and click "I/O assignment" tab so that I/O assignment is as shown below.

	Slot	Type	Model	Points
0	0 (0-0)	Special	QD62	16 points
1	0 (0-1)	Input	QX10	16 points
2	0 (0-2)	Output	QY10	16 points

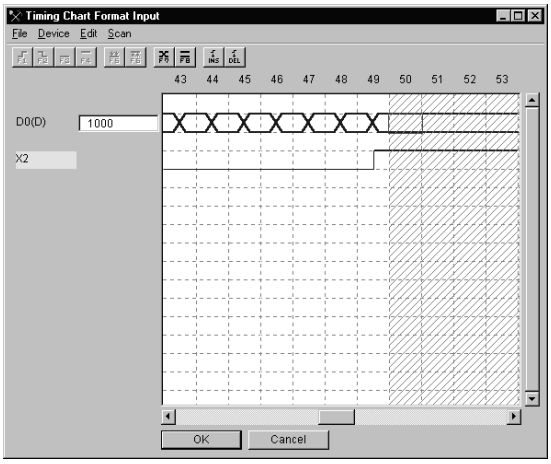
3) Select [Tool] - [Start ladder logic test] on GPPW to start ladder logic test tool (LLT). (Once started, parameter and program will be automatically written and execution state is set to RUN.)
4) Select [Start] - [I/O System Settings] on initial window of Ladder logic test tool (LLT) to start I/O system setting.

(2) Operation of I/O system settings

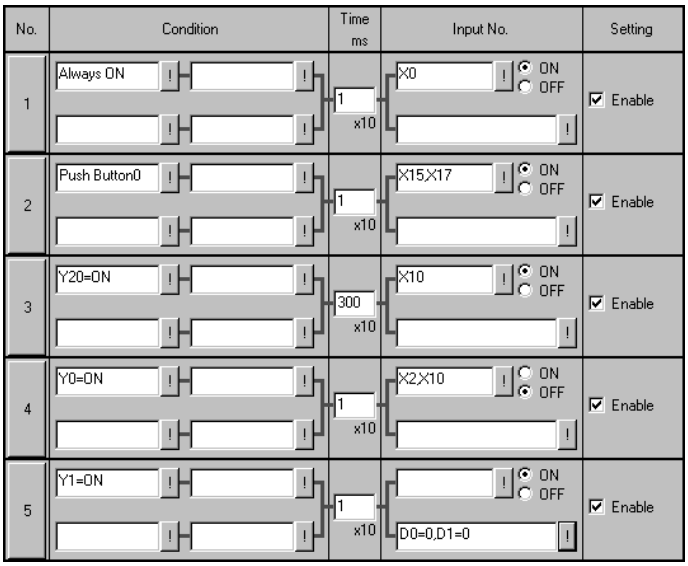
1) Make the following settings.
• Timing chart input
The following setting is performed: D0 is counted up by turning Y4 ON, and X2 turns ON when count reaches 1000 (matching output).



<Timing chart format input screen>
Count up D0 (32 bit integer) assuming present value.
Turn ON X2 at the moment D0 reaches 1000.
D0: Counted up in 20 count units from 0 to 49th scan.
20 (0 scan), 40, 60, 80 to 1000 (49th scan)
X2: Turned OFF 0 to 48th scan, turned ON only for 49th scan.



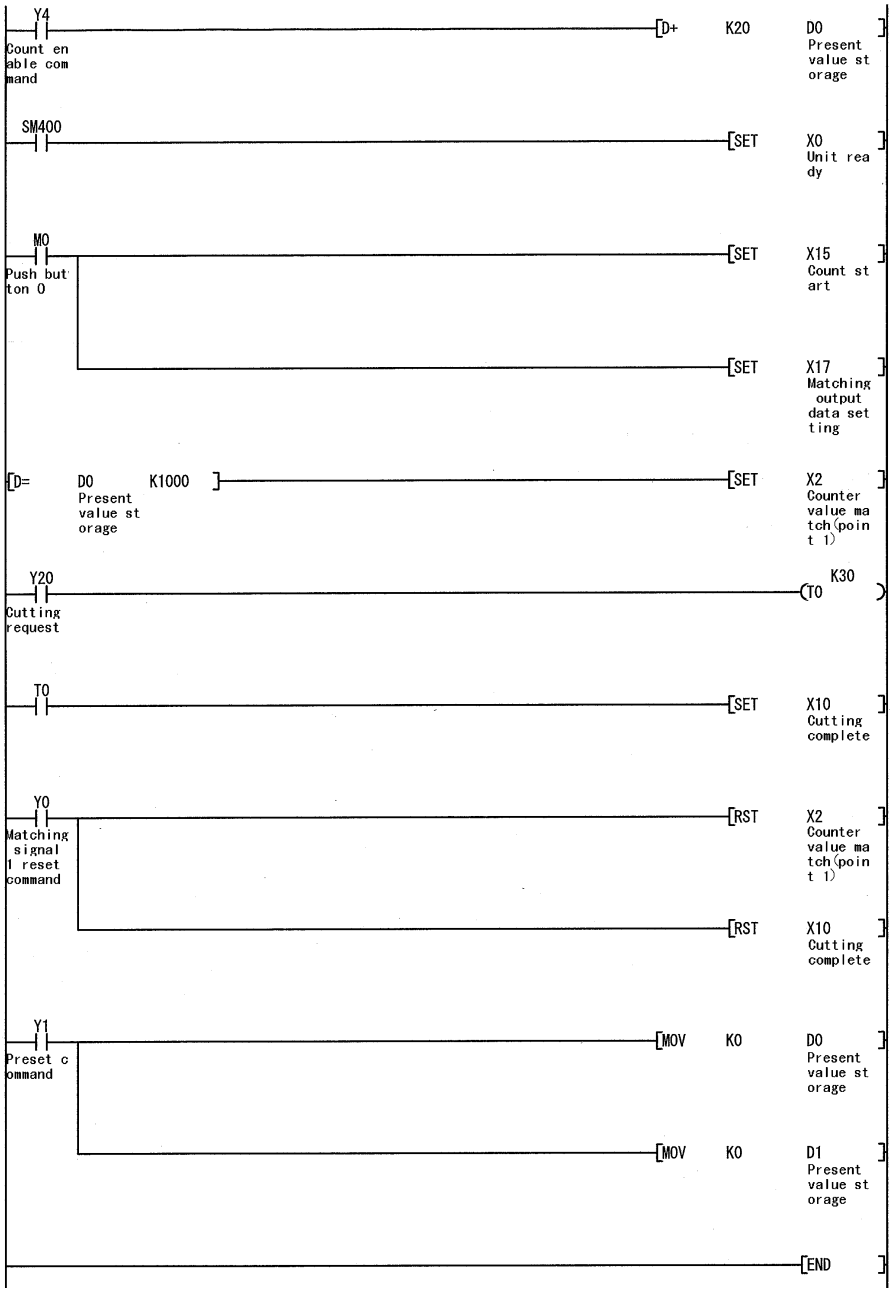
• Device value input



Set No.	Contents
1	X0 (unit ready) is normally turned ON.
2	By clicking push button 0, X15 (count operation start) and X17 (matching data setting) which must be turned ON by user, can be turned ON. Operation will start by clicking push button 0.
3	When Y20 (cut request) is turned ON, X10 (cut complete) turns ON 3 seconds later. This assumes the operation through cutting has been completed, after requesting cut.
4	When Y0 (matching signal No. 1 reset command) is turned ON, X2 (counter value matching (point No. 1)) and X10 (cutting complete) are turned OFF. Operation in which turning Y0 ON turns X2 OFF assumes the operation of high-speed counter unit. Turing X10 OFF assumes the operation to return cutter signal to initial value.
5	When Y1 (preset command) is turned ON, D0 and D1 are set to "0". This assumes the preset operation of high-speed counter unit.

2) Save I/O system settings.
3) Select [File] - [Execute I/O System Settings] to execute I/O system setting.
   Execution state of ladder logic test tool (LLT) is set to RUN.
4) Select [Online] - [Monitor Mode] to set I/O system setting to monitor mode.

When I/O system setting has been performed, the following pseudo program is created.
When running program, the pseudo program will be executed after the created program is executed.



(3) Displaying timing chart

To confirm the device value, monitor using timing chart.

1) Starting the timing chart

Select [Timing Chart] - [Run] from device memory monitor to start timing chart.

2) Registering device and starting monitoring

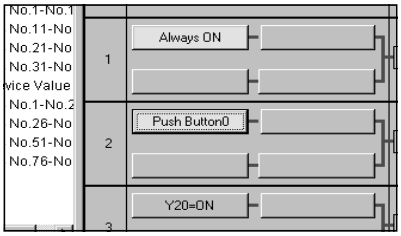
Register the devices shown below and click "Monitor Stop" button to start monitoring.

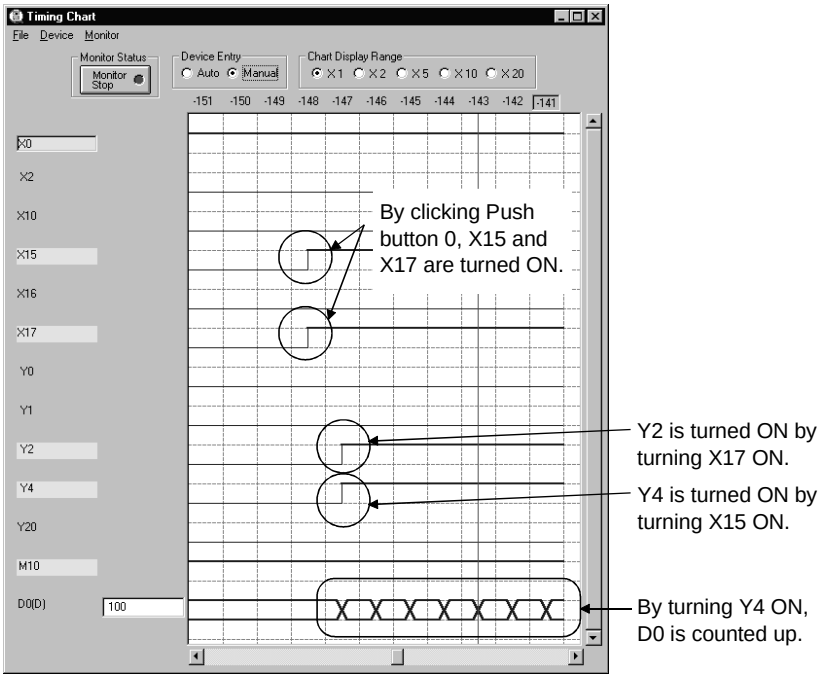
• X0, X2, X10, X15, X16, X17, Y0, Y1, Y2, Y4, Y20, M10, D0 (Double word)

(4) Confirming the program operation

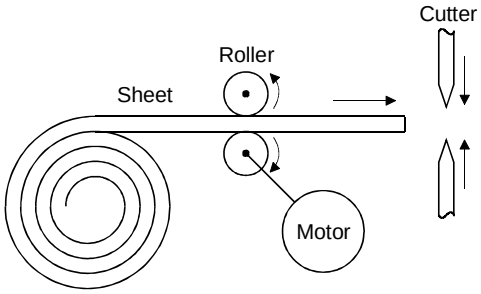
1) Click Push button 1. (Initial setting)

When Push button 0 of I/O system settings is clicked, operation will start.
By clicking Push button 0, X15 and X17 are turned ON.
Turning X15 ON turns Y4 ON, and turning X17 ON turns Y2 ON. In addition, DO will be counted up in 20-count units by turning ON Y4.





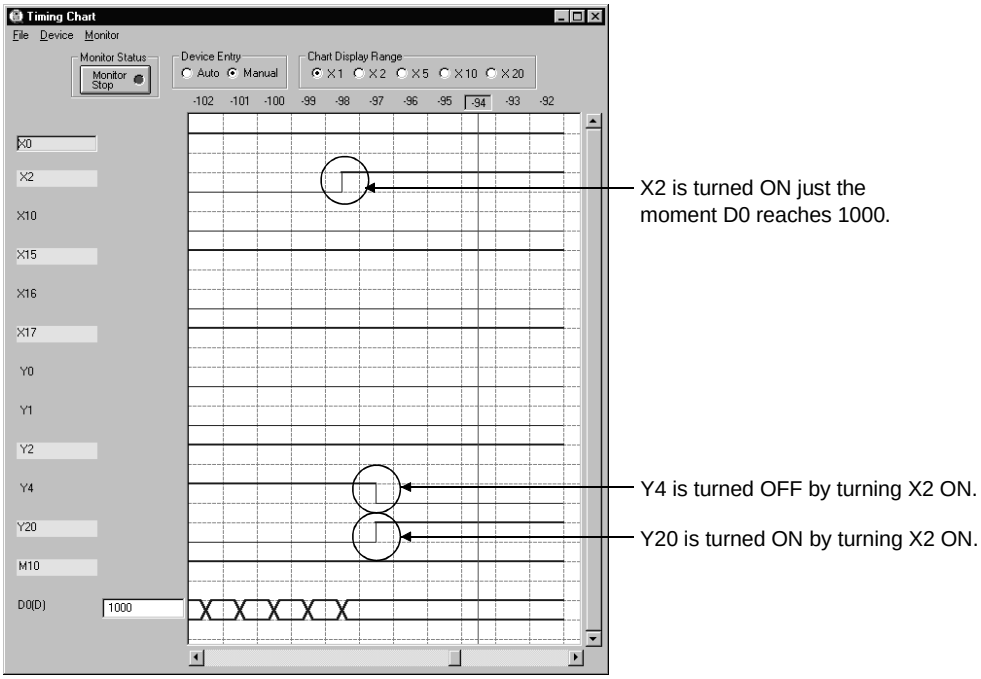
<Actual machine status>



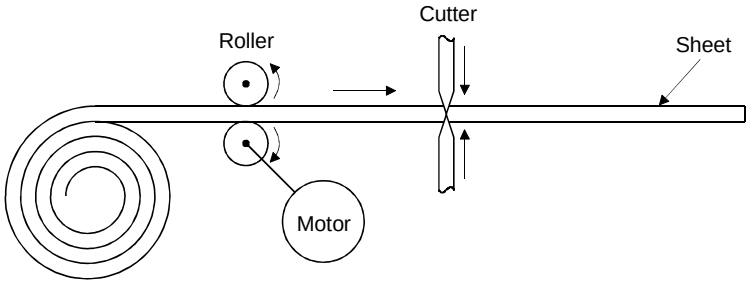
2) Turning X2 ON (Sheet feeding complete → Start cutting)

X2 is turned ON the moment D0 reaches 1000.

Y4 is turned OFF by turning X2 ON to stop roller operation, and cutting is executed by cutter when Y20 is turned ON.



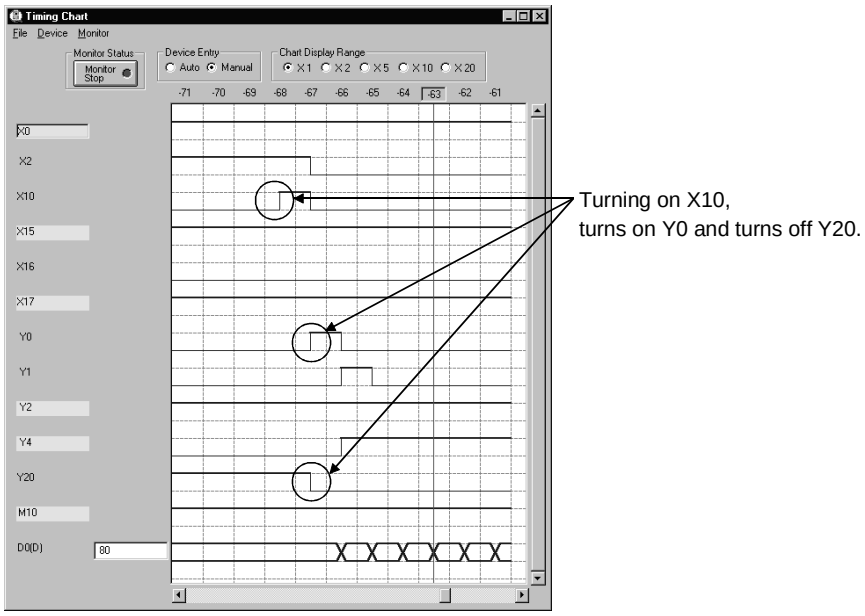
<Actual machine status>



3) Turning X10 ON 3 seconds after Y20 is turned ON (Cutting completed)

Assuming that 3 seconds is needed until cutting operation is complete, X10 should be turned ON 3 seconds after Y20 is turned ON.

When X10 is turned ON, Y20 is turned OFF and Y0 is turned ON.



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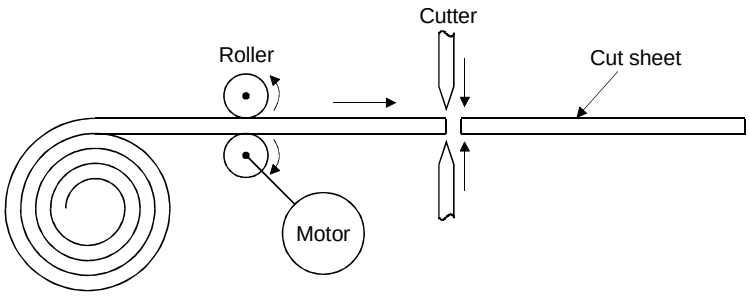

MEMO

8. TROUBLESHOOTING

8.1 Error Messages Displayed on the LED Indicators

This section describes error messages and error codes occurring in the ladder logic test tool (LLT), gives a description and cause of the error, and suggests remedies.

(1) Ladder Logic Test Tool (LLT) for A series CPU Functions

Error Message Table

Error Message	Error Code (D9008) ∗1	Details Error Code (D9091)) ∗1	Error Description and Cause	Remedy
"INSTRCT CODE ERR." (Checked at RUN → STOP or at the execution of an instruction)	10	101	The program contains an instruction code which could not be decoded by the ladder logic test tool (LLT).	Read the error step using GPPW and modify the program step.
		102	Index qualification used for a 32-bit constant.	
		103	The device specified in the dedicated instruction is incorrect.	
		104	The program structure of the dedicated instruction is incorrect.	
		105	The command name of the dedicated instruction is incorrect.	
		107	(1) The index qualification used for the device number and SV in timer or counter OUT instructions. (2) The index qualification used for the label number of the pointer (P) added at the start of an instruction jump destination or for the label number of the interrupt pointer (I) added at the start of an interrupt program for the following instructions. CJ SCJ CALL JMP LEDA/B FCALL LEDA/B BREAK	
"MISSING END INS." (Checked at RUN → STOP)	12	121	There is no END (FEND) instruction in the main program.	Write END in the end of main program.
		122	A sub program has been allocated in the parameters and there is no END (FEND) instruction.	Write END in the end of the sub-program.
"CAN'T EXECUTE(P)" (Checked at the execution of the instruction)	13	131	The device number of the pointer (P) or the interrupt pointer (I) used as a label added to the destination head is duplicating.	Remove the duplicated number of pointer (P) with the destination head and correct so that the number is not duplicated.
		132	The label of the pointer (P) specified by CJ SCJ CALL CALLP JMP LEDA/B FCALL and LEDA/B BREAK instructions is not specified prior to the END instruction.	Read the error step using GPPW, check the step and insert the destination pointer (P).

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Error Message Table (cont.)

Error Message	Error Code (D9008) ∗1	Details Error Code (D9091)) ∗1	Error Description and Cause	Remedy
"CAN'T EXECUTE(P)" (Checked at the execution of the instruction)	13	133	(1) There is no CALL instruction for the RET instruction in the program. (2) There is no FOR instruction for the NEXT, LEDA/B BREAK instructions in the program. (3) The nesting level of CALL, CALLP, or FOR exceeds the nesting limit six (6) and is executing the sixth level. (4) There is no RET or NEXT instructions for the CALL or FOR instruction.	(1) Read the error step using GPPW. Check and modify the program step. (2) Nesting level for the CALL, CALLP and FOR instructions must be five (5) or less.
		134	There is no parameter settings for the sub program. Can not execute the CHG instruction.	Read the error step using GPPW. Delete the line containing the CHG instruction.
		136	There is no parameter settings for sub program 1. Can not execute the ZCHG1 instruction.	Read the error step using GPPW. Delete the line containing the ZCHG1 instruction.
		137	There is no parameter settings for sub program 2. Can not execute the ZCHG2 instruction.	Read the error step using GPPW. Delete the line containing the ZCHG2 instruction.
		138	There is no parameter settings for sub program 3. Can not execute the ZCHG3 instruction.	Read the error step using GPPW. Delete the line containing the ZCHG3 instruction.
"WDT ERROR" (Checked at the execution of the sequence program.)	22	220	A program instruction is executed infinitely in a single scan.	Read the error step and confirm there is no occurrence of an infinite loop.
"END NOT EXECUTE" (Checked at the execution of the instruction.)	24	241	The entire program has been executed without executing the END instruction. (1) There is no END instruction. (2) The END instruction is replaced with some other instruction.	Please write the program to PLC again.
"SP.UNIT ERROR" (Checked at the execution of the FROM/TO instruction or special function module dedicated instruction.)	46	461	There is no special function module in the area specified by the FROM/TO instruction.	(1) Read the error step using GPPW. Check and modify the FROM/TO instruction in the program step. (2) Correct the I/O unit allocation parameter settings.

Error Message Table (cont.)

Error Message	Error Code (D9008) ∗1	Details Error Code (D9091) ∗1	Error Description and Cause	Remedy
"OPERATION ERROR" (Checked at the execution of the instruction)	50	501	(1) Operations using the file register (R), are executed with the device number or block number exceeding the range specified for the file register (R). (2) The file register is used in the program without setting necessary parameters for the file register (R).	(1) Read the error step using GPPW. Check and modify the program step. (2) Set the parameters for the file register (R).
		502	The combination of devices specified by instruction is incorrect.	Read the error step using GPPW. Check and modify the program step.
		503	The storage data or constants are not within the usable range.	
		504	The number of data handling settings exceeds the usable range.	

∗1 Characters in parentheses ( ) indicate the special register number where the information is saved.

(2) Ladder Logic Test Tool (LLT) for QnA series CPU

Error Message Table

Error Message	Error Code (SD0) ∗1	Error Description and Cause	Remedy
END NOT EXECUTE	1010	The entire program has been executed without executing the END instruction. (1) There is no END instruction. (2) The END instruction is replaced with some other instruction.	Please write the program to PLC again.
	1011		
	1012		
SP.UNIT ERROR	2110	There is no special function module in the area specified by the FROM/TO instruction.	(1) Read the error step and correct the contents of the FROM/TO instruction. (2) Correct the I/O unit parameter settings.
	2111	There is no network function module in the area specified by the link direct device (J # \ #).	Check and modify the FROM/TO instruction in the program step.
	2112	There is no network function module or the unit in the area specified is not supporting the instruction.	Check and modify the special function unit dedicated instruction in the error step of the program.
	2113	There is no simulation data for the special function unit simulation.	
MISSING PARA.	2200	Parameter file is missing.	Please write the parameter again.
FILE SET ERROR	2400	The file specified in the parameter settings is not available.	(1) Please delete the file name from the parameter settings. (2) Make a file as specified in the parameter settings.
FILE OPE.ERROR	2410	The file specified in the sequence program is not available.	(1) Check and modify the specified file name. (2) Create the specified file.
CAN'T EXE.PRG.	2500	A program file exists with a device which exceeds the device range specified in the device parameter settings.	Read common information of error using GPPW. Check and correct the device by comparing device allocation parameter settings.
	2501	Multiple program files exist. But, the program settings parameter is set to "None".	Change the parameter settings to "Present" or delete unnecessary programs.
	2502	The program is incompatible with QnA CPU or the file content is not a sequence program.	Please write the program again.
	2503	No program files exist.	Please check the program configuration.
	2504	Two or more Ordinary/Control SFC programs were executed.	Please check the parameter and program configuration.
PARAMETER ERROR	3001	Parameter data is corrupted.	Please write the parameter again.
INSTRCT CODE ERR.	4000	The program contains an instruction code which cannot be decoded by the CPU.	Please write the program again.
MISSING END INS.	4010	The program contains no "END (FEND)" instruction.	Please check and correct the program.
CAN'T SET(P)	4020	The total number of pointers used in the program files exceeds the maximum allowable number defined in the parameter settings.	Check the error step and correct the program.
	4021	Overlapping of common pointers exist.	

Error Message Table (cont.)

Error Message	Error Code (SD0) ∗1	Error Description and Cause	Remedy
OPERATION ERROR	4100	An instruction contains data that cannot be processed.	Check the error step and correct the program.
	4101	The instruction data exceeds the allowable number of data handled. Or the storage data constants specified in the instruction exceeds the usable range.	
	4102	Incorrect network number or station number is specified in a network dedicated instruction.	
	4103	Illegal configuration of PID dedicated instruction.	
FOR NEXT ERROR	4200	A FOR instruction is executed without NEXT instruction. Or the number of NEXT instructions is lower than the number of FOR instruction.	Check the error step and correct the program.
	4201	A NEXT instruction is executed without a FOR instruction. Or the number of NEXT instructions is greater than the number of FOR instructions.	
	4202	The nesting exceeds 16 loops.	Reduce nesting count to 16 or less loops.
	4203	A BREAK instruction is executed when there is no FOR instruction.	Check the error step and correct the program.
CAN'T EXECUTE (P)	4210	A CALL instruction is executed without a destination pointer.	Check the error step and correct the program.
	4211	The executed subroutine program contains no RET instruction.	
	4212	A RET instruction is existing before the FEND instruction.	
	4213	The nesting exceeds 16 loops.	Reduce nesting count to 16 or less loops.
INST. FORMAT ERROR	4230	Mismatch in the number of CHK and CHKEND instructions.	Check the error step and correct the program.
	4231	Mismatch in the number of IX and IXEND instructions.	
	4232	The structure of FOR - NEXT instructions is incorrect.	
	4233	The structure of DO - WHILE instructions is incorrect.	
	4234	The structure of SELECT- CASE instructions is incorrect.	
	4235	The check condition for the CHK instruction is incorrect.	
	4236	The nesting exceeds 16 loops.	Reduce nesting to 16 or less loops.
	4237	An EXITFOR instruction is executed when there is existence of FOR instruction.	Check the error step and correct the program.
	4238	An EXITDO instruction is executed when there is no existence of DO instruction.	

Error Message Table (cont.)

Error Message	Error Code (SD0) ∗1	Error Description and Cause	Remedy
WDT ERROR	5000	An instruction in a program of initial execution type is infinitely executed in a single scan.	Read the error step and confirm there is no occurrence of an infinite loop.
	5001	An instruction in the program is infinitely executed in a single scan.	Read the error step and confirm there is no occurrence of an infinite loop.
F∗∗∗∗	9000	The program turns ON annunciator.	Check the user condition that turns On the annunciator and make corrective action for that condition.

∗1 Characters in parentheses ( ) indicate the special register number where the information is saved.

(3) Ladder Logic Test Tool (LLT) for FX series CPU Functions

Error Message Table

Error Message	Error Code (D8065, D8066) ∗1	Error Description and Cause	Remedy
WDT ERROR	6105	Occurrence of an infinite loop.	Check the program or contents of the operands in the application instruction.
FILE NOT FOUND	6409	Illegal parameter settings.	Correct the parameter settings and write parameters again.
INVALID CODE ERROR	6503	Data instruction code is corrupted.	Transfer the program from GPPW again.
EXIST SAME LABEL No.	6504	Overlapping label numbers.	Check the program and correct the overlapping label numbers.
STL-MC INST.ERROR	6505	(1) There is no RET instruction. (2) MC and MCR instructions are designated within an STL state.	Check the program and correct the mutual instructions.
FOR NEXT ERROR	6607	Illegal occurrence of FOR to NEXT instructions. FOR to NEXT nesting exceeds the maximum nesting level of 6.	Check the program or contents of the operands in the application instruction.
OPERATION ERROR	6701	No jump destination is specified for CJ or CALL instruction.	Check the program or contents of the operands in the application instruction.
CAN'T EXECUTE (P)	6702	The nestings of CALL instructions exceed the maximum nesting level of 6.	Check the program or contents of the operands in the application instruction.
FOR NEXT ERROR	6704	FOR - NEXT nestings exceed the maximum nesting level of 6.	Check the program or contents of the operands in the application instruction.
OPERATION ERROR	6705	An incompatible device is specified as an operand of an application instruction.	Check the program or contents of the operands in the application instruction.
	6706	A device is specified outside the allowable range of an application instruction operand.	
	6707	A file register which is not defined in the parameter settings is accessed.	
SP. UNIT ERROR	6708	FROM - TO instruction error.	Check the program or contents of the operands in the application instruction.
OPERATION ERROR	6709	(1) Illegal nesting of FOR - NEXT instructions. (2) Illegal nesting of CALL - SRET instructions.	Check the program or contents of the operands in the application instruction.

∗1 Characters in parentheses ( ) indicate the special register number where the information is saved.

Errors not displayed on the LED indicators are stored as operation error codes in the special data register D8067.

Devices related to error displays (see Appendix 1)

M8067 : Operation error generated
M8068 : Operation error latch
D8067 : Operation error code number
D8068 : Latch for step number where operation error was generated
D8069 : Step where M8067 error was generated

(4) Ladder Logic Test Tool (LLT) for Q series CPU (A Mode) Functions

The error codes of the Q series CPU (A mode) are the same as those of the A series CPU. Refer to the error message list of the ladder logic test tool (LLT) for A series CPU functions in Section 8.1(1).

(5) Ladder Logic Test Tool (LLT) for Q series CPU (Q Mode) Functions

Refer to the QnA for the error message list.
Note that the following error message is specific to the Q mode.

SP PARA. ERROR	3301	There is an error in the intelligent function utility settings.	(1) Check and correct the intelligent function unit settings. (2) Check and correct the parameter settings (I/O allocation, Device settings).

APPENDICES

Appendix 1 List of Supported Devices

The ladder logic test tool (LLT) supports the devices for an A series CPU, QnA series CPU, Q series CPU, and FXCPU.
(Non-supported devices are reserved as devices for reading and writing only.)
For the motion controller CPU, refer to the compatible devices of the A series CPU. For the compatible CPU, refer to Section 2.3.
The devices supported by the ladder logic test tool (LLT) are listed in Appendix Table 1.1 to Appendix Table 1.15.

Appendix 1.1 The A series CPU function ladder logic test tool (LLT)

(1) Device list

Appendix Table 1.1 List of Devices Supported by the Ladder Logic Test Tool (LLT)

Device		Device range (points)							
		A0J2H A1FX	A1N A1S A1SJ	A2C A2CJ A2S	A2N(S1)	A3N A1SH A1SJH A2SH	A2A(S1)	A3A	A2U(S1) A2US(S1) A2USH-S1 A3U A4U
Bit device	Input (X) ＊1	X0 to X1FF (512 points)	X0 to XFF (256 points)	X00 to X1FF (512 points)	X00 to X3FF (1024 points)	X0 to X7FF (2048 points)	X00 to X3FF (1024 points)	X00 to X7FF (2048 points)	X00 to X1FFF (8192 points)
	Output (Y) ＊1	Y0 to Y1FF (512 points)	Y0 to YFF (256 points)	Y00 to Y1FF (512 points)	Y00 to Y3FF (1024 points)	Y0 to Y7FF (2048 points)	Y00 to Y3FF (1024 points)	Y00 to Y7FF (2048 points)	Y00 to Y1FFF (8192 points)
	Internal relay (M)	M0 to M2047 (2048 points)				M0 to M8191 (8192 points)			
	Special relay (M)	M9000 to M9255 (256 points)							
	Link relay (B)	B0 to B3FF (1024 points)					B0 to BFFF (4096 points)		B0 to B1FFF (8192 points)
	Annunciator (F)	F0 to F255 (256 points)					F0 to F2047 (2048 points)		
Word device	Timer (T)	T0 to T255 (256 points)					T0 to T2047 (2048 points)		
	Counter (C)	C0 to C255 (256 points)					C0 to C1023 (1024 points)		
	Data register (D)	D0 to D1023 (1024 points)					D0 to D6143 (6144 points)		D0 to D8191 (8192 points)
	Special register (D)	D9000 to D9255 (256 points)							
	Link register (W)	W0 to W3FFF (1024 points)					W0 to WFFF (8192 points)		W0 to W1FFF (8192 points)
	File register (R)	R0 to R8191 (8192 points)							
	Extension file register	Block 1 to 64 (8k points) ＊2							
	Accumulator (A)	A0, A1 (2 points)							
	Index register (Z, V)	Z, V (2 points)					Z, Z1 to Z6, V, V1 to V6 (14 points)		
Nesting (N)		N0 to N7 (8 points)							
Pointer (P)		P0 to P255 (256 points)							
Decimal constant (K)		K-2147483648 to K2147483647							
Hexadecimal constant (H)		H0 to HFFFFFFFF							
Character string constant		"ABC", "123"							

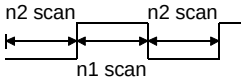
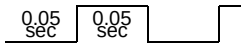
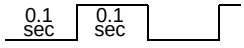
＊1 : Remote I/O is included.
＊2 : In the SW2D5□-GPPW, the data of file register can be written in the block No. 1 through 48 only.

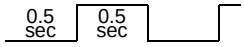
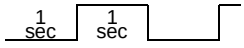
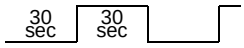
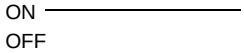
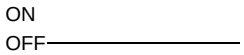
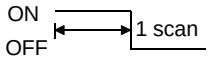
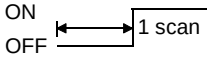
App.

(2) Special Relay List

Appendix Table 1.2 lists the special relays supported by the ladder logic test tool (LLT) for the A series CPU functions. See the A series actual PLC Users Manual for details about the special relays.

Appendix Table 1.2 List of Special Relays Supported by the Ladder Logic Test Tool (LLT)

Number	Name	Description
M9008	Self-diagnostic error	OFF :No error ON :Error
M9009	Annunciator detected	OFF :Not detected ON :Detected
M9010	Operation error flag	OFF :No error ON :Error
M9011	Operation error flag	OFF :No error ON :Error
M9012	Carry flag	OFF :Carry OFF ON :Carry ON
M9020	User timing clock No. 0	
M9021	User timing clock No. 1	
M9022	User timing clock No. 2	
M9023	User timing clock No. 3	
M9024	User timing clock No. 4	
M9028	Clock data read request	OFF :No processing ON :Read request
M9030 ＊1	0.1-second clock	
M9031 ＊1	0.2-second clock	

Number	Name	Description
M9032 ＊1	1-second clock	
M9033 ＊1	2-second clock	
M9034 ＊1	1-minute clock	
M9036	Normally ON	
M9037	Normally OFF	
M9038	ON one scan only after RUN	
M9039	RUN flag (OFF one scan only after RUN)	
M9042	Stop status contact	OFF :Not stop status ON :Stop status
M9051	CHG instruction execution disabled	OFF :Enabled ON :Disabled
M9054	STEP RUN flag	OFF :Not STEP RUN ON :STEP RUN
M9091	Instruction error flag	OFF :No error ON :Error

＊1 : The values obtained are based on the set values of a constant scan.

(3) Special Register List

Appendix Table 1.3 lists the special registers supported by the ladder logic test tool (LLT) for the A series CPU functions. See the A series actual PLC Users Manual for details about the special registers.

Appendix Table 1.3 List of Special Registers Supported by the Ladder Logic Test Tool (LLT)

Number	Name	Description
D9008	Self-diagnostic error	Self-diagnostic error number
D9009	Annunciator detected	F number from external breakdown
D9010	Error step	Step number where operation error occurred
D9011	Error step	Step number where operation error occurred
D9015	CPU operation status	CPU operation status
D9016	Program number	Saves the BIN value of the executing sequence program.
D9017 ∗2	Scan time	Minimum scan time (10 ms units)
D9018 ∗2	Scan time	Scan time (10ms units)
D9019 ∗2	Maximum scan time	Maximum scan time (10ms units)
D9020 ∗3	Constant scan	Constant scan time (user settable in 10 ms units)
D9021 ∗2	Scan time	Scan time (1 ms units)
D9022 ∗1	1-second counter	Number of counts in 1-second intervals
D9025	Clock data	Clock data (year, month)
D9026	Clock data	Clock data (day, hour)
D9027	Clock data	Clock data (minute, second)
D9028	Clock data	Clock data (, day of week)
D9035	Extension file register	Block No. used
D9036	Designates device number of extension file register.	Device number for direct access of each extension file registers device.
D9037		
D9091	Detailed error number	Self-diagnosis detailed error number
D9124	Quantity of annunciators detected	Quantity of annunciators detected
D9125	Number of detected annunciators	Number of detected annunciators
D9126		
D9127		
D9128		
D9129		
D9130		
D9131		
D9132		

∗1 : Value derived from the constant scan set value.

∗2 : Value equal to all constant scan set values. Default value is 100 ms.

∗3 : The set constant time becomes the time for one scan.

Appendix 1.2 The QnA series CPU Function Ladder Logic Test Tool (LLT)

(1) Device list

Appendix Table 1.4 List of Devices Supported by the Ladder Logic Test Tool (LLT)

Device Name		Device Range (Points)	Remarks
Bit device	Input (X)	X0 to X1FFF (8192 points)	Actual inputs are disabled.
	Output (Y)	Y0 to Y1FFF (8192 points)	Actual outputs are disabled.
	Internal relay (M)	M0 to M8191 (8191 points)	—
	Latch relay (L)	L0 to L8191 (8191 points)	—
	Annunciator (F)	F0 to F2047 (2048 points)	—
	Edge relay (V)	V0 to V2047 (2048 points)	—
	Link special relay (SB)	SB0 to SB7FF (2048 points)	—
	Link relay (B)	B0 to B1FFF (8192 points)	
	Special relay (SM)	SM0 to SM2047 (2048 points)	See (b) Special Relay List for details about the special relays supported.
	Function input (FX)	FX0 to FX4 (5 points)	—
	Function output (FY)	FY0 to FY4 (5 points)	—
Word device	Data register (D)	D0 to D12287 (12288 points)	—
	Special register (SD)	SD0 to SD2047 (2048 points)	See (c) Special Register List for details about the special registered supported.
	Link register (W)	W0 to W1FFF (8192 points)	—
	Link special register (SW)	SW0 to SW7FF (2048 points)	—
	Timer (T)	T0 to T2047 (2048 points)	—
	Retentive timer (ST)	(ST0 to ST2047) (0 points)	—
	Counter (C)	C0 to C1023 (1024 points)	—
	Function register (FD)	FD0 to FD4 (5 points)	—
	File register (R)	R0 to R1042431 (1042432 points)	—
	Buffer register (Un\G)	Un\G0 to Un\G16383 (16384 points)	I/O assignments must be set for the parameters.
	Index register (Z)	Z0 to Z15 (16 points)	—
Nesting (N)		N0 to N14 (15 points)	—
Pointer (P)		P0 to P4095 (4096 points)	—
Decimal constant (K)		K-2147483648 to K2147483647	—
Hexadecimal constant (H)		H0 to HFFFFFFFF	—
Real number constant		E±1.17549-38 to E±3.40282+38	—
Character string constant		"ABC", "123"	Maximum 16 characters per instruction.

(2) Special Relay List

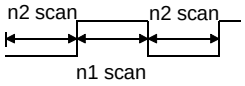
Appendix Table 1.5 lists the special relays supported by the ladder logic test tool (LLT) for the QnA series CPU functions. See the QnA series actual PLC Users Manual for details about the special relays.

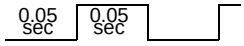
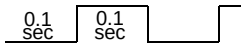
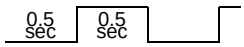
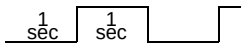
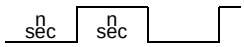
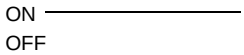
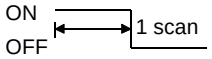
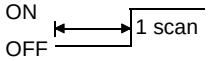
Appendix Table 1.5 List of Special Relays Supported by the Ladder Logic Test Tool (LLT)

Number	Name	Description
SM0	Diagnostic error	OFF :No error ON :Error
SM1	Self-diagnostic error	OFF :No self-diagnostic error ON :Self-diagnostic error
SM5	Error common information	OFF :No error common information ON :Error common information
SM16	Error individual information	OFF :No error individual information ON :Error individual information
SM50	Error reset	OFF → ON :Error reset
SM56	Operation error	OFF :Normal ON :Operation error
SM62	Annunciator detected	OFF :Not detected ON :Detected
SM203	STOP contacts	STOP status
SM205	STEP-RUN contacts	STEP-RUN status
SM213	Clock data read request	OFF :No processing ON :Read request
SM400	Normally ON	ON OFF
SM401	Normally OFF	ON OFF
SM402	ON one scan only after RUN	ON OFF 1 scan
SM403	OFF one scan only after RUN	ON OFF 1 scan
SM404	ON one scan only after RUN	ON OFF 1 scan

Number	Name	Description
SM405	OFF one scan only after RUN	ON OFF 1 scan
SM410 ∗1	0.1-second clock	0.05 sec 0.05 sec
SM411 ∗1	0.2-second clock	0.1 sec 0.1 sec
SM412 ∗1	1-second clock	0.5 sec 0.5 sec
SM413 ∗1	2-second clock	1 sec 1 sec
SM414 ∗1	2n-second clock	n sec n sec
SM420	User timing clock No.0	
SM421	User timing clock No.1	
SM422	User timing clock No.2	
SM423	User timing clock No.3	
SM424	User timing clock No.4	n2 scan n2 scan n1 scan
SM430	User timing clock No.5	
SM431	User timing clock No.6	
SM432	User timing clock No.7	
SM433	User timing clock No.8	
SM434	User timing clock No.9	
SM510	Low-speed program execution flag	OFF :Complete or no execution ON :Executing

Appendix Table 1.5 List of Special Relays Supported by the Ladder Logic Test Tool (LLT) (cont.)

Number	Name	Description
SM640	Use file register	OFF :File registers not used ON :File registers used
SM700	Carry flag	OFF :Carry OFF ON :Carry ON
SM703	Sort order	OFF :Ascending ON :Descending
SM704	Block comparison	OFF :Some do not match ON :All match
SM715	EI flag	OFF :DI ON :EI
SM776	Local device enable/disable setting at CALL time	OFF :Local device disable ON :Local device enable
SM1008	Self-diagnostic error	OFF :No error ON :Error
SM1009	Annunciator detected	OFF :Not detected ON :Detected
SM1010	Operation error	OFF :Normal ON :Operation error
SM1020	User timing clock No.0	
SM1021	User timing clock No.1	
SM1022	User timing clock No.2	
SM1023	User timing clock No.3	
SM1024	User timing clock No.4	

Number	Name	Description
SM1030	0.1-second clock	
SM1031	0.2-second clock	
SM1032	1-second clock	
SM1033	2-second clock	
SM1034	2n-second clock	
SM1036	Normally ON	
SM1037	Normally OFF	
SM1038	ON one scan only after RUN	
SM1039	OFF one scan only after RUN	
SM1042	Stop status contact	OFF :Not stop status ON :Stop status
SM1054	STEP RUN flag	ON :STEP RUN OFF :Not STEP RUN

(3) Special Register List

Appendix Table 1.6 lists the special registers supported by the ladder logic test tool (LLT) for the QnA series CPU functions. See the QnA series actual PLC Users Manual for details about the special registers.

Appendix table 1.6 List of Special Registers Supported by the Ladder Logic Test Tool (LLT)

Number	Name	Description
SD0	Diagnostic error	Diagnostic error number
SD1	Time the diagnostic error occurred	Time the diagnostic error occurred
SD2		
SD3		
SD4	Error information class	Error information class code
SD5	Error common information	Error common information
SD6		
SD7		
SD8		
SD9		
SD10		
SD11		
SD12		
SD13		
SD14		
SD15		
SD16	Error independent information	Error independent information
SD17		
SD18		
SD19		
SD20		
SD21		
SD22		
SD23		
SD24		
SD25		
SD26		
SD50	Error reset	Reset error number
SD62	Annunciator No.	Annunciator No.
SD63	Annunciator quantity	Annunciator quantity
SD64	Annunciator detected number table	Annunciator detected number
SD65		
SD66		
SD67		
SD68		
SD69		

Number	Name	Description
SD70	Annunciator detected number table	Annunciator detected number
SD71		
SD72		
SD73		
SD74		
SD75		
SD76		
SD77		
SD78		
SD79		
SD200	Switch status	CPU switch status
SD203	CPU operating status	CPU operating status ＊3
SD210	Clock data	Clock data (year, month)
SD211	Clock data	Clock data (day, hour)
SD212	Clock data	Clock data (minute, second)
SD213	Clock data	Clock data (, day of week)
SD290	Device assignment	No. of X points assigned
SD291		No. of Y points assigned
SD292		No. of M points assigned
SD293		No. of L points assigned
SD294		No. of B points assigned
SD295		No. of F points assigned
SD296		No. of SB points assigned
SD297		No. of V points assigned
SD298		No. of S points assigned
SD299		No. of T points assigned

＊1 : Value derived from the constant scan setting value and number of scans.
＊2 : Values equal to all constant scan setting values.
＊3 : SD203 supports the CPU operation status only. STOP/PAUSE cause is fixed at 0.

Appendix Table 1.6 List of Special Registers Supported by the Ladder Logic Test Tool (LLT) (cont.)

Number	Name	Description
SD300	Device assignment	No. of ST points assigned
SD301		No. of C points assigned
SD302		No. of D points assigned
SD303		No. of W points assigned
SD304		No. of SW points assigned
SD412 ∗1	1-second counter	Number of counts in 1-second intervals
SD414 ∗1	2n-second clock setting	2n-second clock units
SD420	Scan counter	Number of scans counted
SD430	Low-speed scan counter	Number of scans counted
SD500	Executed program number	Program execution type.
SD510	Low-speed program number	Current low-speed execution file name
SD520 ∗2	Present scan time	Present scan time (1 ms units)
SD521 ∗2		Present scan time (1 μs units)
SD522 ∗2	Initial scan time	Initial scan time (1 ms units)
SD523 ∗2		Initial scan time (1 μs units)
SD524 ∗2	Minimum scan time	Minimum scan time (1 ms units)
SD525 ∗2		Minimum scan time (1 μs units)
SD526 ∗2	Maximum scan time	Maximum scan time (1 ms units)
SD527 ∗2		Maximum scan time (1 μs units)
SD528 ∗2	Current low-speed scan time	Current scan time (1 ms units)
SD529 ∗2		Current scan time (1 μs units)

Number	Name	Description
SD532 ∗2	Minimum low-speed scan time	Minimum low-speed scan time (1 ms units)
SD533 ∗2		Minimum scan time (1 μs units)
SD534 ∗2	Maximum low-speed scan time	Maximum scan time (1 ms units)
SD535 ∗2		Maximum scan time (1 μs units)
SD647	File register capacity	File register capacity
SD648	File register block number	File register block number
SD1008	Self-diagnostic error	Self-diagnostic error number
SD1009	Annunciator No.	Annunciator No.
SD1015	CPU operation status	CPU operation status
SD1017 ∗2	Scan time	Minimum scan time (10 ms units)
SD1018 ∗2	Scan time	Scan time (10 ms units)
SD1019 ∗2	Scan time	Maximum scan time (10 ms units)
SD1021 ∗2	Scan time	Scan time (1 ms units)
SD1022 ∗2	1-second counter	Number of counts of 1-second units
SD1035	Extension file register	Used block number
SD1124	Number of annunciators detected	Number of annunciators detected
SD1125	Number of annunciators detected	Number of annunciators detected
SD1126		
SD1127		
SD1128		
SD1129		
SD1130		
SD1131		
SD1132		

∗1 : Value derived from the constant scan setting value and number of scans.

∗2 : Values equal to all constant scan setting values.

∗3 : SD203 supports the CPU operation status only. STOP/PAUSE cause is fixed at 0.

POINT
Special relays/registers that have contents different from those of Q4ACPU will operate by the contents of special relays/registers of Q4ACPU.

Appendix 1.3 FX series CPU function ladder logic test tool (LLT)

(1) Device list

Appendix Table 1.7 List of Devices Supported by the Ladder Logic Test Tool (LLT) (CPU type: FX_0/FX_{0S})

Device Name			Device Range (Points)	Remarks
Bit device	Input (X)		X000 to X017 (16 points)	Octal number. Actual inputs are disabled.
	Output (Y)		Y000 to Y015 (14 points)	Octal number. Actual outputs are disabled.
	Auxiliary relay (M)	General purpose	M0 to M495 (496 points)	—
		Hold*1	M496 to M511 (16 points)	
		Special	M8000 to M8255 (57 points)	
	State (S)	Initial state	S0 to S9 (10 points)	—
		General purpose	S10 to S63 (54 points)	
Word device	Timer (T)	100 ms	T0 to T31 (32 points)	T32-T55 switched by M8028 drive
		100 ms / 10 ms	T32 to T55 (24 points)	
	Counter (C)	16-bit up	C0 to C13 (14 points)	—
		16-bit up*1	C14 to C15 (2 points)	
	Data register (D) (32-bit for pair use)	16-bit general purpose	D0 to D29 (30 points)	—
		16-bit hold*1	D30 to D31 (2 points)	
		16-bit special	D8000 to D8255 (27 points)	
		16-bit index	V, Z (2 points)	
Nesting (N)		For master control	N0 to N7 (8 points)	—
Pointer (P)		For JMP, CALL branching	P0 to P63 (64 points)	—
Decimal constant (K)		16 bits	-32768 to 32767	—
		32 bits	-2147483648 to 2147483647	—
Hexadecimal constant (H)		16 bits	H0 to HFFFF	—
		32 bits	H0 to HFFFFFFFF	—

*1 Area fixed to back up for interruption: This cannot be changed.

Appendix Table 1.8 List of Devices Supported by the Ladder Logic Test Tool (LLT) (CPU type: FX_{0N})

Device Name			Device Range (Points)	Remarks
Bit device	Input (X)	Total number of points with expansion	X000 to X177 (128 points)	Octal number. Actual inputs are disabled.
	output (Y)	Total number of points with expansion	Y000 to Y177 (128 points)	Octal number. Actual outputs are disabled.
	Auxiliary relay (M)	general purpose	M0 to M383 (384 points)	—
		Hold*1	M384 to M511 (128 points)	
		Special	M8000 to M8255 (67 points)	
	State (S)	Initial state*1	S0 to S9 (10 points)	—
		Hold*1	S10 to S127 (118 points)	
Word device	Timer (T)	100 ms	T0 to T31 (32 points)	T32-T62 switched by M8028 drive
		100 ms / 10 ms	T32 to T62 (31 points)	
		1 ms	T63 (1 point)	—
	Counter (C)	16 bit up	C0 to C15 (16 points)	—
		16bit up*1	C16 to C31 (16 points)	
	Data register (D) (32-bit for pair use)	16-bit general purpose	D0 to D127 (128 points)	—
		16-bit hold*1	D128 to D255 (128 points)	
		16-bit special	D8000 to D8255 (106 points)	
		File*1	D1000 to D2499 (1500 points)	
		16-bit index	V, Z (2 points)	
Nesting (N)		For master control	N0 to N7 (8 points)	—
Pointer (P)		For JMP, CALL branching	P0 to P63 (64 points)	—
Decimal constant (K)		16 bits	-32768 to 32767	—
		32 bits	-2147483648 to 2147483647	—
Hexadecimal constant (H)		16 bits	H0 to HFFFF	—
		32 bits	H0 to HFFFFFFFF	—

*1 Area fixed to back up for interruption: This cannot be changed.

Appendix Table 1.9 List of Devices Supported by the Ladder Logic Test Tool (LLT) (CPU type: FX_1)

Device Name			Device Range (Points)	Remarks
Bit device	Input (X)	Total number of points with expansion	X000 to X177 (128 points)	Octal number. Actual inputs are disabled.
	Output (Y)	Total number of points with expansion	Y000 to Y177 (128 points)	Octal number. Actual outputs are disabled.
	Auxiliary relay (M)	General purpose	M0 to M499 (500 points)	—
		Hold ＊1	M500 to M1023 (524 points)	
		Special	M8000 to M8255 (156 points)	
	State (S)	Initial state ＊1	S0 to S9 (10 points)	—
		General purpose ＊1	S10 to S499 (490 points)	
		Hold ＊2	S500 to S899 (400 points)	
		Annunciator ＊3	S900 to S999 (100 points)	
Word device	Timer (T)	100 ms	T0 to T199 (200 points)	—
		10 ms	T200 to T245 (46 points)	
	Counter (C)	16 bits up ＊1	C0 to C99 (100 points)	—
		16 bits up ＊2	C100 to C125 (36 points)	
	Data register (D) (32-bit for pair use)	16-bit general purpose ＊1	D0 to D99 (100 points)	—
		16-bit hold ＊2	D100 to D127 (28 points)	
		16-bit special	D8000 to D8255 (106 points)	
		16-bit index	V, Z (2 points)	
Nesting (N)		For master control	N0 to N7 (8 points)	—
Pointer (P)		For JMP, CALL branching	P0 to P63 (64 points)	—
Decimal constant (K)		16 bits	-32768 to 32767	—
		32 bits	-2147483648 to 2147483647	—
Hexadecimal constant (H)		16 bits	H0 to HFFFF	—
		32 bits	H0 to HFFFFFFFF	—

＊1 : Area not backed up for interruption. However, this area can be changed to area backed up for interruption by using parameter settings.

＊2 : Area backed up for interruption. This area can be changed to area not backed up for interruption by using parameter settings.

＊3 : Area fixed to back up for interruption: This area cannot be changed.

Appendix Table 1.10 List of Devices Supported by the Ladder Logic Test Tool (LLT) (CPU type: FX_2/FX_{2C})

Device Name			Device Range (Points)	Remarks
Bit device	Input (X)	Total number of points with expansion	X000 to X377 (256 points)	Octal number. Actual inputs are disabled.
	Output (Y)	Total number of points with expansion	Y000 to Y377 (256 points)	Octal number. Actual outputs are disabled.
	Auxiliary relay (M)	General purpose ∗1	M0 to M499 (500 points)	—
		Hold ∗2	M500 to M1023 (524 points)	
		Hold ∗3	M1024 to M1535 (512 points)	
		Special	M8000 to M8255 (156 points)	
	State (S)	Initial state ∗1	S0 to S9 (10 points)	—
		General purpose ∗1	S10 to S499 (490 points)	
		Hold ∗2	S500 to S899 (400 points)	
		Annunciator ∗3	S900 to S999 (100 points)	
Word device	Timer (T)	100 ms	T0 to T199 (200 points)	—
		10 ms	T200 to T245 (46 points)	
		1 ms retentive ∗3	T246 to T249 (4 points)	
		100 ms retentive ∗3	T250 to T255 (6 points)	
	Counter (C)	16-bit up ∗1	C0 to C99 (100 points)	—
		16-bit up ∗2	C100 to C199 (100 points)	
		32-bit bi-directional ∗1	C200 to C219 (20 points)	
		32-bit bi-directional ∗2	C220 to C234 (15 points)	
	Data register (D) (32-bit for pair use)	16-bit general purpose ∗1	D0 to D199 (200 points)	—
		16-bit hold ∗2	D200 to D511 (312 points)	
		16-bit hold ∗3	D512 to D999 (488 points)	
		16-bit special	D8000 to D8255 (106 points)	
		File ∗3	D1000 to D2999 (2000 points)	
		RAM file	D6000 to D7999 (2000 points)	
		16-bit index	V, Z (2 points)	
Nesting (N)		For master control	N0 to N7 (8 points)	—
Pointer (P)		For JMP, CALL branching	P0 to P127 (128 points)	—
Decimal constant (K)		16 bits	-32768 to 32767	—
		32 bits	-2147483648 to 2147483647	—
Hexadecimal constant (H)		16 bits	H0 to HFFFF	—
		32 bit	H0 to HFFFFFFFF	—

∗1 : Area not backed up for interruption. However, this area can be changed to area backed up for interruption by using parameter settings.

∗2 : Area backed up for interruption. This area can be changed to area not backed up for interruption by using parameter settings.

∗3 : Area fixed to back up for interruption: This area cannot be changed.

Appendix Table 1.11 List of Devices Supported by the Ladder Logic Test Tool (LLT) (CPU type: FX_{1S})

Device Name			Device Range (Points)	Remarks
Bit device	Input (X)	Total number of points with expansion	X000 to X017 (16 points)	Octal number. Actual inputs are disabled.
	output (Y)	Total number of points with expansion	Y000 to Y015 (14 points)	Octal number. Actual outputs are disabled.
	Auxiliary relay (M)	general purpose	M0 to M383 (384 points)	—
		Hold＊1	M384 to M511 (128 points)	
		Special	M8000 to M8255 (256 points)	
	State (S)	Initial state＊1	S0 to S9 (10 points)	—
		Hold＊1	S0 to S127 (128 points)	
Word device	Timer (T)	100 ms	T0 to T31 (32 points)	T32-T62 switched by M8028 drive
		100 ms / 10 ms	T32 to T62 (31 points)	
		1 ms retentive＊1	T63 (1 point)	—
	Counter (C)	16 bit up	C0 to C15 (16 points)	—
		16bit up＊1	C16 to C31 (16 points)	
	Data register (D) (32-bit for pair use)	16-bit general purpose	D0 to D127 (128 points)	—
		16-bit hold＊1	D128 to D255 (128 points)	
		16-bit special	D8000 to D8255 (256 points)	
		File＊1	D1000 to D2499 (1500 points)	
		16-bit index	V0 to V7, Z0 to Z7 (16 points)	
Nesting (N)		For master control	N0 to N7 (8 points)	—
Pointer (P)		For JMP, CALL branching	P0 to P63 (64 points)	—
Decimal constant (K)		16 bits	-32768 to 32767	—
		32 bits	-2147483648 to 2147483647	—
Hexadecimal constant (H)		16 bits	H0 to HFFFF	—
		32 bits	H0 to HFFFFFFFF	—

＊1 Area fixed to back up for interruption: This cannot be changed.

Appendix Table 1.12 List of Devices Supported by the Ladder Logic Test Tool (LLT) (CPU type: FX_{1N})

Devices other than high-speed counter are supported:
Refer to handy manual attached to the sequencer for the range of FX_{1N} series devices.

Appendix Table 1.13 List of Devices Supported by the Ladder Logic Test Tool (LLT) (CPU type: FX_{2N}/$FX2_{2NC}$)

Device Name			Device Range (Points)	Remarks
Bit device	Input (X)	Total number of points with expansion	X000 to X377 (256 points)	Octal number. Actual inputs are disabled.
	Output (Y)	Total number of points with expansion	Y000 to Y377 (256 points)	Octal number. Actual outputs are disabled.
	Auxiliary relay (M)	General purpose ∗1	M0 to M499 (500 points)	—
		Hold ∗2	M500 to M1023 (524 points)	
		Hold ∗3	M1024 to M3071 (2048 points)	
		Special	M8000 to M8255 (156 points)	
	State (S)	Initial state ∗1	S0 to S9 (10 points)	—
		General purpose ∗1	S10 to S499 (490 points)	
		Hold ∗2	S500 to S899 (400 points)	
		Annunciator ∗3	S900 to S999 (100 points)	
Word device	Timer (T)	100 ms	T0 to T199 (200 points)	—
		10 ms	T200 to T245 (46 points)	
		1 ms retentive ∗3	T246 to T249 (4 points)	
		100 ms retentive ∗3	T250 to T255 (6 points)	
	Counter (C)	16-bit up ∗1	C0 to C99 (100 points)	—
		16-bit up ∗2	C100 to C199 (100 points)	
		32-bit bi-directional ∗1	C200 to C219 (20 points)	
		32-bit bi-directional ∗2	C220 to C234 (15 points)	
	Data register (D) (32-bit for pair use)	16-bit general purpose ∗1	D0 to D199 (200 points)	—
		16-bit hold ∗2	D200 to D511 (312 points)	
		16-bit hold ∗3	D512 to D7999 (7488 points)	
		16-bit special	D8000 to D8255 (106 points)	
		16-bit index	V0 to V7, Z0 to Z7 (16 points)	
Nesting (N)		For master control	N0 to N7 (8 points)	—
Pointer (P)		For JMP, CALL branching	P0 to P127 (128 points)	—
Decimal constant (K)		16 bits	-32768 to 32767	—
		32 bits	-2147483648 to 2147483647	—
Hexadecimal constant (H)		16 bits	H0 to HFFFF	—
		32 bit	H0 to HFFFFFFFF	—

∗1 : Area not backed up for interruption. However, this area can be changed to area backed up for interruption by using parameter settings.

∗2 : Area backed up for interruption. This area can be changed to area not backed up for interruption by using parameter settings.

∗3 : Area fixed to back up for interruption: This area cannot be changed.

(2) Special Relay List

Appendix Table 1.14 lists the special relays supported by the ladder logic test tool (LLT) for the FX series CPU functions. See the FX series actual PLC Programming Manual for details about the special relays.

Appendix Table 1.14 List of Special Relays Supported by the Ladder Logic Test Tool (LLT)

No.	Name	Description	FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}
M8000	RUN monitor N/O contact	OFF :STOP ON :RUN	○						
M8001	RUN monitor N/C contact	OFF :RUN ON :STOP	○						
M8002	Initial pulse N/O contact	ON one scan after RUN	○						
M8003	Initial pulse N/C contact	OFF one scan after RUN	○						
M8004	Error occurred	ON if any of M8060 to M8067 operates.	○						
M8011	10 ms clock	5 ms 5 ms	○						
M8012	100 ms clock	50 ms 50 ms	○						
M8013	1 s clock	0.5 s 0.5 s	○						
M8014	1 min clock	30 s 30 s	○						
M8018	Internal real-time clock detected	Normally ON	—	—	—	△	○	○	△
M8020	Zero	ON if counting result is 0	○						
M8021	Borrow	ON if counting result is less than maximum minus value.	○						
M8022	Carry	ON if counting result increases a digit.	○						
M8023	Decimal-point operation instruction	ON when floating decimal-point instruction is executed.	—	—	—	○	—	—	—
M8024	Designate BMOV direction	ON :Write OFF :Read	—	—	—	—	—	—	○
M8026	RAMP mode designation	ON :Hold output value OFF :Reset output value	—	—	—	○	—	—	○
M8028	Switch timer instruction	OFF :100 ms base ON :10 ms base	○	○	—	—	○	—	—

○ : This device or function is supported by the actual PLC.

— : This device or function is not supported by the actual PLC.

△ : This device is supported by actual PLCs with a clock function.
For the ladder logic test tool (LLT), always ON regardless whether the actual PLC has a clock function.

Appendix Table 1.14 List of Special Relays Supported by the Ladder Logic Test Tool (LLT) (cont.)

No.	Name	Description	FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}
M8029	Instruction execution complete	OFF :Executing ON :Execution complete	○						
M8031	Non-hold memory all clear instruction	OFF :Hold ON :Clear	○						
M8032	Hold memory all clear instruction	OFF :Hold ON :Clear	○						
M8033	Memory hold stop instruction	OFF :Clear ON :Hold	○						
M8034	Disable all outputs instruction	OFF :Output enabled ON :Output OFF	○						
M8038	RAM file clear instruction	OFF :Hold ON :Clear	—	—	—	○	—	—	—
M8039	Constant scan mode designation	OFF :Normal scan ON :Constant scan mode	○						
M8040	Disable transition instruction	OFF :Transition enabled ON :Transition disabled	○						
M8041	Transition start instruction (for IST command)	OFF :Stop ON :Transition start	○						
M8042	Start pulse instruction (for IST command)	ON :IST command start instruction	○						
M8043	Home position return complete instruction (for IST command)	ON :IST command home position return instruction	○						
M8044	Home position condition (for IST command)	ON :Home position OFF :Home position return not complete	○						
M8045	All output reset disabled (for IST command)	ON :Reset disabled OFF :Reset enabled	○						
M8046	STL state operation	ON if any of S0 to S899 operates.	○						
M8047	STL monitor enable	ON :D8040 to D8047 enabled	○						
M8048	Annunciator operation	ON if any of S900 to S999 operates.	—	—	○	○	—	—	○

○ : This device or function is supported by the actual PLC.

— : This device or function is not supported by the actual PLC.

△ : This device is supported by actual PLCs with a clock function.
For the ladder logic test tool (LLT), always ON regardless whether the actual PLC has a clock function.

Appendix Table 1.14 List of Special Relays Supported by the Ladder Logic Test Tool (LLT) (cont.)

No.	Name	Description	FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}
M8049	Annunciator enable instruction	ON :D8049 enabled OFF : D8049 enabled	—	—	○	○	—	—	○
M8067	Operation error occurred	ON :Operation error OFF :No operation error	○						
M8068	Operation error latch	Holds M8067 status	○						
M8074	RAM file register setting	ON :Use OFF :Do not use	—	—	—	○	—	—	—
M8160	XCH SWAP function setting	ON :8-bit conversion OFF :Normal mode	—	—	—	○	—	—	○
M8161	8-bit processing mode	ASC, ASCI, HEX processing method	—	○	—	○	○	○	○
M8164	Change number of FROM/TO instruction transfer points	Transfer points switch instruction	—	—	—	—	—	—	○
M8168	SMOV HEX data handling functions	Digit shift in 4-bit unit	—	—	—	○	—	—	○
M8200	Counting direction of counter	ON :C200 down OFF :C200 up	—	—	—	○	—	○	○
M8201	Counting direction of counter	ON :C201 down OFF :C201 up	—	—	—	○	—	○	○
M8202	Counting direction of counter	ON :C202 down OFF :C202 up	—	—	—	○	—	○	○
M8203	Counting direction of counter	ON :C203 down OFF : C203 up	—	—	—	○	—	○	○
M8204	Counting direction of counter	ON :C204 down OFF :C204 up	—	—	—	○	—	○	○
M8205	Counting direction of counter	ON :C205 down OFF :C205 up	—	—	—	○	—	○	○
M8206	Counting direction of counter	ON :C206 down OFF :C206 up	—	—	—	○	—	○	○
M8207	Counting direction of counter	ON :C207 down OFF :C207 up	—	—	—	○	—	○	○
M8208	Counting direction of counter	ON :C208 down OFF :C208 up	—	—	—	○	—	○	○
M8209	Counting direction of counter	ON :C209 down OFF :C209 up	—	—	—	○	—	○	○

○ : This device or function is supported by the actual PLC.

— : This device or function is not supported by the actual PLC.

△ : This device is supported by actual PLCs with a clock function.

For the ladder logic test tool (LLT), always ON regardless whether the actual PLC has a clock function.

Appendix Table 1.14 List of Special Relays Supported by the Ladder Logic Test Tool (LLT) (cont.)

No.	Name	Description	FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}
M8210	Counting direction of counter	ON :C210 down OFF :C210 up	—	—	—	○	—	○	○
M8211	Counting direction of counter	ON :C211 down OFF :C211 up	—	—	—	○	—	○	○
M8212	Counting direction of counter	ON :C212 down OFF :C212 up	—	—	—	○	—	○	○
M8213	Counting direction of counter	ON :C213 down OFF :C213 up	—	—	—	○	—	○	○
M8214	Counting direction of counter	ON :C214 down OFF :C214 up	—	—	—	○	—	○	○
M8215	Counting direction of counter	ON :C215 down OFF :C215 up	—	—	—	○	—	○	○
M8216	Counting direction of counter	ON :C216 down OFF :C216 up	—	—	—	○	—	○	○
M8217	Counting direction of counter	ON :C217 down OFF :C217 up	—	—	—	○	—	○	○
M8218	Counting direction of counter	ON :C218 down OFF :C218 up	—	—	—	○	—	○	○
M8219	Counting direction of counter	ON :C219 down OFF :C219 up	—	—	—	○	—	○	○
M8220	Counting direction of counter	ON :C220 down OFF :C220 up	—	—	—	○	—	○	○
M8221	Counting direction of counter	ON :C221 down OFF :C221 up	—	—	—	○	—	○	○
M8222	Counting direction of counter	ON :C222 down OFF :C222 up	—	—	—	○	—	○	○
M8223	Counting direction of counter	ON :C223 down OFF :C223 up	—	—	—	○	—	○	○
M8224	Counting direction of counter	ON :C224 down OFF :C224 up	—	—	—	○	—	○	○
M8225	Counting direction of counter	ON :C225 down OFF :C225 up	—	—	—	○	—	○	○
M8226	Counting direction of counter	ON :C226 down OFF :C226 up	—	—	—	○	—	○	○
M8227	Counting direction of counter	ON :C227 down OFF :C227 up	—	—	—	○	—	○	○

○ : This device or function is supported by the actual PLC.

— : This device or function is not supported by the actual PLC.

△ : This device is supported by actual PLCs with a clock function.

For the ladder logic test tool (LLT), always ON regardless whether the actual PLC has a clock function.

Appendix Table 1.14 List of Special Relays Supported by the Ladder Logic Test Tool (LLT) (cont.)

No.	Name	Description	FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}
M8228	Counting direction of counter	ON :C228 down OFF :C228 up	—	—	—	○	—	○	○
M8229	Counting direction of counter	ON :C229 down OFF :C229 up	—	—	—	○	—	○	○
M8230	Counting direction of counter	ON :C230 down OFF :C230 up	—	—	—	○	—	○	○
M8231	Counting direction of counter	ON :C231 down OFF :C231 up	—	—	—	○	—	○	○
M8232	Counting direction of counter	ON :C232 down OFF :C232 up	—	—	—	○	—	○	○
M8233	Counting direction of counter	ON :C233 down OFF :C233 up	—	—	—	○	—	○	○
M8234	Counting direction of counter	ON :C234 down OFF :C234 up	—	—	—	○	—	○	○

○ :This device or function is supported by the actual PLC.

— :This device or function is not supported by the actual PLC.

△ :This device is supported by actual PLCs with a clock function.

For the ladder logic test tool (LLT), always ON regardless whether the actual PLC has a clock function.

(3) Special Register List

Appendix Table 1.15 lists the special registers supported by the ladder logic test tool (LLT) for the FX series CPU functions. See the FX series actual PLC Programming Manual for details about the special registers.

Appendix Table 1.15 List of Special Registers Supported by the Ladder Logic Test Tool (LLT)

No.	Name	Description	FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}
D8000	Watchdog timer	200 ms ∗1	○						
D8001	PLC type and system version	∗2	○						
D8002	Memory capacity	Maximum value for model	○						
D8004	Error M number	M8060 to M8068	○						
D8006	Low battery voltage detection level	30 (0.1 V units)	—	—	○	○	—	—	○
D8010	Scan present value	0.1 ms units ∗3	○						
D8011	Minimum scan time	0.1 ms units ∗3	○						
D8012	Maximum scan time	0.1 ms units ∗3	○						
D8013	Seconds	Operates as 1-second clock	—	—	—	△	○	○	△
D8014	Minutes	Time data	—	—	—	△	○	○	△
D8015	Hours	Time data	—	—	—	△	○	○	△
D8016	Day	Time data	—	—	—	△	○	○	△
D8017	Month	Time data	—	—	—	△	○	○	△
D8018	Year	Time data	—	—	—	△	○	○	△
D8019	Day of week	Time data	—	—	—	△	○	○	△
D8028	Z register contents	Z register contents	○						
D8029	V register contents	V register contents	○						
D8030	Analog volume 1	∗4	—	○	—	—	○	○	—
D8031	Analog volume 2	∗4	—	○	—	—	○	○	—
D8039	Constant scan time	Initial value: 100 ms (1 ms units) ∗5	○						

○ : This device or function is supported by the actual PLC.
— : This device or function is not supported by the actual PLC.
△ : This device is supported by actual PLCs with a clock function.
For the ladder logic test tool (LLT), always ON regardless whether the actual PLC has a clock function.
∗1 : Initial value: 200 ms for all models. Can be changed but no watchdog timer check is conducted.
∗2 : FX_0, FX_{0S} 20000
FX_{0N} 20000
FX_1 21000
FX_2, FX_{2C} 20000
FX_{1S} 22000
FX_{1N} 26000
FX_{2N}, FX_{2NC} 24000
∗3 : Values equal to all constant scan setting values. Default value is 100 ms.
∗4 : Operates as a general data register. Test by writing values from 0 to 255 using the GPPW device test functions.
∗5 : The set constant time becomes the time for one scan.

Appendix Table 1.15 List of Special Registers Supported by the Ladder Logic Test Tool (LLT) (cont.)

No.	Name	Description	FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}
D8040	ON state number 1	STL monitor contents				○			
D8041	ON state number 2	STL monitor contents				○			
D8042	ON state number 3	STL monitor contents				○			
D8043	ON state number 4	STL monitor contents				○			
D8044	ON state number 5	STL monitor contents				○			
D8045	ON state number 6	STL monitor contents				○			
D8046	ON state number 7	STL monitor contents				○			
D8047	ON state number 8	STL monitor contents				○			
D8049	ON state minimum number	STL monitor contents				○			
D8067	Operation error code number	Error code number				○			
D8068	Operation error occurred step number latch	Saves step number where error occurred				○			
D8069	M8067 error occurred step number	Step number where error occurred				○			
D8102	Memory capacity	Maximum value for model	—	—	—	—	○	○	○
D8164	Designate number of FROM/TO instruction transfer points	Write transfer points	—	—	—	—	—	—	○
D8182	Z1 register contents	Z1 register contents	—	—	—	—	○	○	○
D8183	V1 register contents	V1 register contents	—	—	—	—	○	○	○
D8184	Z2 register contents	Z2 register contents	—	—	—	—	○	○	○
D8185	V2 register contents	V2 register contents	—	—	—	—	○	○	○
D8186	Z3 register contents	Z3 register contents	—	—	—	—	○	○	○
D8187	V3 register contents	V3 register contents	—	—	—	—	○	○	○
D8188	Z4 register contents	Z4 register contents	—	—	—	—	○	○	○
D8189	V4 register contents	V4 register contents	—	—	—	—	○	○	○
D8190	Z5 register contents	Z5 register contents	—	—	—	—	○	○	○
D8191	V5 register contents	V5 register contents	—	—	—	—	○	○	○
D8192	Z6 register contents	Z6 register contents	—	—	—	—	○	○	○
D8193	V6 register contents	V6 register contents	—	—	—	—	○	○	○
D8194	Z7 register contents	Z7 register contents	—	—	—	—	○	○	○
D8195	V7 register contents	V7 register contents	—	—	—	—	○	○	○

○ : This device or function is supported by the actual PLC.

— : This device or function is not supported by the actual PLC.

△ : This device is supported by actual PLCs with a clock function.
For the ladder logic test tool (LLT), always ON regardless whether the actual PLC has a clock function.

∗1 : Initial value: 200 ms for all models. Can be changed but no watchdog timer check is conducted.
∗2 : FX_0, FX_{0S} 20000
FX_{0N} 20000
FX_1 21000
FX_2, FX_{2C} 20000
FX_{1S} 22000
FX_{1N} 26000
FX_{2N}, FX_{2NC} 24000
∗3 : Values equal to all constant scan setting values. Default value is 100 ms.
∗4 : Operates as a general data register. Test by writing values from 0 to 255 using the GPPW device test functions.
∗5 : The set constant time becomes the time for one scan.

Appendix 1.4 Ladder logic test tool (LLT) for Q series CPU (A mode) functions

(1) Device list

Since the devices of the Q series CPU (A mode) are the same as those of the A4UCPU, refer to A4U in the List of Devices Supported by the Ladder Logic Test Tool (LLT) in Appendix Table 1.1.

(2) Special relay list

Since the special relays of the Q series CPU (A mode) are the same as those of the A series CPU, refer to the List of Special Relays Supported by the Ladder Logic Test Tool (LLT) in Appendix Table 1.2.

(3) Special register list

Since the special registers of the Q series CPU (A mode) are the same as those of the A series CPU, refer to the List of Special Registers Supported by the Ladder Logic Test Tool (LLT) in Appendix Table 1.3.

Appendix 1.5 Ladder logic test tool (LLT) for Q series CPU (Q mode) functions

(1) Device list

Appendix Table 1.16 List of Devices Supported by the Ladder Logic Test Tool (LLT)

Device		Device Range (Points)	Setting Range	Remarks
Bit device	Input	X0 to X1FFF (8192 Points)	Fixed	Actual inputs are disabled.
	Output	Y0 to Y1FFF (8192 Points)	Fixed	Actual outputs are disabled.
	Internal relay	M0 to M8191 (8192 Points)	Changeable	—
	Latch relay	L0 to L8191 (8192 Points)	Changeable	—
	Annunciator	F0 to F2047 (2048 Points)	Changeable	—
	Edge relay	V0 to V2047 (2048 Points)	Changeable	—
	Step relay	S0 to S511/Block	Changeable	Incompatible with SFC.
	Link special relay	SB0 to SB7FF (2048 Points)	Changeable	—
	Link relay	B0 to B1FFF (8192 Points)	Changeable	—
Word device	Timer	T0 to T2047 (2048 Points)	Changeable	No operation in real time. High-speed timer can be set in 0.1ms increments (in parameter). 1ms increments in conventional LLT.
	Retentive timer	None (ST0 to-)	Changeable	No operation in real time. High-speed retentive timer can be set in 0.1ms increments (in parameter). 1ms increments in conventional LLT.
	Counter	C0 to C1023 (1024 Points)	Changeable	—
	Data register	D0 to D12287 (12288 Points)	Changeable	—
	Link register	W0 to W1FFF (8192 Points)	Changeable	—
	Link special register	SW0 to SW7FF (2048 Points)	Changeable	—

Appendix Table 1.16 List of Devices Supported by the Ladder Logic Test Tool (LLT) (cont.)

Name		Device Range (Points)	Setting Range	Remarks
Bit	Function input	FX0 to FXF (16 points)	Fixed	—
	Function output	FY0 to FYF (16 points)	Fixed	—
	Special relay	SM0 to SM2047 (2048 points)	Fixed	Compatible with some functions.
Word	Function register	FD0 to FD4 (5 points)	Fixed	—
	Special register	SD0 to SD2047 (2048 points)	Fixed	Compatible with some functions.
Bit	Link input	Jn\X0 to Jn\X1FFF (8192 points)	Fixed	Incompatible with link functions.
	Link output	Jn\Y0 to Jn\Y1FFF (8192 points)	Fixed	Incompatible with link functions.
	Link relay	Jn\B0 to JnB\3FFF (16384 points)	Fixed	Incompatible with link functions.
	Link special relay	Jn\SB0 to Jn\SB1FF (512 points)	Fixed	Incompatible with link functions.
Word	Link register	Jn\W0 to Jn\W3FFF (16384 points)	Fixed	Incompatible with link functions.
	Link special register	JnS\W0 to JnS\W1FF (512 points)	Fixed	Incompatible with link functions.
Word	Buffer register	Un\G0 to Un\G65535 (65536 points)	Fixed	16384 points in conventional LLT.
	Index register	Z0 to Z15 (16 points)	Fixed	—
	File register	R0 to R18383 (18384 points) ZR0 to ZR1042432 (1042433 points)	Fixed	—
—	Nesting	N0 to N14 (15 points)	Fixed	—
—	Pointer	P0 to P4095 (4096 points)	Fixed	—
—	Interrupt pointer	I0 to I47 (48 points)	Fixed	Incompatible with interrupt functions.
Bit	SFC block	BL0 to BL319 (320 points)	Fixed	Incompatible with SFC.
	SFC transition device	TR0 to TR511 (512 points)	Fixed	Incompatible with SFC.
—	Network No.	J1 to J255 (256 points)	Fixed	Incompatible with link functions.
—	I/O No.	U0 to UFF (256 points)	Fixed	Incompatible with link/special modules.
—	Decimal constant	K-2147483648 to K2147483647	Fixed	—
—	Hexadecimal constant	H0 to HFFFFFFFF	Fixed	—
—	Real number constant	E±1.17549-38 to E±3.40282+38	Fixed	—
—	Character string constant	"ABC", "123"etc.	Fixed	Up to 16 characters per instruction
Bit	CPU shared memory	Un\GO to Un\GOFFF (4096 points)	Fixed	Valid only multiple CPU setting time

(2) Special Relay List

Appendix Table 1.17 List of Special Relays Supported by the Ladder Logic Test (LLT)

Device Name	Remarks	Device Name	Remarks	Device Name	Remarks	Device Name	Remarks
SM0	Diagnostic error	SM410 ＊1	0.1 sec. clock	SM620	Card B use flag normally ON	SM1022	User clock No. 2
SM1	Self-diagnostic error	SM411 ＊1	0.2 sec. clock	SM621	Card B protect flag normally OFF	SM1023	User clock No. 3
SM5	Error common information	SM412 ＊1	1 sec. clock	SM622	Drive 3 flag normally ON	SM1024	User clock No. 4
SM16	Error individual information	SM413 ＊1	2 sec. clock	SM623	Drive 4 flag normally ON	SM1030	0.1 sec. clock
SM50	Error reset	SM414 ＊1	2n sec. clock	SM640	File register use	SM1031	0.2 sec. clock
SM56	Operation error	SM415 ＊1	2n millsec. clock	SM700	Carry flag	SM1032	1 sec. clock
SM62	Annunciator detection	SM420	User clock No. 0	SM703	Sort order	SM1033	2 sec. clock
SM203	STOP contact	SM421	User clock No. 1	SM704	Block comparison	SM1034	2n sec. clock
SM205	STEP-RUN contact	SM422	User clock No. 2	SM715	EI flag	SM1036	Normally ON
SM213	Clock data read request	SM423	User clock No. 3	SM722	BIN/DBIN error processing switch-over	SM1037	Normally OFF
SM400	Normally ON	SM424	User clock No. 4	SM776	Local device enable/disable setting at CALL time OFF :Local device disable ON :Local device enable	SM1038	ON only 1 scan after RUN
SM401	Normally OFF	SM430	User clock No. 5	SM777	Local device enable/disable setting in cyclic execution program OFF :Local device disable ON :Local device enable	SM1039	OFF only 1 scan after RUN
SM402	ON only 1 scan after RUN	SM431	User clock No. 6	SM1008	Self-diagnostic error	SM1042	STOP contact
SM403	OFF only 1 scan after RUN	SM432	User clock No. 7	SM1009	Annunciator detection	SM1054	STEP-RUN contact
SM404	ON only 1 scan after RUN	SM433	User clock No. 8	SM1010	Operation error	—	—
SM405	OFF only 1 scan after RUN	SM434	User clock No. 9	SM1020	User clock No. 0	—	—
SM408 ＊1	0.01 sec. clock	SM510	Low-speed program execution	SM1021	User clock No. 1	—	—

＊1 : Derived from the constant scan setting and scan count. The time set as a constant scan is the time of 1 scan. 1 scan time = constant scan time.

(3) Special Device List

Appendix Table 1.18 List of Special Devices Supported by the Ladder Logic Test (LLT)

Device Name	Remarks	Device Name	Remarks	Device Name	Remarks	Device Name	Remarks
SD0	Diagnostic error	SD64	Detection table	SD227	Display device data	SD527 *1	Max. scan time
SD1	Error occurrence time	SD65	Detection table	SD290	Device assignment	SD528 *1	Current scan time
SD2	Error occurrence time	SD66	Detection table	SD291	Device assignment	SD529 *1	Current scan time
SD3	Error occurrence time	SD67	Detection table	SD292	Device assignment	SD532 *1	Min. scan time
SD4	Error information segment	SD68	Detection table	SD293	Device assignment	SD533 *1	Min. scan time
SD5	Error common information	SD69	Detection table	SD294	Device assignment	SD534 *1	Max. scan time
SD6	Error common information	SD70	Detection table	SD295	Device assignment	SD535 *1	Max. scan time
SD7	Error common information	SD71	Detection table	SD296	Device assignment	SD647	File register capacity
SD8	Error common information	SD72	Detection table	SD297	Device assignment	SD648	R block No.
SD9	Error common information	SD73	Detection table	SD298	Device assignment	SD1008	Diagnostic error
SD10	Error common information	SD74	Detection table	SD299	Device assignment	SD1009	Annunciator detection
SD11	Error common information	SD75	Detection table	SD300	Device assignment	SD1015	CPU operation status
SD12	Error common information	SD76	Detection table	SD301	Device assignment	SD1017 *1	Min. scan time
SD13	Error common information	SD77	Detection table	SD302	Device assignment	SD1018 *1	Current scan time
SD14	Annunciator number	SD78	Detection table	SD303	Device assignment	SD1019 *1	Max. scan time
SD15	Error common information	SD79	Detection table	SD304	Device assignment	SD1021 *1	Current scan time
SD16	Error individual information	SD200	CPU switch status	SD412 *2	1 sec. counter	SD1022 *2	1 sec. counter
SD17	Error individual information	SD201	LED status	SD414 *2	2n sec. clock setting	SD1035	R block No.
SD18	Error individual information	SD203	CPU operation status	SD415 *2	2n millsec. clock setting	SD1124	Number of annunciators
SD19	Error individual information	SD210	Clock year, month	SD420	Scan counter	SD1125	Annunciator number
SD20	Error individual information	SD211	Clock day, hour	SD430	Low-speed scan counter	SD1126	Annunciator number
SD21	Error individual information	SD212	Clock minute, second	SD500	Execution program No.	SD1127	Annunciator number
SD22	Error individual information	SD213	Year, day of the week	SD510	Low-speed program No.	SD1128	Annunciator number
SD23	Error individual information	SD220	Display device data	SD520 *1	Current scan time	SD1129	Annunciator number
SD24	Error individual information	SD221	Display device data	SD521 *1	Current scan time	SD1130	Annunciator number

Appendix Table 1.18 List of Special Devices Supported by the Ladder Logic Test (LLT) (cont.)

Device Name	Remarks	Device Name	Remarks	Device Name	Remarks	Device Name	Remarks
SD25	Error individual information	SD222	Display device data	SD522 ＊1	Initial scan time	SD1131	Annunciator number
SD26	Error individual information	SD223	Display device data	SD523 ＊1	Initial scan time	SD1132	Annunciator number
SD60	Error reset	SD224	Display device data	SD524 ＊1	Min. scan time	—	—
SD62	Annunciator number	SD225	Display device data	SD525 ＊1	Min. scan time	—	—
SD63	Number of annunciators	SD226	Display device data	SD526 ＊1	Max. scan time	—	—

＊1: Same as all constant scan settings. Default is 100msec.

＊2: Derived from the constant scan setting and scan count. The time set as a constant scan is the time of 1 scan. 1 scan time = constant scan time.

Appendix 2 List of Supported Instruction

The ladder logic test tool (LLT) supports the A series CPU/QnA series CPU/Q series CPU instructions.
However, some instructions are subject to restrictions and some are not supported.
Unsupported instructions are not processed (NOP).
See Appendices Table 2.1 to 2.4 for the instructions supported by the ladder logic test tool (LLT).

POINT
Unsupported instructions are not processed (NOP), and the "Unsupported information indicator lamp" lights up on the initial window of the ladder logistic test tool (LLT) functions. (Refer to the display contents in Section 3.3 "Description of the Initial Window Display".

Appendix 2.1 A series CPU function ladder logic test tool (LLT)

Appendix Table 2.1 List of Supported Instructions (A Series CPU Function)

(1) Sequence Instructions

Class	Instruction Symbol	Restriction
Contact instructions	LD, LDI, AND, ANI, OR, ORI	—
Coupling instructions	ANB, ORB, MPS, MRD, MPP	—
Output instructions	OUT, OUT T, OUT C, SET, RST, PLS, PLF	—
Shift instruction	SFT(P)	—
Master control instructions	MC, MCR	—
End instructions	FEND, END	—
Other instructions	STOP, NOP	—

(2) Basic Instructions

Class	Instruction Symbol	Restriction
Comparative operation instructions	=, <>, >, <=, <, >=, D=, D<>, D>, D<=, D<, D>=	—
Arithmetic operation instructions	+(P), -(P), D+(P), D-(P), ＊(P), /(P), D＊(P), D/(P), B+(P), B-(P), DB+(P), DB-(P), B＊(P), B/(P), DB＊(P), DB/(P), INC(P), DEC(P), DINC(P), DDEC(P)	—
BCD ↔ BIN conversion instructions	BCD(P), DBCD(P), BIN(P), DBIN(P)	—
Data transfer instruction	MOV(P), DMOV(P), CML(P), DCML(P), BMOV(P), FMOV(P), XCH(P), DXCH(P)	—
Program branching instructions	CJ, SCJ, JMP, CALL(P), RET	—
Program switching instructions	CHG	—

Appendix Table 2.1 List of Supported Instructions (A Series CPU Function) (cont.)

(3) Applied Instructions

Class	Instruction Symbol	Restriction
Logical arithmetic instructions	WAND(P), DAND(P), WOR(P), DOR(P), WXOR(P), DXOR(P), WXNR(P), DXNR(P), NEG(P)	—
Rotation instructions	ROR(P), RCR(P), ROL(P), RCL(P), DROR(P), DRCR(P), DROL(P), DRCL(P)	—
Shift instruction	SFR(P), SFL(P), BSFR(P), BSFL(P), DSFR(P), DSFL(P),	—
Data processing instructions	SER(P), SUM(P), DSUM(P), DECO(P), ENCO(P), SEG, BSET(P), BRST(P), DIS(P), UNI(P), ASC	SEG conducts 7-segment decoding regardless of M9052 ON/OFF status.
FIFO instruction	FIFW(P), FIFR(P)	—
Buffer memory access instructions	FROM(P), DFRO(P), TO(P), DTO(P)	—
FOR to NEXT instructions	FOR, NEXT	—
Display instructions	LED, LEDA, LEDB, LEDR	—
Other instructions	STC, CLC, DUTY	STC converted to SET M9012 CLC converted to RST M9012

(4) Dedicated Instructions

Class	Instruction Symbol	Restriction
Direct output instruction	DOUT, DSET(P), DRST(P)	—
Structural program instructions	BREAK(P), FCALL(P)	—
Data operation instructions	DSER(P), SWAP(P), DIS(P), UNI(P), TEST(P), DTEST(P)	—
I/O operation instruction	FF	—
Real number processing instructions	BSQR(P), BDSQR(P), BSIN(P), BCOS(P), BTAN(P), BASIN(P), BACOS(P), BATAN(P), INT(P), DINT(P), FLOAT(P), DFLOAT(P), ADD(P), SUB(P), MUL(P), DIV(P), RAD(P), DEG(P), SIN(P), COS(P), TAN(P), ASIN(P), ACOS(P), ATAN(P), SQR(P), EXP(P), LOG(P)	—
Character string processing instructions	BINDA(P), DBINDA(P), BINHA(P), DBINHA(P), BCDDA(P), DBCDDA(P), DABIN(P), DDABIN(P), HABIN(P), DHABIN(P), DABCD(P), DDABCD(P), LEN(P), STR(P), DSTR(P), VAL(P), DVAL(P), ASC(P), HEX(P), SMOV(P), SADD(P), SCMP(P), WTOB(P), BTOW(P)	—
Data control instructions	LIMIT(P), DLIMIT(P), BAND(P), DBAND(P), ZONE(P), DZONE(P)	—
Clock instructions	DATERD(P)	—
Extension file register instructions	RSET(P), BMOVR(P), BXCHR(P), ZRRD(P), ZRWR(P), ZRRDB(P), ZRWRB(P)	—
Program switching instructions	ZCHG	—

Appendix 2.2 QnA series function ladder logic test tool (LLT)

Appendix Table 2.2 List of Supported Instructions (QnA series CPU functions)

(1) Sequence Instructions

Class	Instruction Symbol	Restriction
Contact instructions	LD, LDI, AND, ANI, OR, ORI, LDP, LDF, ANDP, ANDF, ORP, ORF	—
Coupling instructions	ANB, ORB, MPS, MRD, MPP, INV, MEP, MEF, EGP, EGF	—
Output instructions	OUT, OUT T, OUT C, OUTH T, SET, RST, PLS, PLF, FF	—
Shift instructions	SFT(P)	—
Master control instructions	MC, MCR	—
End instructions	FEND, END	—
Other instructions	STOP, NOP, NOPLF, PAGE	—

(2) Basic Instructions

Class	Instruction Symbol	Restriction
Comparative operation instructions	=, <>, >, <=, <, >=, D=, D<>, D>, D<=, D<, D>=, E=, E<>, E>, E<=, E<, E>=, $=, $<>, $>, $<=, $<, $>=, BKCMP□(P)	—
Arithmetic operation instructions	+(P), -(P), D+(P), D-(P), ＊(P), /(P), D＊(P), D/(P), B+(P), B-(P), DB+(P), DB-(P), B＊(P), B/(P), DB＊(P), DB/(P), E+(P), E-(P), E＊(P), E/(P), BK+(P), BK-(P), $+(P), INC(P), DEC(P), DINC(P), DDEC(P)	—
Data conversion instructions	BCD(P), DBCD(P), BIN(P), DBIN(P), INT(P), DINT(P), FLT(P), DFLT(P), DBL(P), WORD(P), GRY(P), DGRY(P), GBIN(P), DGBIN(P), NEG(P), DNEG(P), ENEG(P), BKBCD(P), BKBIN(P)	—
Data transfer instructions	MOV(P), DMOV(P), EMOV(P), $MOV(P), CML(P), DCML(P), BMOV(P), FMOV(P), XCH(P), DXCH(P), BXCH(P), SWAP(P)	—
Program branching instructions	CJ, SCJ, JMP, GOEND	—
Other convenient instructions	TTMR, STMR, RAMP, MTR	—

Appendix Table 2.2 List of supported instructions (QnA series CPU functions) (cont.)

(3) Applied Instructions

Class	Instruction Symbol	Restriction
Logical arithmetic instructions	WAND(P), DAND(P), BKAND(P), WOR(P), DOR(P), BKOR(P), WXOR(P), DXOR(P), BKXOR(P), WXNR(P), DXNR(P), BKNXR(P)	—
Rotation instructions	ROR(P), RCR(P), ROL(P), RCL(P), DROR(P), DRCR(P), DROL(P), DRCL(P)	—
Shift instructions	SFR(P), SFL(P), BSFR(P), BSFL(P), DSFR(P), DSFL(P),	—
Bit processing instructions	BSET(P), BRST(P), TEST(P), DTEST(P), BKRST(P)	—
Data processing instructions	SER(P), DSER(P), SUM(P), DSUM(P), DECO(P), ENCO(P), SEG(P), DIS(P), UNI(P), NDIS(P), NUNI(P), WTOB(P) BTOW(P), MAX(P), MIN(P), DMAX(P), DMIN(P), SORT(P), DSORT(P), WSUM(P), DWSUM(P)	SORT(P), DSORT(P) are executed one scan.
Structural instructions	FOR, NEXT, BREAK(P), CALL(P), RET, FCALL(P), ECALL(P), EFCALL(P)	—
Data table operation instruction	FIFW(P), FIFR(P), FPOP(P), FINS(P), FDEL(P)	—
Buffer memory access instructions	FROM(P), DFRO(P), TO(P), DTO(P)	—
Character string processing instructions	BINDA(P), DBINDA(P), BINHA(P), DBINHA(P), BCDDA(P), DBCDDA(P), DABIN(P), DDABIN(P), HABIN(P), DHABIN(P), DABCD(P), DDABCD(P) LEN(P), STR(P), DSTR(P), VAL(P), DVAL(P), ESTR(P), EVAL(P), ASC(P), HEX(P), RIGHT(P), LEFT(P), MIDR(P), MIDW(P), INSTR(P), EMOD(P), EREXP(P)	—
Special function instructions	SIN(P), COS(P), TAN(P), ASIN(P), ACOS(P), ATAN(P), RAD(P), DEG(P), SQR(P), EXP(P), LOG(P), BSQR(P), BDSQR(P), BSIN(P), BCOS(P), BTAN(P), BASIN(P), BACOS(P), BATAN(P)	—
Data control instructions	LIMIT(P), DLIMIT(P), BAND(P), DBAND(P), ZONE(P), DZONE(P), RSET(P), QDRSET(P)	—
Clock instructions	DATERD(P), DATE+(P), DATE-(P), SECOND(P), HOUR(P)	DATERD(P) reads the computer clock data.
Program control instructions	PSTOP(P), POFF(P), PSCAN(P), PLOW(P)	—
Display instructions	LED, LEDR	—
Other instructions	DUTY, ZRRDB(P), ZRWRB(P), ADRSET(P)	—

Appendix 2.3 FX series function ladder logic test tool (LLT)

Appendix Table 2.3 List of Supported Instructions (FX series CPU functions)

(1) Sequence Instructions

Class	Instruction Symbol	Restriction
Contact instructions	LD, LDI, LDP, LDF, AND, ANI, ANDP, ANDF, OR, ORI, ORP, ORF	∗1
Coupling instructions	ANB, ORB, MPS, MRD, MPP, INV	∗1
Output instructions	OUT, SET, RST, PLS, PLF	—
Master control instructions	MC, MCR	—
Step ladder instructions	STL, RET	—
Other instructions	END, NOP	—

∗1: The LDP, LDF, ANDP, ANDF, ORP, ORF, and INV instructions are only compatible with FX_{1S}, FX_{1N}, FX_{2N} and FX_{2NC} PLC.

(2) Applied Instructions

Class	FNC No.	Instruction Symbol	32-bit Instruction	Pulses Execution Instruction	Applicable PLCs							Compatibility with Ladder logic test tool (LLT)
					FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}	
Program flowchart	00	CJ	—	△	○	○	○	○	○	○	○	●
	01	CALL	—	YES	—	—	○	○	○	○	○	●
	02	SRET	—	—	—	—	○	○	○	○	○	●
	03	IRET	—	—	○	○	○	○	○	○	○	×
	04	EI	—	—	○	○	○	○	○	○	○	×
	05	DI	—	—	○	○	○	○	○	○	○	×
	06	FEND	—	—	○	○	○	○	○	○	○	●
	07	WDT	—	△	○	○	○	○	○	○	○	×
	08	FOR	—	—	○	○	○	○	○	○	○	●
	09	NEXT	—	—	○	○	○	○	○	○	○	●
Transition/Comparison	10	CMP	YES	△	○	○	○	○	○	○	○	●
	11	ZCP	YES	△	○	○	○	○	○	○	○	●
	12	MOV	YES	△	○	○	○	○	○	○	○	●
	13	SMOV	—	YES	—	—	—	○	—	—	○	●
	14	CML	YES	YES	—	—	—	○	—	—	○	●
	15	BMOV	—	△	—	○	—	○	○	○	○	●
	16	FMOV	YES	YES	—	—	—	○	—	—	○	●
	17	XCH	YES	YES	—	—	—	○	—	—	○	●
	18	BCD	YES	△	○	○	○	○	○	○	○	●
	19	BIN	YES	△	○	○	○	○	○	○	○	●

Appendix Table 2.3 List of Supported Instructions (FX series CPU functions) (cont.)

Class	FNC No.	Instruc-tion symbol	32-bit Instruction	Pulses Execution Instruction	Applicable PLCs							Compatibility with Ladder logic test tool (LLT)
					FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}	
Arithmetic/logical operations	20	ADD	YES	△	○	○	○	○	○	○	○	●
	21	SUB	YES	△	○	○	○	○	○	○	○	●
	22	MUL	YES	△	○	○	○	○	○	○	○	●
	23	DIV	YES	△	○	○	○	○	○	○	○	●
	24	INC	YES	△	○	○	○	○	○	○	○	●
	25	DEC	YES	△	○	○	○	○	○	○	○	●
	26	WAND	YES	△	○	○	○	○	○	○	○	●
	27	WOR	YES	△	○	○	○	○	○	○	○	●
	28	WXOR	YES	△	○	○	○	○	○	○	○	●
	29	NEG	YES	YES	–	–	–	○	–	–	○	●
Rotation shift	30	ROR	YES	YES	–	–	–	○	–	–	○	●
	31	ROL	YES	YES	–	–	–	○	–	–	○	●
	32	RCR	YES	YES	–	–	–	○	–	–	○	●
	33	RCL	YES	YES	–	–	–	○	–	–	○	●
	34	SFTR	–	△	○	○	○	○	○	○	○	●
	35	SFTL	–	△	○	○	○	○	○	○	○	●
	36	WSFR	–	YES	–	–	–	○	–	–	○	●
	37	WSFL	–	YES	–	–	–	○	–	–	○	●
	38	SFWR	–	YES	–	–	–	○	○	○	○	●
	39	SFRD	–	YES	–	–	–	○	○	○	○	●
Data processing	40	ZRST	–	△	○	○	○	○	○	○	○	●
	41	DECO	–	△	○	○	○	○	○	○	○	●
	42	ENCO	–	△	○	○	○	○	○	○	○	●
	43	SUM	YES	YES	–	–	–	○	–	–	○	●
	44	BON	YES	YES	–	–	–	○	–	–	○	●
	45	MEAN	YES	YES	–	–	–	○	–	–	○	●
	46	ANS	–	–	–	–	–	○	–	–	○	●
	47	ANR	–	YES	–	–	–	○	–	–	○	●
	48	SOR	YES	YES	–	–	–	○	–	–	○	●
	49	FLT	YES	YES	–	–	–	○	–	–	○	●
High-speed processing	50	REF	–	△	○	○	○	○	○	○	○	×
	51	REFF	–	YES	–	–	○	○	–	–	○	×
	52	MTR	–	–	–	–	–	○	○	○	○	×
	53	HSCS	YES	–	○	○	○	○	○	○	○	×
	54	HSCR	YES	–	○	○	○	○	○	○	○	×
	55	HSZ	YES	–	–	–	–	○	–	–	○	×
	56	SPD	–	–	–	–	–	○	○	○	○	×
	57	PLSY	YES	–	○	○	–	○	○	○	○	×
	58	PWM	–	–	○	○	–	○	○	○	○	×
	59	PLSR	YES	–	–	–	–	–	○	○	○	×

Appendix Table 2.3 List of Supported Instructions (FX series CPU functions) (cont.)

Class	FNC No.	Instruc-tion symbol	32-bit Instruction	Pulses Execution Instruction	Applicable PLCs							Compatibility with Ladder logic test tool (LLT)
					FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}	
Convenient instructions	60	IST	—	—	○	○	○	○	○	○	○	●
	61	SER	YES	YES	—	—	—	○	—	—	○	●
	62	ABSD	YES	—	—	—	—	○	○	○	○	●
	63	INCD	—	—	—	—	—	○	○	○	○	●
	64	TTMR	—	—	—	—	—	○	—	—	○	●
	65	STMR	—	—	—	—	—	○	—	—	○	●
	66	ALT	—	—	○	○	—	○	○	○	○	●
	67	RAMP	—	—	○	○	—	○	○	○	○	●
	68	ROTC	—	—	—	—	—	○	—	—	○	×
	69	SORT	—	—	—	—	—	○	—	—	○	●
External devices, I/O	70	TKY	YES	—	—	—	—	○	—	—	○	×
	71	HKY	YES	—	—	—	—	○	—	—	○	×
	72	DSW	—	—	—	—	—	○	○	○	○	×
	73	SEGD	—	YES	—	—	—	○	—	—	○	×
	74	SEGL	—	—	—	—	—	○	○	○	○	×
	75	ARWS	—	—	—	—	—	○	—	—	○	×
	76	ASC	—	—	—	—	—	○	—	—	○	●
	77	PR	—	—	—	—	—	○	—	—	○	×
	78	FROM	YES	YES	—	○	—	○	—	○	○	●
	79	TO	YES	YES	—	○	—	○	—	○	○	●
External devices, SER	80	RS	—	—	—	○	—	○	○	○	○	×
	81	PRUN	YES	YES	—	—	—	○	○	○	○	×
	82	ASCI	—	YES	—	○	—	○	○	○	○	●
	83	HEX	—	YES	—	○	—	○	○	○	○	●
	84	CCD	—	YES	—	○	—	○	○	○	○	×
	85	VRRD	—	YES	—	—	○	○	○	○	○	×
	86	VRSC	—	YES	—	—	—	○	○	○	○	×
	87	—										—
	88	PID	—	—	—	—	—	○	○	○	○	×
	89	—										—
External devices, F2	90	MNET	—	YES	—	—	—	—	—	—	—	×
	91	ANRD	—	YES	—	—	—	—	—	—	—	×
	92	ANWR	—	YES	—	—	—	—	—	—	—	×
	93	RMST	—	—	—	—	—	○	—	—	—	×
	94	RMWR	YES	YES	—	—	—	○	—	—	—	×
	95	RMRD	YES	YES	—	—	—	○	—	—	—	×
	96	RMMN	—	YES	—	—	—	○	—	—	—	×
	97	BLK	—	YES	—	—	—	—	—	—	—	×
	98	MCDE	—	YES	—	—	—	—	—	—	—	×
	99	—										—

Appendix Table 2.3 List of Supported Instructions (FX series CPU functions) (cont.)

Class	FNC No.	Instruc-tion symbol	32-bit Instruction	Pulses Execution Instruction	Applicable PLCs							Compatibility with Ladder logic test tool (LLT)
					FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}	
Floating decimal-point	110	ECMP	YES	YES	—	—	—	—	—	—	○	●
	111	EZCP	YES	YES	—	—	—	—	—	—	○	●
	118	EBCD	YES	YES	—	—	—	—	—	—	○	●
	119	EBIN	YES	YES	—	—	—	—	—	—	○	●
	120	EADD	YES	YES	—	—	—	—	—	—	○	●
	121	ESUB	YES	YES	—	—	—	—	—	—	○	●
	122	EMUL	YES	YES	—	—	—	—	—	—	○	●
	123	EDIV	YES	YES	—	—	—	—	—	—	○	●
	127	ESQR	YES	YES	—	—	—	—	—	—	○	●
	129	INT	YES	YES	—	—	—	—	—	—	○	●
	130	SIN	YES	YES	—	—	—	—	—	—	○	●
	131	COS	YES	YES	—	—	—	—	—	—	○	●
	132	TAN	YES	YES	—	—	—	—	—	—	○	●
	147	SWAP	YES	YES	—	—	—	—	—	—	○	●
Positioning	155	ABS	YES	—	—	—	—	—	○	○	—	×
	156	ZRN	YES	—	—	—	—	—	○	○	—	×
	157	PLSV	YES	—	—	—	—	—	○	○	—	×
	158	DRVI	YES	—	—	—	—	—	○	○	—	×
	159	DRVA	YES	—	—	—	—	—	○	○	—	×
Clock operations	160	TCMP	—	YES	—	—	—	—	○	○	○	●
	161	TZCP	—	YES	—	—	—	—	○	○	○	●
	162	TADD	—	YES	—	—	—	—	○	○	○	●
	163	TSUB	—	YES	—	—	—	—	○	○	○	●
	166	TRD	—	YES	—	—	—	—	○	○	○	●
	167	TWR	—	YES	—	—	—	—	○	○	○	×
	169	HOUR	YES	—	—	—	—	—	○	○	—	●
Other	170	GRY	YES	YES	—	—	—	—	—	—	○	●
	171	GBIN	YES	YES	—	—	—	—	—	—	○	●
	176	RD3A	—	YES	—	—	—	—	—	○	—	×
	177	WR3A	—	YES	—	—	—	—	—	○	—	×
Contact comparison	224	LD=	YES	—	—	—	—	—	○	○	○	●
	225	LD>	YES	—	—	—	—	—	○	○	○	●
	226	LD<	YES	—	—	—	—	—	○	○	○	●
	228	LD<>	YES	—	—	—	—	—	○	○	○	●
	229	LD≤	YES	—	—	—	—	—	○	○	○	●
	230	LD≥	YES	—	—	—	—	—	○	○	○	●
	232	AND=	YES	—	—	—	—	—	○	○	○	●
	233	AND>	YES	—	—	—	—	—	○	○	○	●

Appendix Table 2.3 List of Supported Instructions (FX series CPU functions) (cont.)

Class	FNC No.	Instruc-tion symbol	32-bit Instruction	Pulses Execution Instruction	Applicable PLCs							Compatibility with Ladder logic test tool (LLT)
					FX_0, FX_{0S}	FX_{0N}	FX_1	FX_2, FX_{2C}	FX_{1S}	FX_{1N}	FX_{2N}, FX_{2NC}	
Contact comparison	234	AND<	YES	—	—	—	—	—	○	○	○	●
	236	AND<>	YES	—	—	—	—	—	○	○	○	●
	237	AND≤	YES	—	—	—	—	—	○	○	○	●
	238	AND≥	YES	—	—	—	—	—	○	○	○	●
	240	OR=	YES	—	—	—	—	—	○	○	○	●
	241	OR>	YES	—	—	—	—	—	○	○	○	●
	242	OR<	YES	—	—	—	—	—	○	○	○	●
	244	OR<>	YES	—	—	—	—	—	○	○	○	●
	245	OR≤	YES	—	—	—	—	—	○	○	○	●
	246	OR≥	YES	—	—	—	—	—	○	○	○	●

● : Supported by ladder logic test tool (LLT).

× : Not supported by ladder logic test tool (LLT).

○ : Instruction supported by the actual PLC.

△ : FX_0, FX_{0S}, and FX_{0N} actual PLCs do not support pulse-executed instructions.

— : Instruction not supported by the actual PLC.

Appendix 2.4 Ladder logic test tool (LLT) for Q series CPU (A mode) functions

Since the supported instructions of the Q series CPU (A mode) are the same as those of the A series CPU, refer to Appendix Table 2.1 "List of Supported Instructions (A series CPU Function)".

Appendix 2.5 Ladder logic test tool (LLT) for Q series CPU (Q mode) functions

Appendix Table 2.4 List of Supported Instructions (Q Series CPU (Q Mode) Function)

(1) Sequence Instructions

Class	Instruction Symbol	Restriction
Contact instructions	LD, LDI, AND, ANI, OP, ORI, LDP, LDF, ANDP, ANDF, ORP, ORF	—
Coupling instructions	ANB, ORB, MPS, MRD, MPP, INV, MEP, MEF, EGP, EGF	—
Output instructions	OUT, OUT T, OUT C, OUTH T, SET, RST, PLS, PLF, FF	—
Shift instruction	SFT(P)	—
Master control instructions	MC, MCR	—
End instructions	FEND, END	—
Other instructions	STOP, NOP, NOPLF, PAGE	—

(2) Basic Instructions

Class	Instruction Symbol	Restriction
Comparative operation instructions	=, <>, >, <=, <, >=, D=, D<>, D>, D<=, D<, D>=, E=, E<>, E>, E<=, E<, E>=, $=, $<>, $>, $<=, $<, $>=, BKCMP□(P)	—
Arithmetic operation instructions	+(P), -(P), D+(P), D-(P), *(P), /(P), D *(P), D/(P), B+(P), B-(P), DB+(P), DB-(P), B*(P), B/(P), DB*(P), DB/(P), E+(P), E-(P), E *(P), E/(P), BK+(P), BK-(P), $+(P), INC(P), DEC(P), DINC(P), DDEC(P)	—
Data conversion instructions	BCD(P), DBCD(P), BIN(P), DBIN(P) INT(P), DINT(P), FLT(P), DFLT(P), DBL(P), WORD(P), GRY(P), DGRY(P), GBIN(P), DGBIN(P), NEG(P), DNEG(P), ENEG(P), BKBCD(P), BKBIN(P)	—
Data transfer instructions	MOV(P), DMOV(P), EMOV(P), $MOV(P), CML(P), DCML(P), BMOV(P), FMOV(P), XCH(P), DXCH(P), BXCH(P), SWAP(P), RBMOV	RBMOV operates as BMOV instruction.
Program branch instructions	CJ, SCJ, JMP, GOEND	—
Other convenient instructions	TTMR, STMR, RAMP, MTR	—

Appendix Table 2.4 List of Supported Instructions (Q Series CPU (Q Mode) Function) (cont.)

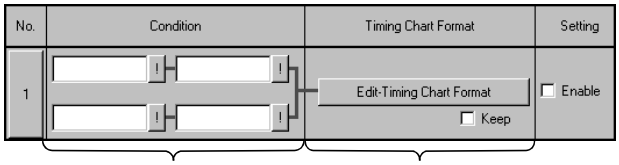
(1) Applied Instructions

Class	Instruction Symbol	Restriction
Logical arithmetic instructions	WAND(P), DAND(P), BKAND(P), WOR(P), DOR(P), BKOR(P), WXOR(P), DXOR(P), BKXOR(P), WXNR(P), DXNR(P), BKNXR(P)	—
Rotation instructions	ROR(P), RCR(P), ROL(P), RCL(P), DROR(P), DRCR(P), DROL(P), DRCL(P)	—
Shift instructions	SFR(P), SFL(P), BSFR(P), BSFL(P), DSFR(P), DSFL(P)	—
Bit processing instructions	BSET(P), BRST(P), TEST(P), DTEST(P), BKRST(P),	—
Data processing instructions	SER(P), DSER(P), SUM(P), DSUM(P), DECO(P), ENCO(P), SEG(P), DIS(P), UNI(P), NDIS(P), NUNI(P), WTOB(P), BTOW(P), MAX(P), MIN(P), DMAX(P), DMIN(P), SORT(P), DSORT(P), WSUM(P), DWSUM(P)	SORT(P) and DSORT(P) are executed in 1 scan.
Structured instructions	FOR, NEXT, BREAK(P), CALL(P), RET, FCALL(P), ECALL(P), EFCALL(P)	—
Data table operation instructions	FIFW(P), FIFR(P), FPOP(P), FINS(P), FDEL(P)	—
Buffer memory access instructions	FROM(P), DFRO(P), TO(P), DTO(P)	—
Character string processing instructions	BINDA(P), DBINDA(P), BINHA(P), DBINHA(P), BCDDA(P), DBCDDA(P), DABIN(P), DDABIN(P), HABIN(P), DHABIN(P), DABCD(P), DDABCD(P), LEN(P), STR(P), DSTR(P), VAL(P), DVAL(P), ESTR(P), EVAL(P), ASC(P), HEX(P), RIGHT(P), LEFT(P), MIDR(P), MIDW(P), INSTR(P), EMOD(P), EREXP(P)	—
Special function instructions	SIN(P), COS(P), TAN(P), ASIN(P), ACOS(P), ATAN(P), RAD(P), DEG(P), SQR(P), EXP(P), LOG(P), BSQR(P), BDSQR(P), BSIN(P), BCOS(P), BTAN(P), BASIN(P), BACOS(P), BATAN(P)	—
Data control instructions	LIMIT(P), DLIMIT(P), BAND(P), DBAND(P), ZONE(P), DZONE(P), RSET(P), QDRSET(P)	—
Clock instructions	DATERD(P), DATA+(P), DATA–(P), SECOND(P), HOUR(P)	DATERD(P) reads clock data of personal computer.
Program control instructions	PSTOP(P), POFF(P), PSCAN(P), PLOW(P)	—
Display instructions	LED, LEDR	—
Other instructions	DUTY, ZRRDB(P), ZRWRB(P), ADRSET(P)	—

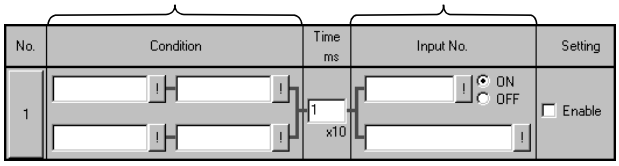
Appendix 3 List of Devices Usable with the I/O System Settings

Some devices designated in the condition setting area and simulation device area by the I/O system settings are subject to restrictions.
A list of the devices which can be used with the I/O system settings is shown below.

<Timing chart input>



<Device value input>



Appendix 3.1 Condition area

Devices which can be designated in condition area are the same for both timing chart input and device value input.

Device Name			Function				
			ACPU	QnACPU	QCPU (A mode)	QCPU (Q mode)	FXCPU
Bit device	Input (X)		○	○	○	○	○
	Output (Y)		○	○	○	○	○
	Internal relay (M)		○	○	○	○	○
	Latch relay (L)		×	○	×	○	—
	Step relay (S)		×	—	×	—	—
	Step relay (S) (for SFC)		—	×	—	×	—
	State (S)		—	—	—	—	○
	Annunciator (F)		○	○	○	○	—
	Edge relay (V)		—	○	—	○	—
	Link special relay (SB)		—	○	—	○	—
	Link relay (B)		○	○	○	○	—
	Special relay	(M)	○	—	○	—	○
		(SM)	—	○	—	○	—
	Timer (T)	Contacts	○ ＊1	○ ＊1	○ ＊1	○ ＊1	○ ＊1
		Coil	×	×	×	×	×

○……...Can be used
×……...Cannot be used
—……...Not supported
＊1 : Only T, ST, and C contacts can be designated.
＊2 : In the FX series, the device name becomes "T".

Device Name			Function				
			ACPU	QnACPU	QCPU (A mode)	QCPU (Q mode)	FXCPU
Bit device	Retentive timer (ST)	Contacts	－	○ ＊1	－	○ ＊1	○ ＊1＊2
		Coil	－	×	－	×	×
	Counter (C)	Contacts	○ ＊1	○ ＊1	○ ＊1	○ ＊1	○ ＊1
		Coil	×	×	×	×	×
	Function input (FX)		－	○	－	○	－
	Function output (FY)		－	○	－	○	－
	Link input (Jn\X)		－	×	－	×	－
	Link output (Jn\Y)		－	×	－	×	－
	Link relay (Jn\B)		－	×	－	×	－
	Link special relay (Jn\SB)		－	×	－	×	－
	SFC block (BL)		－	×	－	×	－
	SFC transition device(TR)		－	×	－	×	－
Word device	Data register (D)		○	○	○	○	○
	Special register	(D)	○	－	○	－	○
		(SD)	－	○	－	○	－
	Link register (W)		○	○	○	○	－
	Link special register (SW)		－	○	－	○	－
	Timer (present value) (T)		×	×	×	×	×
	Retentive timer (present value) (ST)		－	×	－	×	－
	Counter (present value) (C)		×	×	×	×	×
	Function register (FD)		－	×	－	×	－
	File register (R or D)		○	○	○	○	○
	Extension file register	(ER)	×	－	×	－	－
		(ZR)	－	○	－	○	－
	Buffer register (Un\G)		－	○	－	○	－
	Link register (Jn\W)		－	×	－	×	－
	Link direct device (Jn\SW)		－	×	－	×	－
	Index register	(Z)	○	○	○	○	○
		(V)	○	－	○	－	○
	Accumulator (A)		○	－	○	－	－

○……...Can be used
×……...Cannot be used
－……...Not supported

＊1 : Only T, ST, and C contacts can be designated.
＊2 : In the FX series, the device name becomes "T".

Appendix 3.2 Simulation device area

(1) Timing chart input

Device Name			Function				
			ACPU	QnACPU	QCPU (A mode)	QCPU (Q mode)	FXCPU
Bit device	Input (X)		○	○	○	○	○
	Output (Y)		○	○	○	○	○
	Internal relay (M)		○	○	○	○	○
	Latch relay (L)		×	○	×	○	—
	Step relay (S)		×	—	×	—	—
	Step relay (S) (for SFC)		—	×	—	×	—
	State (S)		—	—	—	—	○
	Annunciator (F)		○	○	○	○	—
	Edge relay (V)		—	○	—	○	—
	Link special relay (SB)		—	○	—	○	—
	Link relay (B)		○	○	○	○	—
	Special relay	(M)	○	—	○	—	○
		(SM)	—	○	—	○	—
	Timer (T)	Contacts	○	○	○	○	×
		Coil	×	×	×	×	×
	Retentive timer (ST)	Contacts	—	○	—	○	×
		Coil	—	×	—	×	×
	Counter (C)	Contacts	○	○	○	○	×
		Coil	×	×	×	×	×
	Function input (FX)		—	○	—	○	—
	Function output (FY)		—	○	—	○	—
	Link input (Jn\X)		—	×	—	×	—
	Link output (Jn\Y)		—	×	—	×	—
	Link relay (Jn\B)		—	×	—	×	—
	Link special relay (Jn\SB)		—	×	—	×	—
	SFC block (BL)		—	×	—	×	—
	SFC transition device(TR)		—	×	—	×	—

○……...Can be used
×……...Cannot be used
—……...Not supported

Device Name			Function				
			ACPU	QnACPU	QCPU (A mode)	QCPU (Q mode)	FXCPU
Word device	Data register (D)		○	○	○	○	○
	Special register	(D)	○	—	○	—	○
		(SD)	—	○	—	○	—
	Link register (W)		○	○	○	○	—
	Link special register (SW)		—	○	—	○	—
	Timer (present value) (T)		×	×	×	×	×
	Retentive timer (present value) (ST)		—	×	—	×	—
	Counter (present value) (C)		×	×	×	×	×
	Function register (FD)		—	×	—	×	—
	File register (R or D)		○	○	○	○	○
	Extension file register	(ER)	○	—	○	—	—
		(ZR)	—	○	—	○	—
	Buffer register (Un\G)		—	○	—	○	—
	Link register (Jn\W)		—	×	—	×	—
	Link direct device (Jn\SW)		—	×	—	×	—
	Index register	(Z)	○	○	○	○	○
		(V)	○	—	○	—	○
	Accumulator (A)		○	—	○	—	—

○……...Can be used
×……...Cannot be used
—……...Not supported

(2) Device value input

Device Name			Function				
			ACPU	QnACPU	QCPU (A mode)	QCPU (Q mode)	FXCPU
Bit device	Input (X)		○	○	○	○	○
	Output (Y)		○	○	○	○	○
	Internal relay (M)		○	○	○	○	○
	Latch relay (L)		×	○	×	○	–
	Step relay (S)		×	–	×	–	–
	Step relay (S) (for SFC)		–	×	–	×	–
	State (S)		–	–	–	–	○
	Annunciator (F)		○	○	○	○	–
	Edge relay (V)		–	○	–	○	–
	Link special relay (SB)		–	○	–	○	–
	Link relay (B)		○	○	○	○	–
	Special relay	(M)	○	–	○	–	○
		(SM)	–	○	–	○	–
	Timer (T)	Contacts	×	×	×	×	×
		Coil	×	×	×	×	×
	Retentive timer (ST)	Contacts	–	×	–	×	×
		Coil	–	×	–	×	×
	Counter (C)	Contacts	×	×	×	×	×
		Coil	×	×	×	×	×
	Function input (FX)		–	○	–	○	–
	Function output (FY)		–	○	–	○	–
	Link input (Jn\X)		–	×	–	×	–
	Link output (Jn\Y)		–	×	–	×	–
	Link relay (Jn\B)		–	×	–	×	–
	Link special relay (Jn\SB)		–	×	–	×	–
	SFC block (BL)		–	×	–	×	–
	SFC transition device(TR)		–	×	–	×	–

○……...Can be used
×……...Cannot be used
－……...Not supported

Device Name			Function				
			ACPU	QnACPU	QCPU (A mode)	QCPU (Q mode)	FXCPU
Word device	Data register (D)		○	○	○	○	○
	Special register	(D)	○	—	○	—	○
		(SD)	—	○	—	○	—
	Link register (W)		○	○	○	○	—
	Link special register (SW)		—	○	—	○	—
	Timer (present value) (T)		×	×	×	×	×
	Retentive timer (present value) (ST)		—	×	—	×	—
	Counter (present value) (C)		×	×	×	×	×
	Function register (FD)		—	×	—	×	—
	File register (R or D)		○	○	○	○	×
	Extension file register	(ER)	×	—	×	—	—
		(ZR)	—	○	—	○	—
	Buffer register (Un\G)		○	○	—	○	—
	Link register (Jn\W)		—	×	—	×	—
	Link direct device (Jn\SW)		—	×	—	×	—
	Index register	(Z)	○	○	○	○	○
		(V)	○	—	○	—	○
	Accumulator (A)		○	—	○	—	—

○……...Can be used
×……...Cannot be used
—……...Not supported

MEMO

INDEX

Ladder Logic Test Function software for Windows
SW5D5C-LLT-E
Operating Manual

MODEL	SW5D5C-LLT-O-E
MODEL CODE	13J977
SH(NA)-080064-C(0011)MEE	

MITSUBISHI ELECTRIC CORPORATION

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